A Complete Bibliography of Publications in *Technometrics* for the decade 1990–1999

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References

Albers:1999:TRU

[AAK99] Willem Albers, Gerda R. J. Arts, and Wilbert C. M. Kallenberg. Test regions using two or more correlated product characteristics. *Technometrics*, 41(2):153–165, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270731.

Atkinson:1997:COD

[AB97] Anthony C. Atkinson and Barbara Bogacka. Compound D- and D_s-optimum designs for determining the order of a chemical reaction. *Technometrics*, 39(4):347–356, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271499.

Abate:1998:BRB

[Aba98] Marcey Abate. Book review: *The Pocket Statistician: A Practical Guide to Quality Improvement* by S. Coleman; T. Greenfield; R. Jones; C. Morris; I. Puzey. *Technometrics*, 40(1):75–76, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271399`.

Acree:1997:BRB

[Acr97] David A. Acree. Book review: *Statistical Process Control Methods* by Gary K. Griffith. *Technometrics*, 39(1):107–108, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270789`.

Abraham:1999:SRC

[ACV99] B. Abraham, H. Chipman, and K. Vijayan. Some risks in the construction and analysis of supersaturated designs. *Technometrics*, 41(2):135–141, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270729`.

Atkinson:1996:EDO

[AD96] A. C. Atkinson and A. N. Donev. Experimental designs optimally balanced for trend. *Technometrics*, 38(4):333–341, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271304`.

Adams:1991:BRB

[Ada91] Benjamin M. Adams. Book review: *Right Every Time: Using the Deming Approach* by Frank Price. *Technometrics*, 33(3):357–358, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268789`.

Adams:1992:BRB

[Ada92] James A. Adams. Book review: *A Quality Technology Primer for Managers* by Joseph R. Tunner. *Technometrics*, 34(3):362–363, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270055`.

Adams:1993:BRB

[Ada93] Benjamin M. Adams. Book review: *Statistical Process Control* by Leonard A. Doty. *Technometrics*, 35(1):90–91, February 1993.

CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269299.

Adams:1994:BRB

[Ada94] Benjamin M. Adams. Book review: *Modern Statistical Quality Control and Improvement* by Nicholas R. Farnum. *Technometrics*, 36(2):223–224, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270244.

Adams:1996:BRB

[Ada96] Benjamin M. Adams. Book review: *Advanced Topics in Statistical Process Control: The Power of Shewhart's Charts* by Donald J. Wheeler. *Technometrics*, 38(3):286, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270614.

Arjas:1991:HPQ

[AHT91] Elja Arjas, Christian Kornerup Hansen, and Poul Thyregod. Heterogeneous part quality as a source of reliability improvement in repairable systems. *Technometrics*, 33(1):1–12, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269003.

Ajmani:1999:BRB

[Ajm99] Vivek B. Ajmani. Book review: *Modern Engineering Statistics* by Lawrence L. Lapin. *Technometrics*, 41(4):373, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271361.

Albers:1994:ATL

[AKO94] Willem Albers, Wilbert C. M. Kallenberg, and Gertjan D. Otten. Accurate test limits with estimated parameters. *Technometrics*, 36(1):92–101, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269202.

Albert:1993:BRB

[Alb93] Jim Albert. Book review: *The Analysis of Contingency Tables* by B. S. Everitt. *Technometrics*, 35(3):327–328, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269530.

Alexander:1991:BRB

[Ale91] Melvin T. Alexander. Book review: *Learning Statistics with the SAS System* by Rudolf Freund. *Technometrics*, 33(1):110–112, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269017.

Alexander:1995:BRB

[Ale95] Melvin T. Alexander. Book review: *Applied Statistics and Probability for Engineers* by Douglas C. Montgomery; George Runger. *Technometrics*, 37(4):455–457, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269738.

Alexander:1998:BRB

[Ale98] William P. Alexander. Book review: *LISREL Approaches to Interaction Effects in Multiple Regression* by James Jaccard; Choi K. Wan. *Technometrics*, 40(3):259–260, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271188.

Alexander:1999:BRB

[Ale99] William Alexander. Book review: *Nonparametric Smoothing and Lack-of-Fit Tests* by Jeffrey D. Hart. *Technometrics*, 41(2):175–176, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270744.

Allen:1996:BRB

[All96] David Allen. Book review: *Modeling Experimental and Observational Data* by Clifford E. Lunneborg. *Technometrics*, 38(3):291, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270620.

Almond:1995:DFL

[Alm95] Russell G. Almond. Discussion: Fuzzy logic: Better science? or better engineering? *Technometrics*, 37(3):267–270, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269907.

Altland:1996:BRB

[Alt96] Henry W. Altland. Book review: *Engineering Methods for Robust Product Design* by William Y. Fowlkes; Clyde M. Creveling. *Technometrics*, 38(3):286–287, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270615.

Altland:1999:BRB

[Alt99] Henry W. Altland. Book review: *Regression Analysis: Statistical Modeling of a Response Variable* by Rudolf J. Freund; William J. Wilson. *Technometrics*, 41(4):368, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271353.

Ammann:1992:BRB

[Amm92] Larry P. Ammann. Book review: *Lisp-Stat, an Object-Oriented Environment for Statistical Computing and Dynamic Graphics* by Luke Tierney. *Technometrics*, 34(2):238–239, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269258.

Anderson:1990:BRB

[And90] Charles Anderson. Book review: *Curves and Surfaces in Computer Aided Geometric Design* by F. Yamaguchi. *Technometrics*, 32(2):229–230, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268878.

Angus:1990:BRBa

[Ang90a] John E. Angus. Book review: *Extreme Value Theory in Engineering* by Enrique Castillo. *Technometrics*, 32(1):107–110, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269867.

Angus:1990:BRBb

[Ang90b] John E. Angus. Book review: *The Asymptotic Theory of Extreme Order Statistics* by Janos Galambos. *Technometrics*, 32(1):110–111, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269868.

Angus:1991:BRBa

[Ang91a] John E. Angus. Book review: *Empirical Bayes Methods* by J. Mantz; T. Lwin. *Technometrics*, 33(2):243–245, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269060.

Angus:1991:BRBb

[Ang91b] John E. Angus. Book review: *Regression Estimators: A Comparative Study* by Marvin Gruber. *Technometrics*, 33(4):480–482, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269428.

Angus:1991:BRBc

[Ang91c] John E. Angus. Book review: *Statistical Inference* by George Casella; Roger L. Berger. *Technometrics*, 33(4):493, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269442.

Angus:1992:BRB

[Ang92] John E. Angus. Book review: *Forecasting, Structural Time Series and the Kalman Filter* by Andrew C. Harvey. *Technometrics*, 34 (4):496–497, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268960.

Annis:1999:EFC

[Ann99] Charles Annis. [Estimating Fatigue Curves with the Random Fatigue-Limit Model]: Discussion. *Technometrics*, 41(4):290–291, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271343. See [PM99].

Anonymous:1990:BMa

[Ano90a] Anonymous. Back matter. *Technometrics*, 32(1):116–118, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269876.

Anonymous:1990:BMb

[Ano90b] Anonymous. Back matter. *Technometrics*, 32(2):??, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268896.

Anonymous:1990:BMc

[Ano90c] Anonymous. Back matter. *Technometrics*, 32(3):368, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269143.

Anonymous:1990:BMd

[Ano90d] Anonymous. Back matter. *Technometrics*, 32(4):470–471, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270156.

Anonymous:1990:CDO

[Ano90e] Anonymous. Correction: "Detecting Outlying Cells in Two-Way Contingency Tables Via Backwards-Stepping". *Technometrics*, 32(1):115, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269875. See [Sim88].

Anonymous:1990:CSD

[Ano90f] Anonymous. Correction: "Small-Disturbance Asymptotic Theory for Linear Calibration Estimators". *Technometrics*, 32(4):468, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270154. See [SS89].

Anonymous:1990:CPB

[Ano90g] Anonymous. Corrections to Piepel, Beckman and Carroll. *Technometrics*, 32(2):241, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268895. See [Pie90b, BNC87, Wei90].

Anonymous:1990:FMa

[Ano90h] Anonymous. Front matter. *Technometrics*, 32(1):93, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269834.

Anonymous:1990:FMb

[Ano90i] Anonymous. Front matter. *Technometrics*, 32(2):217, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268852.

Anonymous:1990:FMc

[Ano90j] Anonymous. Front matter. *Technometrics*, 32(3):339, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269091.

Anonymous:1990:FMd

[Ano90k] Anonymous. Front matter. *Technometrics*, 32(4):445, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270112.

Anonymous:1990:VI

[Ano90l] Anonymous. Volume information. *Technometrics*, 32(4):472–477, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270111.

Anonymous:1991:BMa

[Ano91a] Anonymous. Back matter. *Technometrics*, 33(1):123–124, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269036.

Anonymous:1991:BMb

[Ano91b] Anonymous. Back matter. *Technometrics*, 33(2):250, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269072.

Anonymous:1991:BMc

[Ano91c] Anonymous. Back matter. *Technometrics*, 33(3):??, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268811.

Anonymous:1991:BMd

[Ano91d] Anonymous. Back matter. *Technometrics*, 33(4):495–496, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269446.

Anonymous:1991:CDU

[Ano91e] Anonymous. Correction: "Diagnostics for Use with Regression Recursive Residuals". *Technometrics*, 33(4):494, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269445. See [Haw91a].

Anonymous:1991:CMQ

[Ano91f] Anonymous. Correction: “Multivariate Quality Control Based on Regression-Adjusted Variables”. *Technometrics*, 33(3):376, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268810`. See [Haw91b].

Anonymous:1991:FMa

[Ano91g] Anonymous. Front matter. *Technometrics*, 33(1):105, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269002`.

Anonymous:1991:FMb

[Ano91h] Anonymous. Front matter. *Technometrics*, 33(2):235, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269037`.

Anonymous:1991:FMc

[Ano91i] Anonymous. Front matter. *Technometrics*, 33(3):355, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268778`.

Anonymous:1991:FMd

[Ano91j] Anonymous. Front matter. *Technometrics*, 33(4):469, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269408`.

Anonymous:1991:VI

[Ano91k] Anonymous. Volume information. *Technometrics*, 33(4):497–501, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269407`.

Anonymous:1992:BMa

[Ano92a] Anonymous. Back matter. *Technometrics*, 34(1):124–126, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269595`.

Anonymous:1992:BMb

[Ano92b] Anonymous. Back matter. *Technometrics*, 34(2):??, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269278`.

Anonymous:1992:BMc

[Ano92c] Anonymous. Back matter. *Technometrics*, 34(3):??, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270077`.

Anonymous:1992:BMd

[Ano92d] Anonymous. Back matter. *Technometrics*, 34(4):503–504, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268970`.

Anonymous:1992:FMa

[Ano92e] Anonymous. Front matter. *Technometrics*, 34(1):97, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269546`.

Anonymous:1992:FMb

[Ano92f] Anonymous. Front matter. *Technometrics*, 34(2):223, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269230`.

Anonymous:1992:FMc

[Ano92g] Anonymous. Front matter. *Technometrics*, 34(3):353, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270027`.

Anonymous:1992:FMd

[Ano92h] Anonymous. Front matter. *Technometrics*, 34(4):??, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268936`.

Anonymous:1992:VI

[Ano92i] Anonymous. Volume information. *Technometrics*, 34(4):505–510, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268935`.

Anonymous:1993:BMa

[Ano93a] Anonymous. Back matter. *Technometrics*, 35(1):107–108, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269328`. See correction [Ano93e].

Anonymous:1993:BMb

[Ano93b] Anonymous. Back matter. *Technometrics*, 35(2):242, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269700.

Anonymous:1993:BMc

[Ano93c] Anonymous. Back matter. *Technometrics*, 35(3):??, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269545.

Anonymous:1993:BMd

[Ano93d] Anonymous. Back matter. *Technometrics*, 35(4):467–468, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270309.

Anonymous:1993:C

[Ano93e] Anonymous. Correction. *Technometrics*, 35(2):241, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269699. See [Ano93a].

Anonymous:1993:CCM

[Ano93f] Anonymous. Correction: Comments on Marr and Quesenberry (1991). *Technometrics*, 35(1):105, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269327. See [FMQ92].

Anonymous:1993:FMa

[Ano93g] Anonymous. Front matter. *Technometrics*, 35(1):83, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269279.

Anonymous:1993:FMb

[Ano93h] Anonymous. Front matter. *Technometrics*, 35(2):219, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269655.

Anonymous:1993:FMc

[Ano93i] Anonymous. Front matter. *Technometrics*, 35(3):321, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269516.

Anonymous:1993:FMd

[Ano93j] Anonymous. Front matter. *Technometrics*, 35(4):449, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270267.

Anonymous:1993:VI

[Ano93k] Anonymous. Volume information. *Technometrics*, 35(4):469–473, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270266.

Anonymous:1994:BMa

[Ano94a] Anonymous. Back matter. *Technometrics*, 36(1):??, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269229.

Anonymous:1994:BMb

[Ano94b] Anonymous. Back matter. *Technometrics*, 36(2):235–236, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270265.

Anonymous:1994:BMc

[Ano94c] Anonymous. Back matter. *Technometrics*, 36(3):??, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269406.

Anonymous:1994:BMd

[Ano94d] Anonymous. Back matter. *Technometrics*, 36(4):439–440, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269988.

Anonymous:1994:FMa

[Ano94e] Anonymous. Front matter. *Technometrics*, 36(1):110, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269189.

Anonymous:1994:FMb

[Ano94f] Anonymous. Front matter. *Technometrics*, 36(2):213, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270219.

Anonymous:1994:FMc

[Ano94g] Anonymous. Front matter. *Technometrics*, 36(3):313, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269367`.

Anonymous:1994:FMd

[Ano94h] Anonymous. Front matter. *Technometrics*, 36(4):419, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269947`.

Anonymous:1994:VI

[Ano94i] Anonymous. Volume information. *Technometrics*, 36(4):441–445, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269946`.

Anonymous:1995:BMa

[Ano95a] Anonymous. Back matter. *Technometrics*, 37(1):??, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269188`.

Anonymous:1995:BMb

[Ano95b] Anonymous. Back matter. *Technometrics*, 37(2):246–248, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269654`.

Anonymous:1995:BMc

[Ano95c] Anonymous. Back matter. *Technometrics*, 37(3):360, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269945`.

Anonymous:1995:BMd

[Ano95d] Anonymous. Back matter. *Technometrics*, 37(4):474–475, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269766`.

Anonymous:1995:FMa

[Ano95e] Anonymous. Front matter. *Technometrics*, 37(1):112, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269144`.

Anonymous:1995:FMb

[Ano95f] Anonymous. Front matter. *Technometrics*, 37(2):226, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269614`.

Anonymous:1995:FMc

[Ano95g] Anonymous. Front matter. *Technometrics*, 37(3):340, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269904`.

Anonymous:1995:FMd

[Ano95h] Anonymous. Front matter. *Technometrics*, 37(4):361–472, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269728`.

Anonymous:1995:VI

[Ano95i] Anonymous. Volume information. *Technometrics*, 37(4):476–480, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269727`.

Anonymous:1996:BMa

[Ano96a] Anonymous. Back matter. *Technometrics*, 38(1):94, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268934`.

Anonymous:1996:BMb

[Ano96b] Anonymous. Back matter. *Technometrics*, 38(2):204, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270443`.

Anonymous:1996:BMc

[Ano96c] Anonymous. Back matter. *Technometrics*, 38(3):302, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270641`.

Anonymous:1996:BMd

[Ano96d] Anonymous. Back matter. *Technometrics*, 38(4):415–417, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271339`.

Anonymous:1996:FMa

[Ano96e] Anonymous. Front matter. *Technometrics*, 38(1):74, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268897.

Anonymous:1996:FMb

[Ano96f] Anonymous. Front matter. *Technometrics*, 38(2):181–196, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270398.

Anonymous:1996:FMc

[Ano96g] Anonymous. Front matter. *Technometrics*, 38(3):284, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270600.

Anonymous:1996:FMd

[Ano96h] Anonymous. Front matter. *Technometrics*, 38(4):400, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271296.

Anonymous:1996:VI

[Ano96i] Anonymous. Volume information. *Technometrics*, 38(4):418–422, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271295.

Anonymous:1997:BMa

[Ano97a] Anonymous. Back matter. *Technometrics*, 39(1):117–118, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270806.

Anonymous:1997:BMb

[Ano97b] Anonymous. Back matter. *Technometrics*, 39(2):??, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270938.

Anonymous:1997:BMc

[Ano97c] Anonymous. Back matter. *Technometrics*, 39(3):??, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271165.

Anonymous:1997:BMd

[Ano97d] Anonymous. Back matter. *Technometrics*, 39(4):436, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271534.

Anonymous:1997:CBOb

[Ano97e] Anonymous. Correction: *Design and Optimization in Organic Synthesis* and *Complex Stochastic Systems and Engineering*. *Technometrics*, 39(4):435, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271533. See [LH97].

Anonymous:1997:CBOa

[Ano97f] Anonymous. Correction: *Design and Optimization in Organic Synthesis* [rather than *Experimental Design and Chemical Synthesis*]. *Technometrics*, 39(4):435, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271532. See [Emp97].

Anonymous:1997:FMa

[Ano97g] Anonymous. Front matter. *Technometrics*, 39(1):100–114, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270762.

Anonymous:1997:FMb

[Ano97h] Anonymous. Front matter. *Technometrics*, 39(2):225, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270899.

Anonymous:1997:FMc

[Ano97i] Anonymous. Front matter. *Technometrics*, 39(3):331, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271128.

Anonymous:1997:FMd

[Ano97j] Anonymous. Front matter. *Technometrics*, 39(4):423, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271498.

Anonymous:1997:VI

[Ano97k] Anonymous. Volume information. *Technometrics*, 39(4):437–440, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print),

1537-2723 (electronic). URL http://www.jstor.org/stable/1271497.

Anonymous:1998:BMa

[Ano98a] Anonymous. Back matter. *Technometrics*, 40(1):86–87, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271422.

Anonymous:1998:BMb

[Ano98b] Anonymous. Back matter. *Technometrics*, 40(2):??, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270677.

Anonymous:1998:BMc

[Ano98c] Anonymous. Back matter. *Technometrics*, 40(3):??, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271209.

Anonymous:1998:BMd

[Ano98d] Anonymous. Back matter. *Technometrics*, 40(4):363, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270561.

Anonymous:1998:CCD

[Ano98e] Anonymous. Correction: “Cumulative Damage Models for System Failure with Application to Carbon Fibers and Composites”. *Technometrics*, 40(2):167, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270675. See [DP97].

Anonymous:1998:FMa

[Ano98f] Anonymous. Front matter. *Technometrics*, 40(1):72, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271386.

Anonymous:1998:FMb

[Ano98g] Anonymous. Front matter. *Technometrics*, 40(2):153, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270642.

Anonymous:1998:FMc

[Ano98h] Anonymous. Front matter. *Technometrics*, 40(3):254, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271166.

Anonymous:1998:FMd

[Ano98i] Anonymous. Front matter. *Technometrics*, 40(4):348–361, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270526.

Anonymous:1998:VI

[Ano98j] Anonymous. Volume information. *Technometrics*, 40(4):364–368, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270525.

Anonymous:1999:BMa

[Ano99a] Anonymous. Back matter. *Technometrics*, 41(1):86–87, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271023.

Anonymous:1999:BMb

[Ano99b] Anonymous. Back matter. *Technometrics*, 41(2):??, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270761.

Anonymous:1999:BMc

[Ano99c] Anonymous. Back matter. *Technometrics*, 41(3):??, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270599.

Anonymous:1999:BMd

[Ano99d] Anonymous. Back matter. *Technometrics*, 41(4):386–387, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271385.

Anonymous:1999:CIE

[Ano99e] Anonymous. Correction: "Interaction Effects in Factorial Analysis of Variance". *Technometrics*, 41(3):275, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270598. See [Emp99].

Anonymous:1999:EFC

[Ano99f] Anonymous. [Estimating Fatigue Curves with the Random Fatigue-Limit Model]: Response. *Technometrics*, 41(4):297–302, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271346`. See [PM99].

Anonymous:1999:FMa

[Ano99g] Anonymous. Front matter. *Technometrics*, 41(1):71, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270989`.

Anonymous:1999:FMb

[Ano99h] Anonymous. Front matter. *Technometrics*, 41(2):166, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270720`.

Anonymous:1999:FMc

[Ano99i] Anonymous. Front matter. *Technometrics*, 41(3):261, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270562`.

Anonymous:1999:FMd

[Ano99j] Anonymous. Front matter. *Technometrics*, 41(4):367, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271341`.

Anonymous:1999:VI

[Ano99k] Anonymous. Volume information. *Technometrics*, 41(4):388–392, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271340`.

Anonymous:2000:CCS

[Ano00] Anonymous. Correction: "A Cepstral F Statistic for Detecting Delay-Fired Seismic Signals". *Technometrics*, 42(2):226, May 2000. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271495`. See [SBD98].

Aragon:1992:BRB

[Ara92] Jorge Aragón. Book review: *The Architecture of Chance* by Richard Lowry. *Technometrics*, 34(2):242–243, May 1992. CO-

DEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269265.

Armstrong:1990:CTR

[Arm90] Robert P. Armstrong. Commentary: Is there really a communications gap between statisticians and engineers? *Technometrics*, 32(3):249–250, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269093. See [HK90].

Armitage:1992:BRB

[Arm92] Stan J. Armitage. Book review: *Understanding Statistics* by Lyman Ott; William Mendenhall. *Technometrics*, 34(3):368–369, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270063.

Armitage:1993:BRB

[Arm93] Stanley J. Armitage. Book review: *Statistical Methods for the Process Industries* by William H. McNeese; Robert A. Klein. *Technometrics*, 35(2):229–230, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269679.

Armstrong:1997:BRB

[Arm97] Ben Armstrong. Book review: *Measurement Error in Nonlinear Models* by R. J. Carroll; D. Ruppert; L. A. Stefanski. *Technometrics*, 39(2):231–232, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270919.

Arnold:1990:BRB

[Arn90] Harvey J. Arnold. Book review: *Introduction to the Practice of Statistics* by David S. Moore; George P. McCabe. *Technometrics*, 32(3):347–348, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269120.

Atkinson:1996:DPP

[Atk96] A. C. Atkinson. Discussion: Posterior probabilities and experimental designs for discriminating between regression models. *Technometrics*, 38(4):314–317, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271298.

Adams:1994:RLD

[AWS94] Benjamin M. Adams, William H. Woodall, and Claude R. Superville. [Run-Length Distributions of Special-Cause Control Charts for Correlated Processes]: Discussion. *Technometrics*, 36 (1):19–22, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269193`. See [WMP94a].

Ayeni:1998:BRB

[Aye98] Babatunde J. Ayeni. Book review: *Straight Talk on Designing Experiments* by Robert G. Launsby; Daniel L. Weese. *Technometrics*, 40(1):75, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271398`.

Bisgaard:1996:SEE

[BA96] Søren Bisgaard and Bruce Ankenman. Standard errors for the eigenvalues in second-order response surface models. *Technometrics*, 38(3):238–246, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270607`.

Babu:1998:BRB

[Bab98] Gutti J. Babu. Book review: *Introduction to Probability Models* by Sheldon M. Ross. *Technometrics*, 40(1):78, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271404`.

Bajorski:1998:BRB

[Baj98] Peter Bajorski. Book review: *Visual Explanations: Images and Quantities, Evidence and Narrative* by Edward R. Tufte. *Technometrics*, 40(1):81, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271409`.

Baker:1996:SNT

[Bak96] R. D. Baker. Some new tests of the power law process. *Technometrics*, 38(3):256–265, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270609`.

Bakir:1998:BRB

[Bak98] Saad T. Bakir. Book review: *Tolerance Design: A Handbook for Developing Optimal Specifications* by C. M. Creveling. *Technometrics*, 40(1):74–75, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271397`.

Balestracci:1993:BRB

[Bal93] Davis Balestracci. Book review: *Intermediate Statistics, A Modern Approach* by James Stevens. *Technometrics*, 35(1):98, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269309`.

Barker:1991:BRB

[Bar91] Anne M. Barker. Book review: *Handbook of Statistical Methods for Engineers and Scientists* by Harrison M. Wadsworth. *Technometrics*, 33(2):238–239, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269051`.

Barker:1992:BRBb

[Bar92a] Lawrence Barker. Book review: *Statistical Analyses of Reliability Data* by M. J. Crowder; A. C. Kimber; R. L. Smith; T. J. Sweeting. *Technometrics*, 34(4):485–486, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268947`.

Barker:1992:BRBa

[Bar92b] Lawrence Barker. Book review: *System Reliability: Concepts and Applications* by Klaas B. Klaassen; Jack C. L. van Peppen. *Technometrics*, 34(2):234–235, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269254`.

Barrett:1995:BRB

[Bar95] Bruce Barrett. Book review: *Regression Analysis: Concepts and Applications* by Franklin A. Graybill; Hariharan K. Iyer. *Technometrics*, 37(2):229, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269625`.

Basu:1990:BRB

[Bas90] Asit P. Basu. Book review: *The Inverse Gaussian Distribution* by Raj S. Chhikara; J. Leroy Folks. *Technometrics*, 32(2):235, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268886.

Basu:1997:BRB

[Bas97] Asit P. Basu. Book review: *Statistical Analysis of Nonnormal Data* by J. V. Deshpande; A. P. Gore; A. Shanubhogue. *Technometrics*, 39(3):341, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271150.

Basu:1999:BRB

[Bas99] Asit P. Basu. Book review: *Aspects of Statistical Inference* by A. H. Welsh. *Technometrics*, 41(3):270–271, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270585.

Bates:1999:BRB

[Bat99] Douglas M. Bates. Book review: *Programming with Data: A Guide to the S Language* by John M. Chambers. *Technometrics*, 41(3):266–267, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270578.

Baxley:1990:EWM

[Bax90] Robert V. Baxley, Jr. [Exponentially Weighted Moving Average Control Schemes: Properties and Enhancements]: Discussion. *Technometrics*, 32(1):13–16, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269836. See [LS90b].

Baxter:1992:BRB

[Bax92] Laurence A. Baxter. Book review: *Probability, Statistics, and Queueing Theory with Computer Science Applications* by Arnold O. Allen. *Technometrics*, 34(2):240–241, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269262.

Baxter:1995:BRB

[Bax95] Laurence A. Baxter. Book review: *Markov Decision Processes: Discrete Stochastic Dynamic Programming* by Martin L. Puterman. *Technometrics*, 37(3):353, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269932.

Baxter:1996:BRBb

[Bax96a] Laurence A. Baxter. Book review: *Random Fields on a Network: Modeling, Statistics, and Applications* by Xavier Guyon. *Technometrics*, 38(4):409–410, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271325.

Baxter:1996:BRBa

[Bax96b] Laurence A. Baxter. Book review: *Reliability Analysis for Engineers: An Introduction* by Roger D. Leitch. *Technometrics*, 38(2):185, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270417.

Bayne:1992:BRB

[Bay92] Charles K. Bayne. Book review: *Latent Variable Path Modeling with Partial Least Squares* by Jan-Bernd Lohmöller. *Technometrics*, 34(1):110–111, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269575.

Bayne:1995:BRB

[Bay95] Charles K. Bayne. Book review: *Practical Guide to Chemometrics* by Stephen John Haswell. *Technometrics*, 37(2):230–231, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269627.

Bayne:1999:BRB

[Bay99] Charles K. Bayne. Book review: *Chemometric Techniques for Quantitative Analysis* by Richard Kramer. *Technometrics*, 41(2):173–174, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270741.

Berk:1995:SCM

[BB95] Kenneth N. Berk and David E. Booth. Seeing a curve in multiple regression. *Technometrics*, 37(4):385–398, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269731.

Birch:1990:CIB

[BBT90] Nancy J. Birch, Richard K. Burdick, and Naitee Ting. Confidence intervals and bounds for a ratio of summed expected mean squares. *Technometrics*, 32(4):437–444, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270123.

Blazek:1995:STC

[BC95] Linda W. Blazek and David E. Coleman. [Shewhart-Type Charts in Nonstandard Situations]: Discussion. *Technometrics*, 37(1):24–26, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269147. See [RD95a].

Becker:1998:EDDa

[BCL98a] Richard A. Becker, Linda A. Clark, and Diane Lambert. Events defined by duration and severity, with an application to network reliability. *Technometrics*, 40(3):177–189, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271167. See discussion [Rob98, Sch98a] and response [BCL98b].

Becker:1998:EDDb

[BCL98b] Richard A. Becker, Linda A. Clark, and Diane Lambert. [Events Defined by Duration and Severity, with an Application to Network Reliability]: Response. *Technometrics*, 40(3):192–194, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271170. See [BCL98a].

Boulanger:1994:EDC

[BE94] Michèle Boulanger and Luis A. Escobar. Experimental design for a class of accelerated degradation tests. *Technometrics*, 36 (3):260–272, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269370.

Beggs:1990:BRB

[Beg90] William J. Beggs. Book review: *Statistical Methods for Nuclear Material Management* by W. Michael Bowen; Carl A. Bennett. *Technometrics*, 32(4):462–463, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270145.

Belunis:1995:BRB

[Bel95] Nancy Belunis. Book review: *A Practical Guide to Statistical Quality Improvement: Opening up the Statistical Toolbox* by Michael R. Beauregard; Raymond J. Mikulak; Barbara A. Olson. *Technometrics*, 37(2):233–234, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269632.

Belunis:1999:BRB

[Bel99] Nancy Belunis. Book review: *Building Continual Improvement* by Donald J. Wheeler; Sheila R. Poling. *Technometrics*, 41(2):169–170, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270736.

Bement:1996:BRB

[Bem96] Thomas R. Bement. Book review: *Fundamentals of Quality Control and Improvement* by Amitava Mitra. *Technometrics*, 38(1):80–81, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268912.

Benbow:1993:BRB

[Ben93] Don Benbow. Book review: *Quality Engineering Statistics* by Robert A. Dovich. *Technometrics*, 35(3):332–333, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269539.

Berk:1991:BRB

[Ber91] Kenneth Berk. Book review: *Nonlinear Regression* by G. A. F. Seber; C. J. Wild. *Technometrics*, 33(3):362–363, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268793.

Berk:1992:BRB

[Ber92a] Robert H. Berk. Book review: *Observing Interaction: An Introduction to Sequential Analysis* by Roger Bakeman; John M. Gottman. *Technometrics*, 34(1):112–113, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269577.

Berliner:1992:BRB

[Ber92b] L. Mark Berliner. Book review: *Bayesian Statistics: An Introduction* by Peter M. Lee. *Technometrics*, 34(1):115, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269580`.

Berens:1996:ASM

[Ber96a] Alan P. Berens. [Applications of Statistical Methods to Nondestructive Evaluation]: Discussion. *Technometrics*, 38(2):113–116, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270400`. See [OM96a].

Berk:1996:BRB

[Ber96b] Robert H. Berk. Book review: *Continuous Univariate Distributions, Volume 2* by Norman L. Johnson; Samuel Kotz; N. Balakrishnan. *Technometrics*, 38(2):189, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270425`.

Berk:1997:BRB

[Ber97] Robert Berk. Book review: *Handbook of the Normal Distribution* by Jagdish K. Patel; Campbell B. Read. *Technometrics*, 39(3): 340, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271149`.

Berk:1998:RDP

[Ber98] Kenneth N. Berk. Regression diagnostic plots in 3-D. *Technometrics*, 40(1):39–47, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271391`.

Bancroft:1993:MPV

[BH93] Bruce A. Bancroft and Gerald R. Hobbs. Mine-product variability estimators with emphasis on the case of coal. *Technometrics*, 35 (4):390–402, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270272`.

Bergman:1997:DEU

[BH97] Bo Bergman and Anders Hynén. Dispersion effects from unreplicated designs in the 2^{k-p} series. *Technometrics*, 39(2):191–198, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270907.

Brush:1990:EOQ

[BHS90] Gary G. Brush, Bruce Hoadley, and Bernard Saperstein. Estimating outgoing quality using the quality measurement plan. *Technometrics*, 32(1):31–41, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269842.

Bieger:1992:BRB

[Bie92] Charles D. Bieger. Book review: *Statistics with STATA* by Lawrence C. Hamilton. *Technometrics*, 34(1):117–118, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269583.

Bilonick:1991:BRB

[Bil91] Richard A. Bilonick. Book review: *An Introduction to Applied Geostatistics* by Edward H. Isaaks; R. Mohan Srivastava. *Technometrics*, 33(4):483–485, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269430.

Bilonick:1992:BRB

[Bil92] Richard A. Bilonick. Book review: *Pierre Gy's Sampling Theory and Sampling Practice* by Francis F. Pitard. *Technometrics*, 34(3):363–364, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270056.

Bilonick:1994:BRB

[Bil94] Richard A. Bilonick. Book review: *Sampling of Heterogeneous and Dynamic Material Systems: Theories of Heterogeneity, Sampling and Homogenizing* by Pierre M. Gy. *Technometrics*, 36(2):218–219, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270238.

Bisgaard:1994:NDR

[Bis94] Søren Bisgaard. A note on the definition of resolution for blocked 2^{k-p} designs. *Technometrics*, 36(3):308–311, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269375.

Bisgaard:1997:DET

[Bis97] Søren Bisgaard. Designing experiments for tolerancing assembled products. *Technometrics*, 39(2):142–152, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270902.

Box:1992:SPMa

[BK92a] George Box and Tim Kramer. Statistical process monitoring and feedback adjustment — a discussion. *Technometrics*, 34(3):251–267, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270028. See discussion [Mac92, Tuc92, VV92, WG92] and response [BK92b].

Box:1992:SPMb

[BK92b] George Box and Tim Kramer. [Statistical Process Monitoring and Feedback Adjustment]: Response. *Technometrics*, 34(3):282–285, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270034. See [BK92a].

Box:1994:SSI

[BL94] George Box and Alberto Luceño. Selection of sampling interval and action limit for discrete feedback adjustment. *Technometrics*, 36(4):369–378, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269952.

Borkowski:1997:DMR

[BL97] John J. Borkowski and James M. Lucas. Designs of mixed resolution for process robustness studies. *Technometrics*, 39(1):63–70, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270773.

Blazek:1992:BRB

[Bla92] Linda W. Blazek. Book review: *Interactive Computer Graphics: Functional, Procedural and Device-Level Methods* by Peter Burger; Duncan Gillies. *Technometrics*, 34(1):105–106, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269567.

Blackwood:1994:BRB

[Bla94] Larry G. Blackwood. Book review: *Factor Analysis in Chemistry* by Edmund R. Malinowski. *Technometrics*, 36(1):115, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269209.

Blischke:1991:BRB

[Bli91] Wallace R. Blischke. Book review: *Practical Statistics* by S. S. Cohen. *Technometrics*, 33(4):489–490, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269437.

Beckman:1987:DMM

[BNC87] Richard J. Beckman, Christopher J. Nachtsheim, and R. Dennis Cook. Diagnostics for mixed-model analysis of variance. *Technometrics*, 29(4):413–426, November 1987. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269452. See corrections[Ano90g].

Bodt:1997:BRB

[Bod97] Barry A. Bodt. Book review: *Engineering Statistics: The Industrial Experience* by B. Ostle; K. Turner; C. Hicks; G. McElrath. *Technometrics*, 39(1):107, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270788.

Boggs:1992:BRB

[Bog92] Brady Boggs. Book review: *No Downtime: Six Steps to Industrial Problem Solving* by L. E. Cook. *Technometrics*, 34(2):234, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269253.

Bonissone:1995:DFL

[Bon95] Piero P. Bonissone. Discussion: Fuzzy logic control technology: A personal perspective. *Technometrics*, 37(3):262–266, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269906.

Booker:1990:BRB

[Boo90] Jane M. Booker. Book review: *Point Process Models with Applications to Safety and Reliability* by W. A. Thompson. *Technometrics*, 32(3):344–345, August 1990. CODEN TCMTA2. ISSN 0040-

1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269117.

Booth:1992:BRB

[Boo92] David E. Booth. Book review: *Time Series* by Maurice Kendall; J. Keith Ord. *Technometrics*, 34(1):118–119, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269585.

Booth:1993:BRB

[Boo93] David E. Booth. Book review: *Statistics, Principles and Methods* by Richard A. Johnson; Gouri K. Bhattacharyya. *Technometrics*, 35(2):237–238, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269691.

Booth:1994:BRBb

[Boo94a] David E. Booth. Book review: *Statistical Methods for SPC and TQM* by Derek Bissell. *Technometrics*, 36(4):420–421, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269959.

Booth:1994:BRBa

[Boo94b] David E. Booth. Book review: *Time Series, Forecasting, Simulation, Applications* by Gareth Janacek; Louise Swift. *Technometrics*, 36(2):217–218, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270237.

Booker:1995:BRB

[Boo95] Jane Booker. Book review: *Poisson Processes* by J. F. C. Kingman. *Technometrics*, 37(1):124, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269173.

Booth:1997:BRB

[Boo97] David E. Booth. Book review: *Time Series Analysis* by James D. Hamilton. *Technometrics*, 39(1):102–103, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270781.

Booth:1998:BRB

[Boo98] David E. Booth. Book review: *Multivariate Statistical Inference and Applications* by Alvin C. Rencher. *Technometrics*, 40 (4):353–354, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270542.

Booth:1999:BRB

[Boo99] David E. Booth. Book review: *Robustness in Statistical Pattern Recognition* by Yurij Kharin. *Technometrics*, 41(4):370–371, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271357.

Borkowski:1994:BRB

[Bor94] John J. Borkowski. Book review: *Optimal Design of Experiments* by Friedrich Pukelsheim. *Technometrics*, 36(2):214–216, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270234.

Borkowski:1995:SPV

[Bor95a] John J. Borkowski. Spherical prediction-variance properties of central composite and Box-Behnken designs. *Technometrics*, 37 (4):399–410, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269732.

Borowiak:1995:BRB

[Bor95b] Dale Borowiak. Book review: *The Theory of Linear Models* by Bent Jorgensen. *Technometrics*, 37(2):228–229, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269624.

Bordley:1997:BRB

[Bor97a] Robert F. Bordley. Book review: *Evaluating Research Articles: From Start to Finish* by Ellen R. Girden. *Technometrics*, 39(4): 431–432, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271521.

Borkowski:1997:BRB

[Bor97b] John J. Borkowski. Book review: *Statistical Tools for Nonlinear Regression* by Sylvie Huet; Annie Bouvier; Marie-Anne Gruet;

Emmanuel Jolivet. *Technometrics*, 39(3):333–334, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271139`.

Borowiak:1997:BRB

[Bor97c] Dale Borowiak. Book review: *Linear Models: A Mean Model Approach* by Barry Kurt Moser. *Technometrics*, 39(4):425–426, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271508`.

Borowiak:1998:BRB

[Bor98] Dale Borowiak. Book review: *Quasi-Likelihood and Its Application* by Christopher C. Heyde. *Technometrics*, 40(4):356, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270545`.

Bossert:1992:BRB

[Bos92] James L. Bossert. Book review: *Introduction to Quality Control* by Kaoru Ishikawa. *Technometrics*, 34(4):494–495, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268958`.

Bowerman:1991:BRB

[Bow91] Bruce L. Bowerman. Book review: *Statistical Design and Analysis of Experiments with Applications to Engineering and Science* by Robert L. Mason; Richard F. Gunst; James L. Hess. *Technometrics*, 33(1):106, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269012`.

Box:1990:CCB

[Box90] George Box. Commentary: [Communications between Statisticians and Engineers/Physical Scientists]. *Technometrics*, 32(3):251–252, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269094`. See [HK90].

Boyer:1990:BRB

[Boy90] John E. Boyer, Jr. Book review: *Statistical Analysis for Engineers: A Computer-Based Approach* by J. Wesley Barnes. *Technometrics*, 32(2):222–223, May 1990. CODEN TCMTA2. ISSN 0040-

1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268870.

Boyles:1996:MPA

[Boy96] Russell A. Boyles. Multivariate process analysis with lattice data. *Technometrics*, 38(1):37–49, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268901.

Bandeen-Roche:1995:BRB

[BR95] Karen J. Bandeen-Roche. Book review: *Quality Control in Analytic Chemistry* by G. Kateman; L. Buydens. *Technometrics*, 37(1):115–116, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269161.

Bresky:1990:BRB

[Bre90] Norman P. Bresky. Book review: *Tools and Methods for the Improvement of Quality* by H. Gitlow; S. Gitlow; A. Oppenheim; R. Oppenheim. *Technometrics*, 32(3):340–341, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269112.

Breiman:1991:MEMa

[Bre91a] Leo Breiman. The $\prod$ method for estimating multivariate functions from noisy data. *Technometrics*, 33(2):125–143, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269038. See discussion [Bre91a, Gu91, HT91] and response [Bre91b].

Breiman:1991:MEMb

[Bre91b] Leo Breiman. [The $\prod$ Method for Estimating Multivariate Functions from Noisy Data]: Response. *Technometrics*, 33(2):156–160, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269042. See [Bre91a].

Breiman:1995:BSR

[Bre95a] Leo Breiman. Better subset regression using the nonnegative garrote. *Technometrics*, 37(4):373–384, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269730.

Bremer:1995:BRB

[Bre95b] Ronald Bremer. Book review: *Outliers in Statistical Data* by Vic Barnett; Toby Lewis. *Technometrics*, 37(1):117–118, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269164.

Bresky:1996:BRB

[Bre96] Norman Bresky. Book review: *Quality Improvement Tools and Techniques* by Peter Mears. *Technometrics*, 38(2):185, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270418.

Breneman:1997:BRB

[Bre97] James E. Breneman. Book review: *Simulation Made Easy, a Manager's Guide* by Charles Harrell; Kerim Tumay. *Technometrics*, 39(4):431, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271518.

Brick:1991:BRB

[Bri91] J. Michael Brick. Book review: *Evaluating the Measurement Process* by D. Wheeler; R. Lyday. *Technometrics*, 33(4):474, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269422.

Brill:1996:BRB

[Bri96] Bob Brill. Book review: *Statistics: Learning in the Presence of Variation* by Robert L. Wardrop. *Technometrics*, 38(4):405–406, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271319.

Brooks:1990:BRBa

[Bro90a] Daniel G. Brooks. Book review: *Linear Programming with Statistical Applications* by Vincent A. Sposito. *Technometrics*, 32 (3):355–356, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269131.

Brooks:1990:BRBb

[Bro90b] Daniel G. Brooks. Book review: *Proceedings of the 20th Symposium on the Interface: Computing Science and Statistics: Computationally Intensive Methods in Statistics* by Edward J. Wegman;

Donald Gantz; John Miller. *Technometrics*, 32(4):465, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270150.

Brooks:1992:BRB

[Bro92] Daniel G. Brooks. Book review: *Scientific Data Analysis: An Introduction to Overdetermined Systems* by Richard L. Branham. *Technometrics*, 34(2):239, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269259.

Brugger:1991:BRB

[Bru91] Richard M. Brugger. Book review: *Defect Prevention: Use of Simple Statistical Tools* by Victor E. Kane. *Technometrics*, 33(1): 117, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269027.

Brugger:1992:BRBa

[Bru92a] Richard M. Brugger. Book review: *Handbook of Statistical Methods in Manufacturing* by Richard Barrett Clements. *Technometrics*, 34(3):360–361, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270052.

Brugger:1992:BRBb

[Bru92b] Richard M. Brugger. Book review: *How to Construct Fractional Factorial Experiments* by Richard F. Gunst; Robert L. Mason. *Technometrics*, 34(4):492–493, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268956.

Brugger:1993:BRBb

[Bru93a] Richard M. Brugger. Book review: *Probability and Its Applications for Engineers* by David H. Evans. *Technometrics*, 35(4): 459–460, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270291.

Brugger:1993:BRBa

[Bru93b] Richard M. Brugger. Book review: *Statistical Methods in Engineering and Quality Assurance* by Peter W. M. John. *Technometrics*, 35(1):91–92, February 1993. CODEN TCMTA2. ISSN 0040-

1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269300`.

Brugger:1994:BRB

[Bru94] Richard M. Brugger. Book review: *Univariate Discrete Distributions* by Norman L. Johnson; Samuel Kotz; Adrienne W. Kemp. *Technometrics*, 36(1):118, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269213`.

Brugger:1995:BRB

[Bru95] Richard M. Brugger. Book review: *Statistics for Engineering Problem Solving* by Stephen B. Vardeman. *Technometrics*, 37(3): 348, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269926`.

Brugger:1996:BRB

[Bru96] Richard M. Brugger. Book review: *How to Perform Skip-Lot and Chain Sampling* by Kenneth S. Stephens. *Technometrics*, 38(1): 82, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268915`.

Brugger:1997:BRB

[Bru97] Richard M. Brugger. Book review: *Fitting Frequency Distributions: Philosophy and Practice, Parts I and II* by David W. Miller. *Technometrics*, 39(2):234–235, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270923`.

Bryson:1992:BRB

[Bry92] Maurice C. Bryson. Book review: *Statistical Analysis of Reliability and Life-Testing Models* by Lee J. Bain; Max Engelhardt. *Technometrics*, 34(4):486–487, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268948`.

Bryson:1999:BRB

[Bry99] Maurice Bryson. Book review: *Probability, Statistics, and Reliability for Engineers* by Bilal M. Ayyub; Richard H. McCuen. *Technometrics*, 41(2):172–173, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270740`.

Bisgaard:1997:DAP

[BS97] Søren Bisgaard and David M. Steinberg. The design and analysis of $2^{k-p} \times s$ prototype experiments. *Technometrics*, 39(1):52–62, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270772.

Bingham:1999:MAT

[BS99] Derek Bingham and Randy R. Sitter. Minimum-aberration two-level fractional factorial split-plot designs. *Technometrics*, 41 (1):62–70, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270995.

Beckman:1989:TST

[BT89] Richard J. Beckman and Gary L. Tietjen. Two-sided tolerance limits for balanced random-effects ANOVA models. *Technometrics*, 31(2):185–197, May 1989. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268816. See correction [BT98].

Beckman:1998:CTS

[BT98] Richard J. Beckman and Gary L. Tietjen. Correction: "Two-sided tolerance limits for balanced random-effects ANOVA models" [*Technometrics* **31** (1989), no. 2, 185–197; MR1007294 (90f:62230)]. *Technometrics*, 40(3):269, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271208. See [BT89].

Buckingham:1990:BRB

[Buc90] Janet Buckingham. Book review: *Dynamic Graphics for Statistics* by William S. Cleveland; Marylyn E. McGill. *Technometrics*, 32 (4):446–447, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270124.

Bulmahn:1991:BRB

[Bul91] Barbara J. Bulmahn. Book review: *How to Think about Statistics* by John L. Phillips. *Technometrics*, 33(1):112, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269018.

Bulmahn:1996:BRB

[Bul96] Barbara J. Bulmahn. Book review: *Introductory Statistics: A Modelling Approach* by J. K. Lindsey. *Technometrics*, 38(2):190, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270427.

Burdick:1991:BRB

[Bur91] Donald Burdick. Book review: *Multivariate Chemometrics in QSAR: A Dialogue* by Peter P. Mager. *Technometrics*, 33(1): 119–120, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269031.

Bzik:1997:BRB

[Bzi97] Thomas J. Bzik. Book review: *Statistical Methods for Engineers and Scientists* by R. M. Bethea; B. S. Duran; T. L. Boullion. *Technometrics*, 39(2):229, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270915.

Burdick:1996:CZM

[BZM96] Richard K. Burdick, Leping Zhou, and Thomas Mathew. Comment on Zhou and Mathew (1994). *Technometrics*, 38(1):92–93, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268933. See [ZM94].

Caby:1994:BRB

[Cab94] Errol Caby. Book review: *Six Sigma Producibility Analysis and Process Characterization* by Mikel J. Harry; J. Ronald Lawson. *Technometrics*, 36(1):122, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269219.

Caby:1998:BRB

[Cab98] Errol Caby. Book review: *Time Series and Dynamic Models* by Christian Gourieroux; Alain Monfort. *Technometrics*, 40(2):158, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270656.

Calvin:1994:BRB

[Cal94] James A. Calvin. Book review: *Hierarchical Linear Models: Applications and Data Analysis Methods* by Anthony S. Bryk; Stephen

W. Raudenbush. *Technometrics*, 36(1):116–117, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269211.

Calvin:1998:BRB

[Cal98] James A. Calvin. Book review: *Regression Models for Categorical and Limited Dependent Variables* by J. Scott Long. *Technometrics*, 40(1):80–81, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271407.

Campbell:1990:BRB

[Cam90] Katherine Campbell. Book review: *Exploration-Geochemical Data Analysis with the IBM PC* by George S. Koch. *Technometrics*, 32(3):358, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269135.

Campbell:1996:BRB

[Cam96] Katherine Campbell. Book review: *Introduction to Disjunctive Kriging and Non-Linear Geostatistics* by Jacques Rivoirard. *Technometrics*, 38(2):187–188, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270423.

Campbell:1998:BRB

[Cam98] Katherine Campbell. Book review: *Setting Environmental Standards: The Statistical Approach to Handling Uncertainty and Variation* by V. Barnett; A. O'Hagan. *Technometrics*, 40(3):262, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271192.

Carey:1990:BRB

[Car90a] Michele Boulanger Carey. Book review: *A Primer of Reliability Theory* by D. L. Grosh. *Technometrics*, 32(3):345–346, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269118.

Carlson:1990:BRB

[Car90b] Richard R. Carlson. Book review: *What Every Engineer Should Know about Quality Control* by Thomas Pyzdek. *Technometrics*, 32(3):342–343, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269114.

Carlson:1992:BRB

[Car92] Richard R. Carlson. Book review: *What Every Manager Should Know about Quality* by Thomas Pyzdek. *Technometrics*, 34(4): 495–496, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268959.

Carlson:1993:BRB

[Car93] Richard R. Carlson. Book review: *Inspection Errors for Attributes in Quality Control* by Norman L. Johnson; Samuel Kotz; Xishi Wu. *Technometrics*, 35(2):232, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269682.

Carniello:1995:BRB

[Car95] Michael L. Carniello. Book review: *Analysis of Two-Way Layouts* by John Mandel. *Technometrics*, 37(4):461, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269745.

Carpenter:1996:BRB

[Car96] Mark Carpenter. Book review: *Reliability Engineering Bible* by Bryan Dodson; Dennis Nolan. *Technometrics*, 38(4):406–407, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271320.

Carpenter:1997:BRB

[Car97] Mark Carpenter. Book review: *Survival Analysis: A Self-Learning Text* by David G. Kleinbaum. *Technometrics*, 39(2):228–229, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270914.

Christensen:1993:TPA

[CB93] Ronald Christensen and Larry G. Blackwood. Tests for precision and accuracy of multiple measuring devices. *Technometrics*, 35 (4):411–420, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270274.

Cutler:1994:AA

[CB94] Adele Cutler and Leo Breiman. Archetypal analysis. *Technometrics*, 36(4):338–347, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269949`.

Crone:1995:SAM

[CC95] L. J. Crone and D. S. Crosby. Statistical applications of a metric on subspaces to satellite meteorology. *Technometrics*, 37(3):324–328, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269916`.

Chen:1999:RTE

[CC99] Shun-Yi Chen and Hubert J. Chen. A range test for the equivalency of means under unequal variances. *Technometrics*, 41(3):250–260, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270569`.

Carter:1990:LSC

[CCC90] Walter H. Carter, Jr., Vernon M. Chinchilli, and Eleanor D. Campbell. A large-sample confidence region useful in characterizing the stationary point of a quadratic response surface. *Technometrics*, 32(4):425–435, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270122`.

Crawford:1992:MLC

[CDKS92] Sybil L. Crawford, Morris H. DeGroot, Joseph B. Kadane, and Mitchell J. Small. Modeling lake-chemistry distributions: Approximate Bayesian methods for estimating a finite-mixture model. *Technometrics*, 34(4):441–453, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268943`.

Capilla:1999:ISE

[CFRH99] Carmen Capilla, Alberto Ferrer, Rafael Romero, and Angel Hualda. Integration of statistical and engineering process control in a continuous polymerization process. *Technometrics*, 41(1):14–28, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270991`.

Carrillo-Gamboa:1992:MEM

[CGG92] Olivia Carrillo-Gamboa and Richard F. Gunst. Measurement-error-model collinearities. *Technometrics*, 34(4):454–464, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268944`.

Chipman:1996:BAO

[CH96a] Hugh Chipman and Michael Hamada. Bayesian analysis of ordered categorical data from industrial experiments. *Technometrics*, 38(1):1–10, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268898`.

Chipman:1996:DFB

[CH96b] Hugh A. Chipman and Michael S. Hamada. Discussion: Factor-based or effect-based modeling? implications for design. *Technometrics*, 38(4):317–320, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271299`.

Chang:1992:BRB

[Cha92] Phil T. Chang. Book review: *Improving Quality Through Planned Experimentation* by Ronald D. Moen; Thomas W. Nolan; Lloyd P. Provost. *Technometrics*, 34(4):491–492, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268954`.

Chaubey:1993:BRB

[Cha93] Yogendra P. Chaubey. Book review: *Resampling-Based Multiple Testing: Examples and Methods for p-Value Adjustment* by Peter H. Westfall; S. Stanely Young. *Technometrics*, 35(4):450–451, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270279`.

Champ:1995:BRB

[Cha95] Charles W. Champ. Book review: *Process Capability Indices* by Samuel Kotz; Norman L. Johnson. *Technometrics*, 37(2):233, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269631`.

Chang:1998:BRB

[Cha98] Joseph T. Chang. Book review: *Probability and Statistical Inference* by Robert Bartoszynski; Magdalena Niewiadomska-Bugaj. *Technometrics*, 40(4):354–356, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270544.

Caspary:1990:DAS

[CHB90] W. F. Caspary, W. Haen, and H. Borutta. Deformation analysis by statistical methods. *Technometrics*, 32(1):49–57, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269844.

Chernick:1991:BRB

[Che91] Michael R. Chernick. Book review: *Statistical Methods in Engineering and Manufacturing* by John E. Brown. *Technometrics*, 33(3):356, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268787.

Chen:1992:BRB

[Che92] Chung Chen. Book review: *Quantitative Forecasting Methods* by Nicholas R. Farnum; LaVerne W. Stanton. *Technometrics*, 34(3):358, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270047.

Chen:1994:BRB

[Che94] Hanfeng Chen. Book review: *Data Analysis: An Introduction* by Jeffrey A. Witmer. *Technometrics*, 36(4):427, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269967.

Cheeseman:1995:DFT

[Che95] Peter Cheeseman. Discussion: Fuzzy thinking. *Technometrics*, 37(3):282–283, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269910.

Chen:1998:BRB

[Che98] Hanfeng Chen. Book review: *Applying Generalized Linear Models* by James K. Lindsey. *Technometrics*, 40(2):156–157, May

1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270654.

Chiu:1991:BRB

[Chi91] Shean-Tsong Chiu. Book review: *Regression Analysis: Theory, Methods, and Applications* by Ashish Sen; Muni Srivastava. *Technometrics*, 33(4):479–480, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269427.

Christensen:1997:BRB

[Chr97] Ronald Christensen. Book review: *Multiple Comparisons: Theory and Methods* by Jason C. Hsu. *Technometrics*, 39(2):232–233, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270920.

Chuang:1991:BRB

[Chu91] Alice Chuang. Book review: *Time Series Analysis: Univariate and Multivariate Methods* by William W. S. Wei. *Technometrics*, 33(1):108–109, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269015.

Chipman:1997:BVS

[CHW97] H. Chipman, M. Hamada, and C. F. J. Wu. A Bayesian variable-selection approach for analyzing designed experiments with complex aliasing. *Technometrics*, 39(4):372–381, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271501.

Cheng:1993:COF

[CL93] Ching-Shui Cheng and Chang Chung Li. Constructing orthogonal fractional factorial designs when some factor-level combinations are debarred. *Technometrics*, 35(3):277–283, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269520.

Clyde:1994:BRB

[Cly94] Merlise Clyde. Book review: *The Statistical Exorcist: Dispelling Statistics Anxiety* by M. Hollander; F. Proschan. *Technometrics*, 36(3):330, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269394.

Coleman:1993:SAPb

[CM93a] David E. Coleman and Douglas C. Montgomery. [A Systematic Approach to Planning for a Designed Industrial Experiment]: Response. *Technometrics*, 35(1):25–27, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269285. See [CM93b].

Coleman:1993:SAPa

[CM93b] David E. Coleman and Douglas C. Montgomery. A systematic approach to planning for a designed industrial experiment. *Technometrics*, 35(1):1–12, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269280. See discussion [Gun93, Hah93, HO93, LST93] and response [CM93a].

Chou:1999:SNP

[CM99] Youn-Min Chou and Robert L. Mason. [Simultaneous Nonparametric Prediction Limits]: Discussion. *Technometrics*, 41(2):102–103, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270722. See [DM99a].

Coakley:1994:BRB

[Coa94] Kevin J. Coakley. Book review: *Statistical Challenges in Modern Astronomy* by Eric D. Feigelson; G. Jogesh Babu. *Technometrics*, 36(3):328, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269390.

Coburn:1991:BRB

[Cob91] Timothy C. Coburn. Book review: *Spatial Data Analysis by Example (Vol. 2: Categorical and Directional Data)* by Graham J. G. Upton; Bernard Fingleton. *Technometrics*, 33(1):119, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269030.

Cohen:1992:BRB

[Coh92] Jonathan Cohen. Book review: *Statistical Methods in Soil and Land Resource Survey* by R. Webster; M. A. Oliver. *Technometrics*, 34(4):497–498, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268961.

Coleman:1992:BRB

[Col92] David Coleman. Book review: *How to Test Normality and Other Distributional Assumptions* by Samuel S. Shapiro. *Technometrics*, 34(3):359–360, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270050`.

Coleman:1993:BRB

[Col93] David E. Coleman. Book review: *Statistical Process Control: Theory and Practice* by G. Barrie Wetherill; Don W. Brown. *Technometrics*, 35(1):89–90, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269298`.

Cook:1993:EPR

[Coo93] R. Dennis Cook. Exploring partial residual plots. *Technometrics*, 35(4):351–362, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270269`.

Cook:1996:AVP

[Coo96a] R. Dennis Cook. Added-variable plots and curvature in linear regression. *Technometrics*, 38(3):275–278, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270611`.

Coons:1996:BRB

[Coo96b] Lori Coons. Book review: *Quality up, Costs down: A Manager's Guide to Taguchi Methods and QFD* by William E. Eureka; Nancy E. Ryan. *Technometrics*, 38(2):183–184, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270415`.

Cox:1993:BRB

[Cox93] Dennis D. Cox. Book review: *Modal and Spectrum Analysis: Data Dependent Systems in State Space* by Sudhakar M. Pandit. *Technometrics*, 35(2):228, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269677`.

Cox:1996:BRB

[Cox96] Dennis D. Cox. Book review: *Spectral Analysis for Physical Applications: Multitaper and Conventional Univariate Techniques* by

Donald B. Percival; Andrew T. Walden. *Technometrics*, 38(3): 294, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270624.

Christensen:1992:CDD

[CPJ92] Ronald Christensen, Larry M. Pearson, and Wesley Johnson. Case-deletion diagnostics for mixed models. *Technometrics*, 34 (1):38–45, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269550.

Carroll:1991:PTI

[CR91] Raymond J. Carroll and David Ruppert. Prediction and tolerance intervals with transformation and/or weighting. *Technometrics*, 33(2):197–210, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269046.

Chang:1993:IES

[CR93] Myron N. Chang and P. V. Rao. Improved estimation of survival functions in the new-better-than-used class. *Technometrics*, 35(2):192–203, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269664.

Coleman:1996:ASM

[CR96] David Coleman and Philip Ramsey. [Applications of Statistical Methods to Nondestructive Evaluation]: Discussion. *Technometrics*, 38(2):117–121, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270401. See [OM96a].

Cornell:1998:GMM

[CR98] John A. Cornell and Phillip J. Ramsey. A generalized mixture model for categorized-components problems with an application to a photoresist-coating experiment. *Technometrics*, 40(1):48–61, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271392.

Crawford:1994:BRB

[Cra94] Sybil L. Crawford. Book review: *Analysis of Quantal Response Data* by B. J. T. Morgan. *Technometrics*, 36(1):117–118, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269212.

Cressie:1997:JPI

[Cre97] Noel Cressie. Jackknifing in the presence of inhomogeneity. *Technometrics*, 39(1):45–51, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270771.

Crowder:1992:SMS

[Cro92] Stephen V. Crowder. An SPC model for short production runs: Minimizing expected cost. *Technometrics*, 34(1):64–73, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269553.

Crosby:1994:BRB

[Cro94] Teri Crosby. Book review: *How to Detect and Handle Outliers* by Boris Iglewicz; David C. Hoaglin. *Technometrics*, 36(3):315–316, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269377.

Crosby:1999:BRB

[Cro99] Teri A. Crosby. Book review: *Into Statistics: A Guide to Understanding Statistical Concepts in Engineering and the Sciences* by Peter J. Smith. *Technometrics*, 41(4):373–374, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271363.

Cryer:1990:BRB

[Cry90] Jonathan D. Cryer. Book review: *The Statistical Theory of Linear Systems* by E. J. Hannan; Manfred Deistler. *Technometrics*, 32(1):111, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269869.

Carroll:1992:DNH

[CS92] R. J. Carroll and C. H. Spiegelman. Diagnostics for nonlinearity and heteroscedasticity in errors-in-variables regression. *Technometrics*, 34(2):186–196, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269234.

Cohen:1993:ETI

[CS93] Arthur Cohen and H. B. Sackrowitz. Evaluating tests for increasing intensity of a Poisson process. *Technometrics*, 35(4):446–448, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270277.

Cucchiara:1992:BRB

[Cuc92] Andrew Cucchiara. Book review: *Applied Logistic Regression* by D. Hosmer; S. Lemeshow. *Technometrics*, 34(3):358–359, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270048.

Cheng:1997:RC

[CV97] Chi-Lun Cheng and John W. Van Ness. Robust calibration. *Technometrics*, 39(4):401–411, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271504.

Carey:1997:RTB

[CWWR97] V. J. Carey, E. E. Walters, C. G. Wager, and B. A. Rosner. Resistant and test-based outlier rejection: Effects on Gaussian one- and two-sample inference. *Technometrics*, 39(3):320–330, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271136.

Czitrom:1992:BRB

[Czi92] Veronica Czitrom. Book review: *Experiments with Mixtures* by John A. Cornell. *Technometrics*, 34(1):104–105, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269566.

Dalal:1990:SCB

[Dal90] S. R. Dalal. Simultaneous confidence bands for regression with unknown unequal variances. *Technometrics*, 32(2):173–186, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268861.

DasGupta:1993:BRB

[Das93] A. DasGupta. Book review: *Sense and Nonsense of Statistical Inference* by Chamont Wang. *Technometrics*, 35(4):462, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270295.

Davis:1999:BRB

[Dav99] Charles B. Davis. Book review: *Compliance Quantified: An Introduction to Data Verification* by Rudolf Avenhaus; Morton John Canty. *Technometrics*, 41(2):174, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270742`.

delCastillo:1999:BRB

[dC99] Enrique del Castillo. Book review: *SPC Methods for Quality Improvement* by Charles P. Quesenberry. *Technometrics*, 41(2):167–168, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270733`.

Draper:1994:IDF

[DDPG94] Norman R. Draper, Timothy P. Davis, Lourdes Pozueta, and Daniel M. Grove. Isolation of degrees of freedom for Box–Behnken designs. *Technometrics*, 36(3):283–291, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269372`.

Deal:1991:BRB

[Dea91] R. B. Deal, Jr. Book review: *Systems Analysis Using Simulation and Markov Models* by John R. Clymer. *Technometrics*, 33(3):371–372, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268804`.

Deal:1994:BRB

[Dea94] R. B. Deal. Book review: *Simulation Modeling and Analysis* by Averill M. Law; W. David Kelton. *Technometrics*, 36(4):429–430, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269971`.

Dean:1995:BRB

[Dea95] Angela Dean. Book review: *Advanced Linear Models: Theory and Applications* by Song-Gui Wang; Shein-Chung Chow. *Technometrics*, 37(1):119–120, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269167`.

Dean:1996:BRB

[Dea96] Angela M. Dean. Book review: *Linear Statistical Models* by James Stapleton. *Technometrics*, 38(4):402–403, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271313.

Dean:1997:BRB

[Dea97] Angela Dean. Book review: *Methods and Applications of Linear Models* by Ronald R. Hocking. *Technometrics*, 39(3):332–333, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271138.

Dehnad:1990:BRB

[Deh90] Khosrow Dehnad. Book review: *Decision Analysis: A Bayesian Approach* by J. Q. Smith. *Technometrics*, 32(2):232–233, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268883.

Derringer:1990:BRB

[Der90] George C. Derringer. Book review: *The Design of Experiments: Statistical Principles for Practical Application* by R. Mead. *Technometrics*, 32(4):448, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270125.

Deutsch:1996:CSH

[Deu96] Clayton V. Deutsch. Constrained smoothing of histograms and scatterplots with simulated annealing. *Technometrics*, 38(3):266–274, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270610.

DeVeaux:1999:BRB

[DeV99] Richard D. DeVeaux. Book review: *Applied Smoothing Techniques for Data Analysis* by Adrian W. Bowman; Adelchi Azzalini. *Technometrics*, 41(3):263, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270572.

Dowling:1997:SIGa

[DGTZ97a] M. M. Dowling, P. M. Griffin, K.-L. Tsui, and C. Zhou. Statistical issues in geometric feature inspection using coordinate measuring machines. *Technometrics*, 39(1):3–17, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270764. See discussion [Hul97, WH97, PE97] and reply [DGTZ97b].

Dowling:1997:SIGb

[DGTZ97b] M. M. Dowling, P. M. Griffin, K.-L. Tsui, and C. Zhou. [Statistical Issues in Geometric Feature Inspection Using Coordinate Measuring Machines]: Reply. *Technometrics*, 39(1):24, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270768. See [DGTZ97a].

Doksum:1992:MVS

[DH92] Kjell A. Doksum and Arnljot Hóyland. Models for variable-stress accelerated life testing experiments based on Wiener processes and the inverse Gaussian distribution. *Technometrics*, 34(1):74–82, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269554.

Dickey:1991:BRB

[Dic91] D. A. Dickey. Book review: *The Analysis of Time Series: An Introduction* by C. Chatfield. *Technometrics*, 33(3):363–364, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268794.

Dickey:1997:BRB

[Dic97] David A. Dickey. Book review: *Introduction to Statistical Time Series* by Wayne A. Fuller. *Technometrics*, 39(1):103–104, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270782.

Diegert:1992:BRB

[Die92] Kathleen Diegert. Book review: *Industrial Quality and Reliability* by G. Barnard; G. Box; D. Cox; A. Seheult; B. Silverman. *Technometrics*, 34(3):360, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270051.

DuMouchel:1994:SBM

[DJ94] William DuMouchel and Bradley Jones. A simple Bayesian modification of *D*-optimal designs to reduce dependence on an assumed model. *Technometrics*, 36(1):37–47, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269197.

Draper:1990:CBT

[DL90a] Norman R. Draper and Dennis K. J. Lin. Connections between two-level designs of resolutions III* and V. *Technometrics*, 32 (3):283–288, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269105.

Draper:1990:SRS

[DL90b] Norman R. Draper and Dennis K. J. Lin. Small response-surface designs. *Technometrics*, 32(2):187–194, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268862.

Dalal:1998:FCD

[DM98] Siddhartha R. Dalal and Colin L. Mallows. Factor-covering designs for testing software. *Technometrics*, 40(3):234–243, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271179.

Davis:1999:SNPa

[DM99a] Charles B. Davis and Roger J. McNichols. Simultaneous non-parametric prediction limits. *Technometrics*, 41(2):89–101, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270721. See discussion [CM99, Gib99, Gil99, Van99] and response [DM99b].

Davis:1999:SNPb

[DM99b] Charles B. Davis and Roger J. McNichols. [Simultaneous Non-parametric Prediction Limits]: Response. *Technometrics*, 41(2): 108–112, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270726. See [DM99a].

Dobrow:1996:BRB

[Dob96] Robert P. Dobrow. Book review: *Probability Models and Applications* by Ingram Olkin; Leon J. Gleser; Cyrus Derman. *Technometrics*, 38(4):408–409, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271323.

Doganaksoy:1993:BRB

[Dog93] Necip Doganaksoy. Book review: *Process Improvement in the Electronics Industry* by Yefim Fasser; Donald Brettner. *Technometrics*, 35(3):334–335, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269542`.

Doganaksoy:1999:BRB

[Dog99] Necip Doganaksoy. Book review: *Quality and Reliability of Technical Systems: Theory, Practice, Management* by Alessandro Birolini. *Technometrics*, 41(2):171–172, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270739`.

Domangue:1990:BRB

[Dom90] Rickie J. Domangue. Book review: *How to Think about Statistics* by John L. Phillips. *Technometrics*, 32(1):94, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269848`.

Donnelly:1990:BRB

[Don90] Patrick P. Donnelly. Book review: *Problem Solving: A Statistician's Guide* by Christopher Chatfield. *Technometrics*, 32(3):349–350, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269123`.

Dovich:1993:BRB

[Dov93] Robert A. Dovich. Book review: *Statistical Techniques for Data Analysis* by John Keenan Taylor. *Technometrics*, 35(3):332, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269538`.

Downing:1994:UCS

[Dow94] Darryl J. Downing. [The Use of Conditional Simulation in Nuclear-Waste-Site Performance Assessment]: Discussion. *Technometrics*, 36(2):147–149, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270223`. See [Got94c].

Downing:1995:BRB

[Dow95] Darryl J. Downing. Book review: *Univariate Tests for Time Series Models* by Jeff B. Cromwell; Walter C. Labys; Michel Terraza. *Technometrics*, 37(3):346, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269923.

Draper:1990:ALR

[DP90] Norman R. Draper and Friedrich Pukelsheim. Another look at rotatability. *Technometrics*, 32(2):195–202, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268863.

Domangue:1991:SOE

[DP91] Rickie Domangue and Steven C. Patch. Some omnibus exponentially weighted moving average statistical process monitoring schemes. *Technometrics*, 33(3):299–313, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268782.

Durham:1997:CDM

[DP97] S. D. Durham and W. J. Padgett. Cumulative damage models for system failure with application to carbon fibers and composites. *Technometrics*, 39(1):34–44, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270770. See correction [Ano98e].

Draper:1993:MDF

[DPL+93] N. R. Draper, P. Prescott, S. M. Lewis, A. M. Dean, P. W. M. John, and M. G. Tuck. Mixture designs for four components in orthogonal blocks. *Technometrics*, 35(3):268–276, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269519. See correction [DPL+94] and comments [SDP+95]..

Draper:1994:CMD

[DPL+94] N. R. Draper, P. Prescott, S. M. Lewis, A. M. Dean, P. W. M. John, and M. G. Tuck. Correction: “Mixture designs for four components in orthogonal blocks” [*Technometrics* **35** (1993), no. 3, 268–276; Draper:1993:MDF (94c:62110)]. *Technometrics*, 36 (2):234, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270264. See [DPL+93].

Drew:1991:BRB

[Dre91] James H. Drew. Book review: *Modern Data Analysis: A First Course in Applied Statistics* by Lawrence C. Hamilton. *Technometrics*, 33(4):487–488, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269434.

Driscoll:1991:BRB

[Dri91] Michael F. Driscoll. Book review: *Genstat 5: A Second Course* by Pete Digby; Nick Galwey; Peter Lane. *Technometrics*, 33(3):371, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268803.

Driscoll:1992:BRB

[Dri92] Michael F. Driscoll. Book review: *Applied Statistics: A Handbook of GENSTAT Analyses* by E. J. Snell; H. R. Simpson. *Technometrics*, 34(4):499, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268963.

Doganaksoy:1993:CAC

[DS93] Necip Doganaksoy and Josef Schmee. Comparisons of approximate confidence intervals for distributions used in life-data analysis. *Technometrics*, 35(2):175–184, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269662.

deVeaux:1998:PIN

[DSSU98] Richard D. De Veaux, Jennifer Schumi, Jason Schweinsberg, and Lyle H. Ungar. Prediction intervals for neural networks via nonlinear regression. *Technometrics*, 40(4):273–282, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270528.

Dunn:1990:BRB

[Dun90] Mark R. Dunn. Book review: *Exploring Statistics with the IBM PC* by David P. Doane. *Technometrics*, 32(3):350, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269124.

Dunn:1996:BRB

[Dun96] Mark R. Dunn. Book review: *Achieving Quality Improvement: A Practical Guide* by Roland Caulcutt. *Technometrics*, 38(2):183, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270413.

Dunn:1997:BRB

[Dun97] Mark R. Dunn. Book review: *Introduction to Modern Statistical Quality Control and Management* by J. A. Swift. *Technometrics*, 39(2):228, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270913.

deVeaux:1992:BRB

[dV92] Richard D. de Veaux. Book review: *Generalized Additive Models* by Trevor J. Hastie; Robert J. Tibshirani. *Technometrics*, 34(2):225–226, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269240.

deVeaux:1993:BRB

[dV93] Richard D. de Veaux. Book review: *Statistics for Spatial Data* by Noel A. C. Cressie. *Technometrics*, 35(3):322–323, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269525.

deVeaux:1996:NNA

[dVU96] Richard D. de Veaux and Lyle H. Ungar. [Neural Networks in Applied Statistics]: Discussion. *Technometrics*, 38(3):215–218, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270602. See [Ste96a].

Easterling:1990:BRB

[Eas90] Robert G. Easterling. Book review: *Prescriptions for Working Statisticians* by Albert Madansky. *Technometrics*, 32(2):218–219, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268865.

Easterling:1999:BRB

[Eas99] Robert G. Easterling. Book review: *Statistics and Truth* by C. R. Rao. *Technometrics*, 41(1):72–73, February 1999. CODEN

TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270996.

Edgeman:1992:BRB

[Edg92] Rick L. Edgeman. Book review: *Engineering Quality by Design: Interpreting the Taguchi Approach* by Thomas B. Barker. *Technometrics*, 34(2):230, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269247.

Edgeman:1998:BRB

[Edg98] Rick L. Edgeman. Book review: *Statistical Methods for Industrial Process Control* by David Drain. *Technometrics*, 40(2):154, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270649.

Engel:1996:GLM

[EH96] Jan Engel and A. Freek Huele. A generalized linear modeling approach to robust design. *Technometrics*, 38(4):365–373, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271307.

Eltinge:1990:BRB

[Elt90] John L. Eltinge. Book review: *Applied Time Series Analysis for Business and Economic Forecasting* by Sufi M. Nazem. *Technometrics*, 32(1):101–102, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269859.

Escobar:1995:PAL

[EM95] Luis A. Escobar and William Q. Meeker, Jr. Planning accelerated life tests with two or more experimental factors. *Technometrics*, 37(4):411–427, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269733.

Escobar:1999:SPB

[EM99] Luis A. Escobar and William Q. Meeker. Statistical prediction based on censored life data. *Technometrics*, 41(2):113–124, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270727.

Emptage:1992:BRB

[Emp92] Michael Emptage. Book review: *An Introduction to Generalized Linear Models* by A. J. Dobson. *Technometrics*, 34(2):224–225, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269239.

Emptage:1993:BRB

[Emp93] Michael R. Emptage. Book review: *Sample Size Choice: Charts for Experiments with Linear Models* by R. E. Odeh; M. Fox. *Technometrics*, 35(2):234–235, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269687.

Emptage:1997:BRB

[Emp97] Michael R. Emptage. Book review: *Design and Optimization in Organic Synthesis; Experimental Design and Chemical Synthesis* by Rolf Carlson. *Technometrics*, 39(2):231, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270918. See correction [Ano97f].

Emptage:1999:BRB

[Emp99] Michael Emptage. Book review: *Interaction Effects in Factorial Analysis of Variance* by James Jaccard. *Technometrics*, 41(1):80, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271008. See correction [Ano99e].

Erkanli:1998:BCC

[EMS98] Alaattin Erkanli, Thomas A. Mazzuchi, and Refik Soyer. Bayesian computations for a class of reliability growth models. *Technometrics*, 40(1):14–23, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271389.

Easterling:1991:SBC

[EMSD91] Robert G. Easterling, Mainak Mazumdar, Floyd W. Spencer, and Kathleen V. Diegert. System-based component-test plans and operating characteristics: Binomial data. *Technometrics*, 33(3):287–298, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268781.

Ensor:1995:BRB

[Ens95] Katherine B. Ensor. Book review: *Time Series Models* by Andrew C. Harvey. *Technometrics*, 37(4):464–465, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269749.

Evans:1994:TAA

[ES94] J. C. Evans and S. J. Schwager. A test of additional accuracy for selecting groups of allocation variables. *Technometrics*, 36(2): 202–211, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270232.

Efromovich:1996:ANB

[ET96] Sam Efromovich and Edward V. Thomas. Application of nonparametric binary regression to evaluate the sensitivity of explosives. *Technometrics*, 38(1):50–58, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268902.

Eubank:1990:BRB

[Eub90] Randall Eubank. Book review: *Nonparametric Regression Analysis of Longitudinal Data* by Hans-Georg Müller. *Technometrics*, 32(2):220–221, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268867.

Eubank:1993:BRB

[Eub93] R. L. Eubank. Book review: *Applied Nonparametric Regression* by Wolfgang Härdle. *Technometrics*, 35(2):225–226, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269674.

Fairley:1991:BRB

[Fai91] David Fairley. Book review: *Robust Regression: Analysis and Applications* by K. D. Lawrence; J. L. Arthur. *Technometrics*, 33(2):239–240, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269052.

Fairley:1994:BRB

[Fai94] David Fairley. Book review: *Alternative Methods of Regression* by David Birkes; Yadolah Dodge. *Technometrics*, 36(3):319–321, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269381.

Faltin:1999:BRB

[Fal99] Frederick W. Faltin. Book review: *Statistical Control by Monitoring and Freedback Adjustment* by George Box; Alberto Luceño. *Technometrics*, 41(2):167, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270732.

Famoye:1995:BRB

[Fam95] Felix Famoye. Book review: *Continuous Univariate Distributions, Volume 1* by Norman L. Johnson; Samuel Kotz; N. Balakrishnan. *Technometrics*, 37(4):466, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269751.

Famoye:1997:BRB

[Fam97] Felix Famoye. Book review: *Seeing through Statistics* by Jessica M. Utts. *Technometrics*, 39(1):108–109, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270791.

Famoye:1999:BRB

[Fam99] Felix Famoye. Book review: *Improving Efficiency by Shrinkage* by Marvin H. J. Gruber. *Technometrics*, 41(2):176, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270745.

Farnsworth:1990:BRB

[Far90] David L. Farnsworth. Book review: *Elementary Statistics* by Mario F. Triola. *Technometrics*, 32(4):456–457, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270136.

Farnsworth:1992:BRB

[Far92] David L. Farnsworth. Book review: *Introduction to Statistics: The Nonparametric Way* by Gottfried E. Noether. *Technometrics*, 34(2):240, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269261.

Farnsworth:1993:BRB

[Far93] David L. Farnsworth. Book review: *A First Course in Order Statistics* by Barry C. Arnold; N. Balakrishnan; H. N. Nagaraja. *Technometrics*, 35(4):452, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270281.

Faraway:1997:RAF

[Far97] Julian J. Faraway. Regression analysis for a functional response. *Technometrics*, 39(3):254–261, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271130.

Fuchs:1994:MPC

[FB94] Camil Fuchs and Yoav Benjamini. Multivariate profile charts for statistical process control. *Technometrics*, 36(2):182–195, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270230.

Fedorov:1996:FDR

[Fed96] Valerii Fedorov. [Follow-Up Designs to Resolve Confounding in Multifactor Experiments]: Discussion. *Technometrics*, 38(4):321–322, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271300. See [MSB96a].

Fellner:1994:RLD

[Fel94] William H. Fellner. [Run-Length Distributions of Special-Cause Control Charts for Correlated Processes]: Discussion. *Technometrics*, 36(1):22–23, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269194. See [WMP94a].

Frank:1993:SVSb

[FF93a] Ildiko E. Frank and Jerome H. Friedman. [A Statistical View of Some Chemometrics Regression Tools]: Response. *Technometrics*, 35(2):143–148, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269659. See [FF93b].

Frank:1993:SVSa

[FF93b] Ildiko E. Frank and Jerome H. Friedman. A statistical view of some chemometrics regression tools. *Technometrics*, 35(2):109–135, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269656. See discussion [HM93].

Faltin:1990:EWM

[FHT90] Frederick W. Faltin, Gerald J. Hahn, and William T. Tucker. [Exponentially Weighted Moving Average Control Schemes: Properties and Enhancements]: Discussion. *Technometrics*, 32(1):19–20, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269838. See [LS90b].

Freeny:1995:GAL

[FL95] Anne E. Freeny and James M. Landwehr. Graphical analysis for a large designed experiment. *Technometrics*, 37(1):1–14, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269145.

Filliben:1997:SAA

[FL97] James J. Filliben and Ker-Chau Li. A systematic approach to the analysis of complex interaction patterns in two-level factorial designs. *Technometrics*, 39(3):286–297, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271133.

Farebrother:1992:CMQ

[FMQ92] R. W. Farebrother, Ray L. Marr, and Charles P. Quesenberry. Comments on Marr and Quesenberry (1991). *Technometrics*, 34 (3):375–376, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270076. See [MQ91] and correction [Ano93f].

Fotopoulos:1995:BRB

[Fot95] Stergios B. Fotopoulos. Book review: *Optimization Techniques in Statistics* by Jagdish S. Rustagi. *Technometrics*, 37(4):466–467, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269752.

Fotopoulos:1996:BRB

[Fot96] Stergios B. Fotopoulos. Book review: *Stochastic Modeling and Analysis of Manufacturing Systems* by David D. Yao. *Technometrics*, 38(1):84–85, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268919.

Fox:1991:BRB

[Fox91] Eric P. Fox. Book review: *Bayesian Statistics 3* by J. Bernardo; M. DeGroot; D. Lindley; A. Smith. *Technometrics*, 33(2):245, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269061.

Fox:1994:BRB

[Fox94] Eric P. Fox. Book review: *Reliability Improvement with Design of Experiments* by Lloyd W. Condra. *Technometrics*, 36(3):316–317, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269378.

Fox:1997:BRB

[Fox97] Eric P. Fox. Book review: *Regression Models* by Richard Breen. *Technometrics*, 39(2):233, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270921.

Fox:1998:BRB

[Fox98] Eric P. Fox. Book review: *Data Analysis: A Bayesian Tutorial* by D. S. Sivia. *Technometrics*, 40(2):155–156, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270652.

Freitas:1992:BRB

[Fre92] Stephen A. Freitas. Book review: *Statistics: A Fresh Approach* by Donald H. Sanders. *Technometrics*, 34(2):244–245, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269269.

Frey:1993:BRB

[Fre93] Michael Frey. Book review: *Stochastic Processes* by D. R. Cox; V. S. Isham. *Technometrics*, 35(3):329–330, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269533.

Frey:1994:BRB

[Fre94] Michael Frey. Book review: *An Introduction to Stochastic Modeling* by H. M. Taylor; S. Karlin. *Technometrics*, 36(4):428–429, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269970.

Frey:1995:BRB

[Fre95] Michael Frey. Book review: *Time Series Analysis by Higher Order Crossings* by Benjamin Kedem. *Technometrics*, 37(2):235, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269635.

Frey:1997:BRB

[Fre97] Michael Frey. Book review: *Stochastic Processes* by Sheldon Ross. *Technometrics*, 39(2):230–231, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270917.

Freitas:1999:BRB

[Fre99] Stephen A. Freitas. Book review: *Modern Industrial Statistics: Design and Control of Quality and Reliability* by Ron S. Kenett; Shelemyahu Zacks. *Technometrics*, 41(3):263–264, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270573.

Friedman:1991:MEM

[Fri91] Jerome H. Friedman. [The $\prod$ Method for Estimating Multivariate Functions from Noisy Data]: Discussion. *Technometrics*, 33 (2):145–148, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269039. See [Bre91a].

Fricker:1997:BRB

[Fri97] Ronald D. Fricker, Jr. Book review: *Statistical Problem Solving in Quality Engineering* by Thomas J. Kazmierski. *Technometrics*, 39(2):227–228, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270912.

Flehinger:1996:IAD

[FRY96] Betty J. Flehinger, Benjamin Reiser, and Emmanuel Yashchin. Inference about defects in the presence of masking. *Technomet-*

rics, 38(3):247–255, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270608.

Fulkerson:1995:BRB

[Ful95] Bill Fulkerson. Book review: *Machine Learning, Neural and Statistical Classification* by D. Michie; D. J. Spiegelhalter; C. C. Taylor. *Technometrics*, 37(4):459, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269742.

Fulkerson:1997:BRB

[Ful97] Bill Fulkerson. Book review: *Pattern Recognition and Neural Networks* by B. D. Ripley. *Technometrics*, 39(2):233–234, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270922.

Galway:1992:BRB

[Gal92] Lionel Galway. Book review: *Spline Models for Observational Data* by Grace Wahba. *Technometrics*, 34(1):113–114, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269578.

Galway:1993:BRB

[Gal93] Lionel Galway. Book review: *Probability and Statistics in Experimental Physics* by Byron P. Roe. *Technometrics*, 35(4):460–461, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270292.

Gallo:1995:BRB

[Gal95] Paul P. Gallo. Book review: *Random Coefficient Models* by Nicholas T. Longford. *Technometrics*, 37(1):120, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269168.

Gan:1995:JMP

[Gan95] F. F. Gan. Joint monitoring of process mean and variance using exponentially weighted moving average control charts. *Technometrics*, 37(4):446–453, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269736.

Ganocy:1997:BRB

[Gan97] Stephen J. Ganocy. Book review: *Design of Experiments for Process Improvement and Quality Assurance* by Robert F. Brewer. *Technometrics*, 39(4):425, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271507.

Gastwirth:1994:BRB

[Gas94] J. L. Gastwirth. Book review: *Applied Nonparametric Statistical Methods* by Peter Sprent. *Technometrics*, 36(2):216–217, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270236.

Gasparini:1997:BRB

[Gas97] Mauro Gasparini. Book review: *Markov Chain Monte Carlo in Practice* by W. R. Gilks; S. Richardson; D. J. Spiegelhalter. *Technometrics*, 39(3):338, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271145.

Gatliffe:1996:BRB

[Gat96] Thomas R. Gatliffe. Book review: *Statistics for Environmental Engineers* by Paul Mac Berthouex; Linfield C. Brown. *Technometrics*, 38(2):182–183, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270412.

Grondona:1991:USC

[GC91] Martin O. Grondona and Noel Cressie. Using spatial considerations in the analysis of experiments. *Technometrics*, 33(4):381–392, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269411.

Grove:1991:TIC

[GD91] D. M. Grove and T. P. Davis. Taguchi's idle column method. *Technometrics*, 33(3):349–353, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268786.

Gilbert:1994:UCS

[GD94] Richard O. Gilbert and Pamela G. Doctor. [The Use of Conditional Simulation in Nuclear-Waste-Site Performance Assessment]:

Discussion. *Technometrics*, 36(2):141–144, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270221. See [Got94c].

George:1994:BRB

[Geo94] Larry George. Book review: *What Every Engineer Should Know about Reliability and Risk Analysis* by M. Modarres. *Technometrics*, 36(2):226–227, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270248.

Georgiev:1998:BRB

[Geo98] Alexander A. Georgiev. Book review: *Functional Data Analysis* by Jim Ramsay; Bernard Silverman. *Technometrics*, 40(3):260–261, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271190.

Ghosh:1993:BRB

[Gho93] Subir Ghosh. Book review: *Variance Components* by Shayle R. Searle; George Casella; Charles E. McCulloch. *Technometrics*, 35(2):221–222, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269669.

Ghosh:1994:BRB

[Gho94] Subir Ghosh. Book review: *Statistical Process Control for Quality Improvement* by James R. Thompson; Jacek Koronacki. *Technometrics*, 36(1):120, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269216.

Goldberg:1992:BEB

[GI92] Kenneth M. Goldberg and Boris Iglewicz. Bivariate extensions of the boxplot. *Technometrics*, 34(3):307–320, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270037.

Gibbons:1991:BRB

[Gib91] Ned M. Gibbons. Book review: *Statistics in Scientific Investigation* by Glen McPherson. *Technometrics*, 33(3):356–357, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268788.

Gibbons:1999:SNP

[Gib99] Robert D. Gibbons. [Simultaneous Nonparametric Prediction Limits]: Discussion. *Technometrics*, 41(2):104–106, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270723`. See [DM99a].

Gill:1992:BRB

[Gil92] P. S. Gill. Book review: *Introduction to Linear Models and Experimental Design* by J. Arthur Woodward; Douglas G. Bonett; Mary-Lynn Brecht. *Technometrics*, 34(3):354, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270042`.

Gilbert:1999:SNP

[Gil99] Richard O. Gilbert. [Simultaneous Nonparametric Prediction Limits]: Discussion. *Technometrics*, 41(2):106–107, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270724`. See [DM99a].

Garcia-Jurado:1995:PUB

[GJMS+95] I. García-Jurado, W. González Manteiga, J. M. Prada Sánchez, M. Febrero-Bande, and R. Cao. Predicting using Box-Jenkins, nonparametric, and bootstrap techniques. *Technometrics*, 37(3): 303–310, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269914`.

Gan:1990:GFT

[GK90] F. F. Gan and K. J. Koehler. Goodness-of-fit tests based on P–P probability plots. *Technometrics*, 32(3):289–303, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269106`.

Gunst:1993:CAI

[GK93] Richard F. Gunst and Nelson A. Kelly. Captive-air irradiation experiments on ozone formation in Southern California. *Technometrics*, 35(3):256–267, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269518`.

Glaz:1998:BRB

[Gla98] Joseph Glaz. Book review: *Frontiers in Queueing: Models and Applications in Science and Engineering* by Jewgeni H. Dshalalow.

Technometrics, 40(2):162–163, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270662`.

Gleser:1991:BRB

[Gle91] Leon Jay Gleser. Book review: *Design and Analysis of Reliability Studies* by Graham Dunn. *Technometrics*, 33(4):472–473, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269420`.

Gleser:1996:BRB

[Gle96] Leon Jay Gleser. Book review: *Measurement, Regression, and Calibration* by Philip J. Brown. *Technometrics*, 38(1):75, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268905`.

Glosup:1993:BRB

[Glo93] Jeffrey Glosup. Book review: *Handbook of the Logistic Distribution* by N. Balakrishnan. *Technometrics*, 35(2):236–237, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269689`.

Glosup:1995:BRB

[Glo95] Jeffrey Glosup. Book review: *Multivariate Statistical Modelling Based on Generalized Linear Models* by L. Fahrmeir; G. Tutz. *Technometrics*, 37(3):350–351, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269929`.

Glosup:1997:BRB

[Glo97] Jeffrey Glosup. Book review: *Statistics for Long-Memory Processes* by Jan Beran. *Technometrics*, 39(1):105–106, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270785`.

Glosup:1999:BRB

[Glo99] Jeffrey Glosup. Book review: *Statistical Evidence: A Likelihood Paradigm* by Richard Royall. *Technometrics*, 41(1):80–81, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271009`.

Godfrey:1990:CCB

[God90] A. Blanton Godfrey. Commentary: Communications between Statisticians and Engineers/Physical Scientists: Does anyone care? *Technometrics*, 32(3):253–255, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269095.

Godsey:1993:BRB

[God93] E. B. Godsey. Book review: *Short Run SPC* by Donald J. Wheeler. *Technometrics*, 35(2):233, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269684.

Godsey:1995:BRB

[God95] E. B. Godsey. Book review: *Bilateral Plans for Inspection and Process Control by Variables* by Gaetano Panizzon. *Technometrics*, 37(4):463–464, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269748.

Goik:1996:BRB

[Goi96] Patrick P. Goik. Book review: *Practical Engineering Statistics* by Daniel Schiff; Ralph D'Agostino. *Technometrics*, 38(4):404, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271316.

Golland:1990:BRB

[Gol90] Ronald W. Golland. Book review: *Principles of Random Variate Generation* by John Dagpunar. *Technometrics*, 32(2):226–227, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268875.

Goldstein:1993:BRB

[Gol93] Richard Goldstein. Book review: *Conditioning Diagnostics: Collinearity and Weak Data in Regression* by David A. Belsley. *Technometrics*, 35(1):85–86, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269293.

Goldman:1995:BRB

[Gol95] Aaron Goldman. Book review: *An Introduction to Regression Graphics* by R. Dennis Cook; Sanford Weisberg. *Technometrics*, 37(3):343–344, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269921.

Goldstein:1998:BRB

[Gol98] Richard Goldstein. Book review: *Latent Class and Discrete Latent Trait Models: Similarities and Differences* by Ton Heinen. *Technometrics*, 40(1):81, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271408.

Goldberg:1999:BRB

[Gol99] Judith D. Goldberg. Book review: *Applied Survival Analysis* by Chap T. Le. *Technometrics*, 41(3):267–268, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270580.

Goodall:1991:BRB

[Goo91] Colin R. Goodall. Book review: *Graphical Models in Applied Multivariate Statistics* by J. Whittaker. *Technometrics*, 33(4):476–478, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269424.

Goodall:1992:BRB

[Goo92a] Colin Goodall. Book review: *Nonlinear Multivariate Analysis* by Albert Gifi. *Technometrics*, 34(3):357–358, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270046.

Goodman:1992:BRB

[Goo92b] Jay H. Goodman. Book review: *Statistics in Spectroscopy* by Howard Mark; Jerry Workman. *Technometrics*, 34(4):498–499, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268962.

Goodfriend:1995:BRB

[Goo95] Jason H. Goodfriend. Book review: *Discrete Event Systems: Sensitivity Analysis and Stochastic Optimization by the Score Function Method* by Reuven Y. Rubinstein; Alexander Shapiro. *Technometrics*, 37(1):124–125, February 1995. CODEN TCMTA2.

ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269174`.

Gotway:1992:BRB

[Got92] Carol A. Gotway. Book review: *Spatial Data Analysis in the Social and Environmental Sciences* by Robert Haining. *Technometrics*, 34(4):499–500, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268964`.

Gotway:1994:BRB

[Got94a] Carol A. Gotway. Book review: *Statistical Methods in Water Resources* by D. R. Helsel; R. M. Hirsch. *Technometrics*, 36(3):323–324, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269385`.

Gotway:1994:UCSb

[Got94b] Carol A. Gotway. [The Use of Conditional Simulation in Nuclear-Waste-Site Performance Assessment]: Reply. *Technometrics*, 36 (2):156–161, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270227`. See [Got94c].

Gotway:1994:UCSa

[Got94c] Carol A. Gotway. The use of conditional simulation in nuclear-waste-site performance assessment. *Technometrics*, 36(2):129–141, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270220`. See discussion [GD94, WB94, Dow94, Jou94, Tor94, Rut94] and reply [Got94b].

Govindarajulu:1992:BRB

[Gov92] Z. Govindarajulu. Book review: *Rank Correlation Methods* by M. Kendall; J. D. Gibbons. *Technometrics*, 34(1):108, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269571`.

Gaudard:1997:BRB

[GR97] Marie Gaudard and Philip J. Ramsey. Book review: *Introduction to Statistical Quality Control* by Douglas C. Montgomery. *Technometrics*, 39(3):332, August 1997. CODEN TCMTA2. ISSN 0040-

1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271137.

Gray:1990:BRB

[Gra90] J. Brian Gray. Book review: *Multivariate Exploratory Data Analysis* by Allen Yates. *Technometrics*, 32(3):356–357, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269132.

Gray:1994:BRB

[Gra94] J. Brian Gray. Book review: *Regression with Graphics: A Second Course in Applied Statistics* by Lawrence C. Hamilton. *Technometrics*, 36(1):112–113, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269206.

Gray:1998:BRB

[Gra98] J. Brian Gray. Book review: *Applied Regression Analysis, Linear Models, and Related Methods* by John Fox. *Technometrics*, 40 (2):156, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270653.

Greer:1994:BRB

[Gre94] Daniel A. Greer. Book review: *Design of Experiments: A No-Name Approach* by Thomas J. Lorenzen; Virgil L. Anderson. *Technometrics*, 36(3):317–318, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269379.

Grego:1998:BRB

[Gre98] John M. Grego. Book review: *Practical Data Analysis for Designed Experiments* by Brian S. Yandell. *Technometrics*, 40(2): 154–155, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270650.

Grice:1990:BRB

[Gri90] John V. Grice. Book review: *Parts Per Million Values for Estimating Quality Levels* by R. E. Odeh; D. B. Owen. *Technometrics*, 32(1):98, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269855.

Grimshaw:1993:CML

[Gri93] Scott D. Grimshaw. Computing maximum likelihood estimates for the generalized Pareto distribution. *Technometrics*, 35(2):185–191, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269663.

Grimshaw:1995:BRB

[Gri95] Scott D. Grimshaw. Book review: *An Introduction to the Bootstrap* by Bradley Efron; Robert J. Tibshirani. *Technometrics*, 37 (3):341, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269918.

Grice:1996:BRB

[Gri96] John V. Grice. Book review: *A Data-Based Approach to Statistics* by Ronald L. Iman. *Technometrics*, 38(4):405, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271318.

Griffith:1997:BRB

[Gri97a] William S. Griffith. Book review: *Applied Methods of Structural Reliability* by Milík Tichý. *Technometrics*, 39(1):104–105, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270784.

Grillenzoni:1997:RGE

[Gri97b] Carlo Grillenzoni. Recursive generalized M-estimators of system parameters. *Technometrics*, 39(2):211–224, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270909.

Griffiths:1998:BRB

[Gri98] Kristi L. Griffiths. Book review: *Handbook of Experimental Methods for Process Improvement* by David Drain. *Technometrics*, 40(1):74, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271396.

Griffith:1999:BRB

[Gri99] William S. Griffith. Book review: *Mathematical Theory of Reliability of Time Dependent Systems with Practical Applications* by Igor

N. Kovalenko; Nickolaj Yu. Kuznetsoy; Philip A. Pegg. *Technometrics*, 41(3):269, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270582`.

Groggel:1992:BRB

[Gro92] David J. Groggel. Book review: *Probability and Statistics* by Athanasios Papoulis. *Technometrics*, 34(2):243, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269266`.

Groggel:1996:BRB

[Gro96] David J. Groggel. Book review: *Analyzing and Modeling Rank Data* by John I. Marden. *Technometrics*, 38(4):403, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271314`.

Groggel:1999:BRB

[Gro99] David J. Groggel. Book review: *Nonparametric Methods for Quantitative Analysis* by Jean Dickinson Gibbons. *Technometrics*, 41(1):75, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271000`.

Gruber:1990:BRB

[Gru90] Marvin H. J. Gruber. Book review: *Bayesian Spectrum Analysis and Parameter Estimation* by G. Larry Bretthorst. *Technometrics*, 32(2):226, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268874`.

Gruber:1995:BRB

[Gru95] Marvin H. J. Gruber. Book review: *Reliability and Decision Making* by Richard E. Barlow; Carlo A. Clarotti; Fabio Spizzichino. *Technometrics*, 37(3):346–347, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269924`.

Gruber:1997:BRB

[Gru97] Marvin H. J. Gruber. Book review: *Statistical Digital Signal Processing and Modeling* by Monson H. Hayes. *Technometrics*, 39 (3):335–336, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271141.

Greenberg:1992:ENR

[GS92] Betsy S. Greenberg and S. Lynne Stokes. Estimating nonconformance rates after zero-defect sampling with rectification. *Technometrics*, 34(2):203–213, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269236.

Gurland:1994:RIF

[GS94] John Gurland and Jayaram Sethuraman. Reversal of increasing failure rates when pooling failure data. *Technometrics*, 36 (4):416–418, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269957.

Greenberg:1995:RTP

[GS95] Betsy S. Greenberg and S. Lynne Stokes. Repetitive testing in the presence of inspection errors. *Technometrics*, 37(1):102–111, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269157.

Grimshaw:1998:RTP

[GSH98] Scott D. Grimshaw, Scott D. Shellman, and Arnon M. Hurwitz. Real-time process monitoring for changing inputs. *Technometrics*, 40(4):283–296, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270529.

Gu:1991:MEM

[Gu91] Chong Gu. [The $\prod$ Method for Estimating Multivariate Functions from Noisy Data]: Discussion. *Technometrics*, 33(2):149–154, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269040. See [Bre91a].

Guess:1990:BRB

[Gue90] Frank M. Guess. Book review: *Bayesian Statistics: Principles, Models, and Applications* by S. James Press. *Technometrics*, 32 (4):453–454, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270132.

Gunst:1990:BRB

[Gun90] Richard F. Gunst. Book review: *MINITAB Supplement to Accompany General Statistics*, by Warren Chase and Fred Brown by Anne Sevin. *Technometrics*, 32(4):456, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270135.

Gunter:1993:SAP

[Gun93] Berton H. Gunter. [A Systematic Approach to Planning for a Designed Industrial Experiment]: Discussion. *Technometrics*, 35 (1):13–14, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269281. See [CM93b].

Gunter:1994:BRBb

[Gun94a] Bert Gunter. Book review: *A First Course in Probability Models and Statistical Inference* by J. H. C. Creighton. *Technometrics*, 36(4):428, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269969.

Gunter:1994:BRBa

[Gun94b] Bert Gunter. Book review: *Visualizing Data* by William S. Cleveland. *Technometrics*, 36(3):314–315, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269376.

Gunst:1996:BRB

[Gun96a] Richard F. Gunst. Book review: *Response Surface Methodology: Process and Product Optimization Using Designed Experiments* by Raymond H. Myers; Douglas C. Montgomery. *Technometrics*, 38 (3):285–286, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270613.

Gunter:1996:BRB

[Gun96b] Berton H. Gunter. Book review: *Practical Continuous Improvement for Professional Services* by Clive Shearer. *Technometrics*, 38(1):84, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268917.

Gunst:1999:BRB

[Gun99] Richard F. Gunst. Book review: *Applied Regression Analysis* by Norman R. Draper; Harry Smith. *Technometrics*, 41(3):265–266, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270576.

Guttorp:1990:BRB

[Gut90] Peter Guttorp. Book review: *Fuzzy Mathematical Models in Engineering and Management Science* by A. Kaufman; M. Gupta. *Technometrics*, 32(2):238, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268889.

Guttorp:1992:BRB

[Gut92] Peter Guttorp. Book review: *The Art of Probability for Scientists and Engineers* by Richard W. Hamming. *Technometrics*, 34 (2):242, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269264.

Haining:1993:EPT

[HA93] Robert Haining and Giuseppe Arbia. Error propagation through map operations. *Technometrics*, 35(3):293–305, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269522.

Haberman:1990:CLA

[Hab90] Shelby J. Haberman. [A Critical Look at Accumulation Analysis and Related Methods]: Discussion. *Technometrics*, 32(2):131–132, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268854. See [HW90b].

Habibullah:1992:BRB

[Hab92] Mohamed Habibullah. Book review: *Log-Linear Models* by R. Christensen. *Technometrics*, 34(2):227, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269241.

Hadi:1992:BRB

[Had92] Ali S. Hadi. Book review: *Finding Groups in Data: An Introduction to Cluster Analysis* by L. Kaufman; P. J. Rousseeuw.

Technometrics, 34(1):111–112, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269576.

Hagwood:1990:BRB

[Hag90] Charles Hagwood. Book review: *Elementary Applications of Probability Theory* by H. Tuckwell. *Technometrics*, 32(1):112–113, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269872.

Hagwood:1991:BRB

[Hag91] Charles Hagwood. Book review: *Multivariate Calibration* by H. Martens; T. Naes. *Technometrics*, 33(3):366–367, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268798.

Hagwood:1996:BRB

[Hag96] Charles Hagwood. Book review: *Mathematical Analysis of Spectral Orthogonality* by John H. Kalivas; Patrick M. Lang. *Technometrics*, 38(1):86, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268921.

Hahn:1990:CCB

[Hah90] Gerald J. Hahn. Commentary: [Communications between Statisticians and Engineers/Physical Scientists]. *Technometrics*, 32(3):257–258, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269096. See [HK90].

Hahn:1993:SAP

[Hah93] Gerald J. Hahn. [A Systematic Approach to Planning for a Designed Industrial Experiment]: Discussion. *Technometrics*, 35(1):15–17, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269282. See [CM93b].

Halteman:1994:BRB

[Hal94] Edward J. Halteman. Book review: *SPC for the Rest of Us: A Personal Path to Statistical Process Control* by Hy Pitt. *Technometrics*, 36(4):424, November 1994. CODEN TCMTA2. ISSN

0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269963.

Hall:1995:BRB

[Hal95] Timothy Hall. Book review: *Numerical Solution of SDE Through Computer Experiments* by Peter E. Kloeden; Eckhard Platen; Henri Schurz. *Technometrics*, 37(1):125, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269175.

Hall:1998:BRB

[Hal98] Kathryn Hall. Book review: *SPC Essentials and Productivity Improvement* by William A. Levinson; Frank Tumbelty. *Technometrics*, 40(1):73, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271394.

Hamilton:1996:BRB

[Ham96] Martin A. Hamilton. Book review: *Environmental Statistics and Data Analysis* by Wayne R. Ott. *Technometrics*, 38(3):292–293, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270622.

Hand:1990:BRB

[Han90] David J. Hand. Book review: *Readings in Decision Analysis* by Simon French. *Technometrics*, 32(4):463–464, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270147.

Hansen:1993:BRB

[Han93] James L. Hansen. Book review: *Process Control: Statistical Principles and Tools* by Ronald Gulezian. *Technometrics*, 35(2):230–231, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269680.

Hansen:1997:BRB

[Han97] Christian K. Hansen. Book review: *Practical Methods for Reliability Data Analysis* by J. I. Ansell; M. J. Phillips. *Technometrics*, 39(2):226, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270910.

Hansen:1998:BRB

[Han98] Mark Hansen. Book review: *Applied Wavelet Analysis with S-PLUS* by Andrew Bruce; Hong-Ye Gao. *Technometrics*, 40(2):159, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270657.

Hapeman:1991:BRB

[Hap91] David E. Hapeman. Book review: *Categorical Data Analysis* by Alan Agresti. *Technometrics*, 33(2):241, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269056.

Hapeman:1992:BRB

[Hap92] David E. Hapeman. Book review: *The Statistical Analysis of Categorical Data* by Erling B. Anderson. *Technometrics*, 34(3):364, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270057.

Hardin:1991:BRB

[Har91a] J. Michael Hardin. Book review: *Robust Estimation and Testing* by Robert G. Staudte; Simon J. Sheather. *Technometrics*, 33 (4):478–479, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269426.

Harper:1991:BRB

[Har91b] William V. Harper. Book review: *Statistics: Theory and Methods* by Donald A. Berry; Bernard W. Lindgren. *Technometrics*, 33(3):369–370, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268801.

Harris:1991:BRBb

[Har91c] Bernard Harris. Book review: *Parametric Statistical Models and Likelihood (Lecture Notes in Statistics 50)* by Ole E. Barndorff-Nielsen. *Technometrics*, 33(4):493–494, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269443.

Harris:1991:BRBa

[Har91d] Thomas J. Harris. Book review: *Adaptive Control* by J. Astrom; B. Wittenmark. *Technometrics*, 33(4):487, November 1991. CODEN

TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269433.

Harris:1992:BRB

[Har92a] Thomas Harris. Book review: *Time Series Analysis, Identification and Adaptive Filtering* by Daniel Graupe. *Technometrics*, 34(3):355–356, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270044.

Harris:1992:OCN

[Har92b] Thomas J. Harris. Optimal controllers for nonsymmetric and nonquadratic loss functions. *Technometrics*, 34(3):298–306, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270036.

Hassett:1991:BRB

[Has91] Nancy C. Hassett. Book review: *Statistical Data Analysis Handbook* by Francis Wall. *Technometrics*, 33(1):113–114, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269020.

Hawkins:1990:BRB

[Haw90] Douglas M. Hawkins. Book review: *Multivariate Statistics: A Practical Approach* by Bernhard Flury; Hans Riedwyl. *Technometrics*, 32(1):98–99, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269856.

Hawkins:1991:DUR

[Haw91a] Douglas M. Hawkins. Diagnostics for use with regression recursive residuals. *Technometrics*, 33(2):221–234, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269048. See correction [Ano91e].

Hawkins:1991:MQC

[Haw91b] Douglas M. Hawkins. Multivariate quality control based on regression-adjusted variables. *Technometrics*, 33(1):61–75, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269008. See correction [Ano91f].

Hawkins:1994:LE

[Haw94] Daniel B. Hawkins. Letter to the Editor. *Technometrics*, 36(4): 438, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269987.

Hamilton:1991:DAS

[HC91] Martin A. Hamilton and Bruce Jay Collings. Determining the appropriate sample size for nonparametric tests for location shift. *Technometrics*, 33(3):327–337, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268784.

Huang:1998:MAT

[HCV98] Peng Huang, Dechang Chen, and Joseph O. Voelkel. Minimum-aberration two-level split-plot designs. *Technometrics*, 40(4):314–326, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270532.

Hahn:1995:STC

[HD95] Gerald J. Hahn and Necip Doganaksoy. [Shewhart-Type Charts in Nonstandard Situations]: Discussion. *Technometrics*, 37(1):29–31, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269149. See [RD95a].

Healy:1990:CCV

[Hea90] John Healy. [CUSUM Charts with Variable Sampling Intervals]: Discussion. *Technometrics*, 32(4):385–386, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270115. See [RAA90a].

Heavlin:1994:BRB

[Hea94] William D. Heavlin. Book review: *Pyzdek's Guide to SPC: Volume Two, Applications and Special Topics* by Thomas Pyzdek. *Technometrics*, 36(4):422–424, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269962.

Heckler:1990:BRB

[Hec90] Charles E. Heckler. Book review: *Mastering the SAS System* by Jay A. Jaffe. *Technometrics*, 32(3):350–351, August 1990. CODEN

TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269125.

Heckler:1995:BRB

[Hec95] Charles E. Heckler. Book review: *Applied Discriminant Analysis* by Carl J. Huberty. *Technometrics*, 37(3):349–350, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269928.

Heckler:1996:BRB

[Hec96] Charles E. Heckler. Book review: *A Step-by-Step Approach to Using the SAS(R) System for Factor Analysis and Structural Equation Modeling* by Larry Hatcher. *Technometrics*, 38(3):296–297, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270628.

Heckler:1999:BRB

[Hec99] Charles E. Heckler. Book review: *Statistical Graphics for Visualizing Multivariate Data* by William G. Jacoby. *Technometrics*, 41(4):369, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271355.

Heitkamp:1990:BRB

[Hei90] Norman Heitkamp. Book review: *SAS System for Elementary Statistical Analysis* by Sandra D. Schlotzhauer; Ramon C. Littell; Cary. *Technometrics*, 32(2):230–231, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268879.

Hembree:1999:BRB

[Hem99] Barry Hembree. Book review: *The SPC Troubleshooting Guide* by Ronald Blank. *Technometrics*, 41(3):266, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270577.

Hess:1991:BRB

[Hes91] James L. Hess. Book review: *Statistics: A Guide to the Use of Statistical Methods in the Physical Sciences* by R. J. Barlow. *Technometrics*, 33(1):108, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269014.

Hesterberg:1993:BRB

[Hes93] Tim Hesterberg. Book review: *Statistical Models in S* by John M. Chambers; Trevor J. Hastie. *Technometrics*, 35(2):227–228, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269676`.

Hesterberg:1995:WAI

[Hes95] Tim Hesterberg. Weighted average importance sampling and defensive mixture distributions. *Technometrics*, 37(2):185–194, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269620`.

Hesterberg:1997:BRB

[Hes97] Tim Hesterberg. Book review: *The Jackknife and Bootstrap* by Jun Shao; Dongsheng Tu. *Technometrics*, 39(4):429, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271515`.

Heydorn:1992:BRB

[Hey92] Richard P. Heydorn. Book review: *Practical Reliability Engineering* by Patrick D. T. O'Connor. *Technometrics*, 34(4):487–488, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268949`.

Heyes:1993:BRB

[Hey93] Gerald B. Heyes. Book review: *Statistical Problem Solving* by Wendell E. Carr. *Technometrics*, 35(3):333–334, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269541`.

Heydorn:1998:BRB

[Hey98] Richard P. Heydorn. Book review: *Reliability and Maintainability Engineering* by Charles E. Ebeling. *Technometrics*, 40(3):256–257, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271182`.

Halverson:1996:BRB

[HH96] Tim Halverson and Ian Hau. Book review: *The Next Phase of Total Quality Management: TQM II and Focus on Profitability* by Robert Stein. *Technometrics*, 38(3):295, August 1996. CODEN

TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270626.

Hahn:1998:KCSa

[HH98a] Gerry Hahn and Roger Hoerl. Key challenges for statisticians in business and industry. *Technometrics*, 40(3):195–200, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271171. See discussion [MTV98, Nem98] and summary [HH98b].

Hahn:1998:KCSb

[HH98b] Gerry Hahn and Roger Hoerl. [Key Challenges for Statisticians in Business and Industry]: Summary. *Technometrics*, 40(3):211–213, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271176. See [HH98a].

Higbee:1998:BRB

[Hig98] Kenneth Higbee. Book review: *Mathematical Classification and Clustering* by Boris Mirkin. *Technometrics*, 40(1):80, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271406.

Hillyer:1995:BRB

[Hil95] Martin Hillyer. Book review: *Statistical Methods in Analytical Chemistry* by Peter C. Meier; Richard E. Zünd. *Technometrics*, 37(1):113–114, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269159.

Hinde:1997:BRB

[Hin97] John Hinde. Book review: *XploRe: An Interactive Statistical Computing Environment* by W. Härdle; S. Klinke; B. A. Turlach. *Technometrics*, 39(4):430–431, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271517.

Hirotsu:1990:CLA

[Hir90] Chihiro Hirotsu. [A Critical Look at Accumulation Analysis and Related Methods]: Discussion. *Technometrics*, 32(2):133–136, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268855. See [HW90b].

Hirst:1996:ERE

[Hir96] David Hirst. Error-rate estimation in multiple-group linear discriminant analysis. *Technometrics*, 38(4):389–399, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271310.

Hoadley:1990:CBS

[HK90] A. Bruce Hoadley and J. R. Kettenring. Communications between statisticians and engineers/physical scientists. *Technometrics*, 32(3):243–247, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269092. See commentary [Arm90, Box90, God90, Hah90, Hoo90, Hun90a, Mac90b, Moo90, Sne90, Tri90, Wan90].

Hamilton:1995:CMU

[HL95] David C. Hamilton and Mary L. Lesperance. A comparison of methods for univariate and multivariate acceptance sampling by variables. *Technometrics*, 37(3):329–339, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269917.

Hirose:1997:IGD

[HL97] Hideo Hirose and Tze Leung Lai. Inference from grouped data in three-parameter Weibull models with applications to breakdown-voltage experiments. *Technometrics*, 39(2):199–210, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270908.

Holliday:1998:EME

[HLD98] Timothy Holliday, Anthony J. Lawrance, and Timothy P. Davis. Engine-mapping experiments: A two-stage regression approach. *Technometrics*, 40(2):120–126, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270646.

Hu:1998:NEL

[HLS98] X. Joan Hu, Jerald F. Lawless, and Kazuyuki Suzuki. Nonparametric estimation of a lifetime distribution when censoring times are missing. *Technometrics*, 40(1):3–13, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271388.

Hastie:1993:SVS

[HM93] Trevor Hastie and Colin Mallows. [A Statistical View of Some Chemometrics Regression Tools]: Discussion. *Technometrics*, 35 (2):140–143, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269658`. See [FF93b] and response [FF93a].

Hansen:1997:MWM

[HNF97] Mark H. Hansen, Vijayan N. Nair, and David J. Friedman. Monitoring wafer map data from integrated circuit fabrication processes for spatially clustered defects. *Technometrics*, 39(3):241–253, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271129`.

Haaland:1993:SAP

[HO93] Perry D. Haaland and M. A. O'Connell. [A Systematic Approach to Planning for a Designed Industrial Experiment]: Discussion. *Technometrics*, 35(1):17–20, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269283`. See [CM93b].

Haaland:1995:IES

[HO95] Perry D. Haaland and Michael A. O'Connell. Inference for effect-saturated fractional factorials. *Technometrics*, 37(1):82–93, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269155`.

Hockman:1994:BRB

[Hoc94] Kymm K. Hockman. Book review: *World Class Quality: Using Design of Experiments to Make It Happen* by Keki R. Bhote. *Technometrics*, 36(4):425–426, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269965`.

Hoffman:1995:BRB

[Hof95] Lorrie L. Hoffman. Book review: *Markov Models and Optimization* by M. H. A. Davis. *Technometrics*, 37(2):236, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269636`.

Holms:1998:DEE

[Hol98] Arthur G. Holms. Design of experiments as expansible sequences of orthogonal blocks with crossed-classification block effects. *Technometrics*, 40(3):244–253, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271180.

Hooper:1990:CCB

[Hoo90] Jeffrey H. Hooper. Commentary: [Communications between Statisticians and Engineers/Physical Scientists]. *Technometrics*, 32(3):259–260, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269097. See [HK90].

Horn:1998:BRB

[Hor98] Paul S. Horn. Book review: *Introduction to Robust Estimation and Hypothesis Testing* by Rand R. Wilcox. *Technometrics*, 40 (1):77–78, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271402.

Hoerl:1992:DIS

[HP92] Roger W. Hoerl and Andrew C. Palm. Discussion: Integrating SPC and APC. *Technometrics*, 34(3):268–272, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270029.

Hall:1997:AIT

[HP97] Peter Hall and A. R. Padmanabhan. Adaptive inference for the two-sample scale problem. *Technometrics*, 39(4):412–422, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271505.

Haitovsky:1992:CRM

[HR92] Yoel Haitovsky and Joel Rapp. Conditional resampling for misclassified multinomial data with applications to sampling inspection. *Technometrics*, 34(4):473–483, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268946. See correction [HR94].

Haitovsky:1994:CCR

[HR94] Yoel Haitovsky and Joel Rapp. Corrections: "Conditional resampling for misclassified multinomial data with applications to sampling inspection" [*Technometrics* **34** (1992), no. 4, 473–482]. *Technometrics*, 36(3):334, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269404`. See [HR92].

Handcock:1993:BAK

[HS93] Mark S. Handcock and Michael L. Stein. A Bayesian analysis of kriging. *Technometrics*, 35(4):403–410, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270273`.

Holmstrom:1997:MDM

[HS97] Lasse Holmström and Stephan R. Sain. Multivariate discrimination methods for top quark analysis. *Technometrics*, 39(1):91–99, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270776`.

Hedayat:1999:COA

[HS99] A. S. Hedayat and John Stufken. Compound orthogonal arrays. *Technometrics*, 41(1):57–61, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270994`.

Hadi:1992:CPF

[HSPF92] Ali S. Hadi, Jeffrey S. Simonoff, S. R. Paul, and K. Y. Fung. Comments on Paul and Fung (1991). *Technometrics*, 34(3):373–375, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270075`. See [PF91].

Hastie:1991:MEM

[HT91] Trevor Hastie and Rob Tibshirani. [The $\prod$ Method for Estimating Multivariate Functions from Noisy Data]: Discussion. *Technometrics*, 33(2):155, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269041`. See [Bre91a].

Hall:1992:EPP

[HT92] Peter Hall and D. M. Titterington. Edge-preserving and peak-preserving smoothing. *Technometrics*, 34(4):429–440, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268942`.

Hulting:1992:BRB

[Hul92] Fred L. Hulting. Book review: *How to Determine Sample Size and Estimate Failure Rate in Life Testing* by Eduardo C. Moura. *Technometrics*, 34(4):488–489, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268950`.

Hulting:1997:SIG

[Hul97] Fred L. Hulting. [Statistical Issues in Geometric Feature Inspection Using Coordinate Measuring Machines]: Discussion. *Technometrics*, 39(1):18–20, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270765`. See [DGTZ97a].

Hunter:1990:CCB

[Hun90a] J. Stuart Hunter. Commentary: [Communications between Statisticians and Engineers/Physical Scientists]. *Technometrics*, 32(3): 261, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269098`. See [HK90].

Hunter:1990:EWM

[Hun90b] J. Stuart Hunter. [Exponentially Weighted Moving Average Control Schemes: Properties and Enhancements]: Discussion. *Technometrics*, 32(1):21–22, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269839`. See [LS90b].

Huzurbazar:1995:BRB

[Huz95] Aparna V. Huzurbazar. Book review: *Concepts in Probability and Stochastic Modeling* by J. Higgins; S. Keller-McNulty. *Technometrics*, 37(4):467, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269753`.

Hamada:1990:CLAb

[HW90a] M. Hamada and C. F. J. Wu. [A Critical Look at Accumulation Analysis and Related Methods]: Response. *Technometrics*, 32(2):159–162, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268859`.

Hamada:1990:CLAa

[HW90b] M. Hamada and C. F. J. Wu. A critical look at accumulation analysis and related methods. *Technometrics*, 32(2):119–130, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268853. See discussion [Hab90, Hir90, Nai90b, YDB90] and response [HW90a].

Hamada:1991:ACD

[HW91] M. Hamada and C. F. J. Wu. Analysis of censored data from highly fractionated experiments. *Technometrics*, 33(1):25–38, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269005.

Hwan:1992:BRB

[Hwa92] Marilyn Hwan. Book review: *Quality Through Design* by N. Logothetis; H. P. Wynn. *Technometrics*, 34(2):230–231, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269248.

Iglewicz:1995:BRB

[IHMT95] Boris Iglewicz, Richard M. Heiberger, Dirk Moore, and Yun Tan. Book review: *Algorithms, Routines, and S Functions, for Robust Statistics* by A. Marazzi. *Technometrics*, 37(3):351–353, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269931.

Inglis:1992:BRB

[Ing92] James Inglis. Book review: *Statistics for Research* by Shirley Dowdy; Stanley Wearden. *Technometrics*, 34(3):367–368, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270062.

Iyer:1990:BRB

[Iye90] Hari Iyer. Book review: *Model Discrimination for Nonlinear Regression Models* by Dale S. Borowiak. *Technometrics*, 32(4):448–450, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270126.

Iyengar:1998:BRB

[Iye98] Satish Iyengar. Book review: *Multivariate Models and Dependence Concepts* by H. Joe. *Technometrics*, 40(4):353, November

1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270541.

Izenman:1990:BRB

[Ize90] Alan Julian Izenman. Book review: *Multivariate Splines* by Charles K. Chui. *Technometrics*, 32(2):235–237, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268887.

Izenman:1991:BRB

[Ize91] Alan Julian Izenman. Book review: *The Multivariate Normal Distribution* by Y. L. Tong. *Technometrics*, 33(4):492–493, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269441.

Jacroux:1992:NDC

[Jac92] Mike Jacroux. A note on the determination and construction of minimal orthogonal main-effect plans. *Technometrics*, 34(1):92–96, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269556.

Jacroux:1993:CMP

[Jac93] Mike Jacroux. On the construction of minimal partially replicated orthogonal main-effect plans. *Technometrics*, 35(1):32–36, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269287.

Jackson:1995:BRB

[Jac95] J. Edward Jackson. Book review: *Statistical Factor Analysis and Related Methods: Theory and Applications* by Alexander Basilevsky. *Technometrics*, 37(2):227–228, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269623.

Jain:1995:BRB

[Jai95] Kamlesh Jain. Book review: *Statistical Methods of Quality Assurance* by H.-J. Mittag; H. Rinne. *Technometrics*, 37(2):234, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269633.

James:1996:BRB

[Jam96] David A. James. Book review: *Modern Applied Statistics with S-PLUS* by W. N. Venables; B. D. Ripley. *Technometrics*, 38 (1):77–78, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268908.

Janky:1994:BRB

[Jan94] Denis G. Janky. Book review: *Applied Engineering Statistics* by Robert M. Bethea; R. Russell Rhinehart. *Technometrics*, 36(2): 221–222, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270241.

Jobe:1992:BCB

[JD92] J. Marcus Jobe and H. T. David. Buehler confidence bounds for a reliability-maintainability measure. *Technometrics*, 34(2):214–222, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269237.

Jones:1996:FDR

[JD96] Bradley Jones and William Dumouchel. [Follow-Up Designs to Resolve Confounding in Multifactor Experiments]: Discussion. *Technometrics*, 38(4):323–326, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271301. See [MSB96a].

Jensen:1990:BRB

[Jen90] Louis Jensen. Book review: *Practical Statistics for the Physical Sciences* by L. L. Havlicek; R. C. Crain. *Technometrics*, 32 (3):357–358, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269134.

Jensen:1991:BRB

[Jen91] Karen L. Jensen. Book review: *Experimental Design in Biotechnology* by Perry D. Haaland. *Technometrics*, 33(1):106–108, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269013.

Jensen:1992:BRB

[Jen92] Karen L. Jensen. Book review: *Practical Application of SPC in the Wire and Cable Industry* by Douglas B. Relyea. *Technometrics*, 34(1):101–102, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269562.

Jensen:1993:BRB

[Jen93] Karen L. Jensen. Book review: *Concepts for R & R Studies* by Larry B. Barrentine. *Technometrics*, 35(1):93–94, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269303.

Johnson:1999:EFC

[JFM99] Valen E. Johnson, Mark Fitzgerald, and Harry F. Martz. [Estimating Fatigue Curves with the Random Fatigue-Limit Model]: Discussion. *Technometrics*, 41(4):294–296, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271345. See [PM99].

Jobe:1999:BRB

[Job99] J. Marcus Jobe. Book review: *Principles of Experimental Design and Analysis* by Alberto Garcia-Diaz; Don T. Phillips. *Technometrics*, 41(1):77, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271004.

John:1990:TTF

[Joh90] Peter W. M. John. Time trends and factorial experiments. *Technometrics*, 32(3):275–282, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269104.

Johnson:1991:BRB

[Joh91] Douglas H. Johnson. Book review: *Modern Elementary Probability and Statistics* by Edward J. Dudewicz; Pinyuen Chen; Baldeo K. Taneja. *Technometrics*, 33(3):370–371, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268802.

Jolliffe:1990:BRB

[Jol90] Ian T. Jolliffe. Book review: *Component and Correspondence Analysis: Dimension Reduction by Functional Approximation* by

Jan L. A. van Rijckevorsel; Jan de Leeuw. *Technometrics*, 32 (4):463, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270146`.

Jolliffe:1993:BRB

[Jol93] Ian T. Jolliffe. Book review: *Introduction to Multiple Time Series Analysis* by Helmut Lütkepohl. *Technometrics*, 35(1):88–89, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269296`.

Jolliffe:1996:BRB

[Jol96] Ian Jolliffe. Book review: *Multidimensional Scaling* by Trevor F. Cox; Michael A. A. Cox. *Technometrics*, 38(4):403–404, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271315`.

Jolliffe:1997:BRB

[Jol97] Ian T. Jolliffe. Book review: *Tree Models of Similarity and Association* by James E. Corter. *Technometrics*, 39(2):237, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270927`.

Jones:1990:BRB

[Jon90] Peter W. Jones. Book review: *Applications of Probability* by British Open University Course Team. *Technometrics*, 32(4):457, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270137`.

Jones:1991:BRBb

[Jon91a] Jason Jones. Book review: *Introduction to Probability and Its Applications* by Richard L. Scheaffer. *Technometrics*, 33(3):374–375, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268807`.

Jones:1991:BRBa

[Jon91b] Peter W. Jones. Book review: *Statistical Methods* by The Open University Course Team. *Technometrics*, 33(1):114, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269021`.

Jones:1992:BRB

[Jon92] P. W. Jones. Book review: *Probabilistic Reasoning in Expert Systems, Theory and Algorithms* by Richard E. Neapolitan. *Technometrics*, 34(1):99–100, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269559.

Jones:1993:BRB

[Jon93] Jason R. Jones. Book review: *Statistical Intervals: A Guide for Practitioners* by Gerald J. Hahn; William Q. Meeker. *Technometrics*, 35(3):323, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269526.

Journel:1994:UCS

[Jou94] André G. Journel. [The Use of Conditional Simulation in Nuclear-Waste-Site Performance Assessment]: Discussion. *Technometrics*, 36(2):149–150, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270224. See [Got94c].

Juang:1991:HMM

[JR91] B. H. Juang and L. R. Rabiner. Hidden Markov models for speech recognition. *Technometrics*, 33(3):251–272, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268779.

Jones:1999:BCC

[JR99] Geoffrey Jones and David M. Rocke. Bootstrapping in controlled calibration experiments. *Technometrics*, 41(3):224–233, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270567.

Jin:1999:FPD

[JS99] Jionghua Jin and Jianjun Shi. Feature-preserving data compression of stamping tonnage information using wavelets. *Technometrics*, 41(4):327–339, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271349.

Jensen:1993:OAP

[JV93] Karen L. Jensen and Stephen B. Vardeman. Optimal adjustment in the presence of deterministic process drift and random adjustment error. *Technometrics*, 35(4):376–389, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270271.

Kafadar:1994:ANR

[Kaf94] Karen Kafadar. An application of nonlinear regression in research and development: A case study from the electronics industry. *Technometrics*, 36(3):237–248, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269368.

Kafadar:1999:ER

[Kaf99] Karen Kafadar. Editor's report. *Technometrics*, 41(4):365–366, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271352.

Kahn:1994:BRB

[Kah94] William D. Kahn. Book review: *Measurement Uncertainty: Methods and Applications* by Ronald H. Dieck. *Technometrics*, 36(4):432–433, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269975.

Kalemkarian:1993:BRB

[Kal93] George S. Kalemkarian. Book review: *The Self-Instructional Route to Statistical Process Control and Just-In-Time Manufacturing* by I. Louis Bare; Bebe Bare. *Technometrics*, 35(1):92, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269301.

Kalemkarian:1998:BRB

[Kal98] George S. Kalemkarian. Book review: *The Management of Quality and Its Control* by Charles S. Tapiero. *Technometrics*, 40(4):351–352, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270539.

Kandel:1995:BRB

[Kan95] Abraham Kandel. Book review: *Statistical Applications Using Fuzzy Sets* by Kenneth G. Manton; Max A. Woodbury; H. Dennis Tolley. *Technometrics*, 37(2):237, May 1995. CODEN TCMTA2.

ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269638`.

Katti:1991:BRB

[Kat91] S. K. Katti. Book review: *Statistical Methods and Concepts* by M. N. Das. *Technometrics*, 33(1):114, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269022`.

Katti:1998:BRB

[Kat98] S. K. Katti. Book review: *Operational Subjective Statistical Methods* by Frank Lad. *Technometrics*, 40(2):157–158, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270655`.

Katti:1994:BRB

[KB94] S. K. Katti and Prabha Betne. Book review: *Nonlinear Statistical Models* by Andrej Pazman. *Technometrics*, 36(4):433–434, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269976`.

Kalagnanam:1997:EST

[KD97] Jayant R. Kalagnanam and Urmila M. Diwekar. An efficient sampling technique for off-line quality control. *Technometrics*, 39 (3):308–319, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271135`.

Kedem:1996:BRB

[Ked96] Benjamin Kedem. Book review: *Stochastic Processes* by J. Medhi. *Technometrics*, 38(1):85–86, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268920`.

Kedem:1998:BRB

[Ked98] Benjamin Kedem. Book review: *An Introduction to Stochastic Processes* by Edward P. C. Kao. *Technometrics*, 40(1):78, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271403`.

Kelley:1997:BRB

[Kel97] D. Lynn Kelley. Book review: *Graphing Statistics and Data: Creating Better Charts* by Anders Wallgren; Britt Wallgren; Rolf

Persson; Ulf Jorner; Jan-Aage Haaland. *Technometrics*, 39(4): 429–430, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271516.

Keating:1990:THA

[KGK90] Jerome P. Keating, Ronald E. Glaser, and Norma S. Ketchum. Testing hypotheses about the shape parameter of a gamma distribution. *Technometrics*, 32(1):67–82, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269846.

Khamis:1995:BRB

[Kha95] Imad H. Khamis. Book review: *Reliability Engineering* by K. K. Aggarwal. *Technometrics*, 37(2):234–235, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269634.

Khuri:1992:RSM

[Khu92] A. I. Khuri. Response surface models with random block effects. *Technometrics*, 34(1):26–37, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269549.

Kianifard:1990:BRB

[Kia90] Farid Kianifard. Book review: *Applied Linear Regression Models* by J. Neter; W. Wasserman; M. H. Kutner. *Technometrics*, 32(3):352–353, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269127.

Kianifard:1992:BRBa

[Kia92a] Farid Kianifard. Book review: *A First Course in the Theory of Linear Statistical Models* by R. H. Myers; J. S. Milton. *Technometrics*, 34(2):228–229, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269243.

Kianifard:1992:BRBb

[Kia92b] Farid Kianifard. Book review: *Applied Multivariate Data Analysis, Volume I: Regression and Experimental Design* by J. D. Jobson. *Technometrics*, 34(4):490–491, November 1992. CODEN

TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268953.

Kianifard:1993:BRBa

[Kia93a] Farid Kianifard. Book review: *Analysis of Variance in Experimental Design* by Harold R. Lindman. *Technometrics*, 35(2):222–223, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269670.

Kianifard:1993:BRBb

[Kia93b] Farid Kianifard. Book review: *Applied Multivariate Data Analysis, Volume II: Categorical and Multivariate Methods* by J. D. Jobson. *Technometrics*, 35(3):326–327, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269529.

Kianifard:1994:BRB

[Kia94] Farid Kianifard. Book review: *Models for Repeated Measurements* by J. K. Lindsey. *Technometrics*, 36(4):426–427, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269966.

Kianifard:1995:BRBa

[Kia95a] Farid Kianifard. Book review: *Logistic Regression: A Self-Learning Text* by D. G. Kleinbaum. *Technometrics*, 37(1):116–117, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269163.

Kianifard:1995:BRBb

[Kia95b] Farid Kianifard. Book review: *Logistic Regression with Missing Values in the Covariates* by W. Vach. *Technometrics*, 37 (4):460–461, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269744.

Kiiveri:1992:CVA

[Kii92] H. T. Kiiveri. Canonical variate analysis of high-dimensional spectral data. *Technometrics*, 34(3):321–331, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270038.

Kim:1991:BRB

[Kim91] Jee Soo Kim. Book review: *Parameter Estimation in Reliability and Life Span Models* by Clifford Cohen; Betty Jones Whitten. *Technometrics*, 33(1):117–118, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269028.

King:1991:BRB

[Kin91] Terry King. Book review: *Smooth Tests of Goodness of Fit* by J. Rayner; D. Best. *Technometrics*, 33(4):491, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269440.

King:1993:BRB

[Kin93] Dennis W. King. Book review: *Statistical Quality Design and Control* by Richard E. DeVor; Tsong-how Chang; John W. Sutherland. *Technometrics*, 35(3):331–332, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269537.

King:1997:BRB

[Kin97] Terry King. Book review: *A Guide to Chi-Squared Testing* by Priscilla E. Greenwood; Mikhail S. Nickulin. *Technometrics*, 39 (4):431, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271520.

Kirmani:1992:BRB

[Kir92] S. N. U. A. Kirmani. Book review: *Stochastic Processes with Applications* by R. N. Bhattacharya; E. C. Waymire. *Technometrics*, 34(1):99, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269558.

Kirmani:1993:BRB

[Kir93] Syed N. U. A. Kirmani. Book review: *Performance Modeling of Automated Manufacturing Systems* by N. Viswanadham; Y. Narahari. *Technometrics*, 35(4):456, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270286.

Kvam:1999:EFC

[KK99] Paul H. Kvam and Eric P. Kvam. [Estimating Fatigue Curves with the Random Fatigue-Limit Model]: Discussion. *Technometrics*, 41(4):292–294, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271344. See [PM99].

Klein:1994:BRB

[Kle94] John Klein. Book review: *Statistical Models Based on Counting Process* by Per Kragh Andersen; Ørnulf Borgan; Richard D. Gill; Niels Keiding. *Technometrics*, 36(1):111–112, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269205.

Kalbfleisch:1991:MAP

[KLR91] J. D. Kalbfleisch, J. F. Lawless, and J. A. Robinson. Methods for the analysis and prediction of warranty claims. *Technometrics*, 33(3):273–285, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268780.

Kelly:1994:INE

[KM94] Robert J. Kelly and Thomas Mathew. Improved nonnegative estimation of variance components in some mixed models with unbalanced data. *Technometrics*, 36(2):171–181, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270229.

Krishnamoorthy:1999:CAM

[KM99] K. Krishnamoorthy and Thomas Mathew. Comparison of approximation methods for computing tolerance factors for a multivariate normal population. *Technometrics*, 41(3):234–249, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270568.

Kandel:1995:DVR

[KMP95] Abraham Kandel, Alejandro Martins, and Roberto Pacheco. Discussion: On the very real distinction between fuzzy and statistical methods. *Technometrics*, 37(3):276–281, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269909.

Ko:1995:BRBb

[Ko95a] Daijin Ko. Book review: *A Handbook of Statistical Analyses Using S-Plus* by Brian S. Everitt. *Technometrics*, 37(2):232–233, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269630.

Ko:1995:BRBa

[Ko95b] Daijin Ko. Book review: *An Introduction to S and S-Plus* by Phil Spector. *Technometrics*, 37(2):232, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269629.

Koehler:1992:BRB

[Koe92] James R. Koehler. Book review: *Statistical Inference for Spatial Processes* by B. D. Ripley. *Technometrics*, 34(1):109, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269573.

Kohberger:1990:BRB

[Koh90] Robert Kohberger. Book review: *Similarity and Clustering in Chemical Information Systems* by Peter Willet. *Technometrics*, 32(3):359–360, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269137.

Kohberger:1994:BRB

[Koh94] Robert C. Kohberger. Book review: *Cluster Analysis* by Brian S. Everitt. *Technometrics*, 36(2):216, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270235.

Koons:1990:BRB

[Koo90] George F. Koons. Book review: *Statistical Thinking for Managers* by David K. Hildebrand; Lyman Ott. *Technometrics*, 32 (2):234–235, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268885.

Kotlovker:1992:BRB

[Kot92] Debbi L. Kotlovker. Book review: *Statistics* by Richard J. Larsen; Morris L. Marx. *Technometrics*, 34(2):245, May 1992. CODEN

TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269270.

Katti:1993:BRB

[KR93] S. K. Katti and Larry Ries. Book review: *Exploring the Limits of Bootstrap* by Raoul LePage; Lynn Billard. *Technometrics*, 35(2):226–227, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269675.

Kramer:1990:BRB

[Kra90] Tim Kramer. Book review: *Statistical Process Control and beyond* by Richard R. Clements. *Technometrics*, 32(1):97, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269853.

Kramer:1992:BRB

[Kra92] Tim Kramer. Book review: *SPC for Practitioners: Special Cases and Continuous Processes* by Gary Fellers. *Technometrics*, 34(4): 493–494, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268957.

Kvam:1993:LTV

[KS93] Paul H. Kvam and Francisco J. Samaniego. Life testing in variably scaled environments. *Technometrics*, 35(3):306–314, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269523.

Kim:1996:NBC

[KSJ96] Choongrak Kim, Barry E. Storer, and Meeseon Jeong. A note on Box–Cox transformation diagnostics. *Technometrics*, 38(2): 178–180, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270411.

Koch:1990:DSI

[KTTS90] Gary G. Koch, Catherine Tangen, Gail Tudor, and Maura E. Stokes. Discussion: Strategies and issues for the analysis of ordered categorical data from multifactor studies in industry. *Technometrics*, 32(2):137–149, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268856.

Kundu:1993:EPU

[Kun93] Debasis Kundu. Estimating the parameters of undamped exponential signals. *Technometrics*, 35(2):215–218, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269666.

Kunert:1997:UFS

[Kun97] Joachim Kunert. On the use of the factor-sparsity assumption to get an estimate of the variance in saturated designs. *Technometrics*, 39(1):81–90, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270775.

Kushary:1992:BRB

[Kus92] Debashis Kushary. Book review: *Nonlinear Estimation* by Gavin J. S. Ross. *Technometrics*, 34(1):108, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269572.

Kushler:1993:BRB

[Kus93] Robert Kushler. Book review: *SPC Using Lotus 1–2–3* by Steven M. Zimmerman; Robert N. Zimmerman. *Technometrics*, 35(4): 457–458, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270288.

Kushary:1998:BRB

[Kus98] Debashis Kushary. Book review: *The EM Algorithm and Extensions* by Geoffrey J. McLachlan; Thriyambakam Krishnan. *Technometrics*, 40(3):260, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271189.

Kvam:1996:ETC

[Kva96] Paul H. Kvam. Estimation techniques for common cause failure data with different system sizes. *Technometrics*, 38(4):382–388, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271309.

Koschat:1991:BRB

[KY91] Martin A. Koschat and Richard A. Young. Book review: *Maximum Entropy Methods in Science and Engineering (Vol. 2)* by G.

J. Ericson; C. R. Smith. *Technometrics*, 33(4):486–487, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269432.

LaLonde:1992:BRB

[LaL92] Steven M. LaLonde. Book review: *SAS Applications Programming, a Gentle Introduction* by Frank C. DiIorio. *Technometrics*, 34(3):366–367, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270061.

LaLonde:1995:BRB

[LaL95] Steven M. LaLonde. Book review: *Chemometrics for Analytical Chemistry Volume 1: PC-Aided Statistical Data Analysis* by Milan Meloun; Jiri Militky; Michele Forina. *Technometrics*, 37(1):114–115, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269160.

Lalonde:1999:BRB

[Lal99] Steven M. Lalonde. Book review: *A First Course in Multivariate Statistics* by Bernard Flury. *Technometrics*, 41(3):262–263, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270571.

Lambert:1990:BRB

[Lam90] Diane Lambert. Book review: *Statistical Methods for Quality Improvement* by Thomas P. Ryan. *Technometrics*, 32(3):340, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269111.

Lambert:1992:ZIP

[Lam92] Diane Lambert. Zero-inflated Poisson regression, with an application to defects in manufacturing. *Technometrics*, 34(1):1–14, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269547.

Lambert:1998:DAV

[Lam98] Diane Lambert. Discussion: Another view. *Technometrics*, 40(3):201–203, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271172.

Larsen:1995:BRB

[Lar95] Greg Larsen. Book review: *Statistics in Engineering: A Practical Approach* by Andrew V. Metcalfe. *Technometrics*, 37(4):455, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269737`.

Laubscher:1994:CUS

[Lau94] Nico F. Laubscher. Comments on the use of spectral control charts. *Technometrics*, 36(3):335–336, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269405`.

Lawrence:1992:BRB

[Law92] Kenneth D. Lawrence. Book review: *Modern Statistical Systems and GPSS Simulation* by Zaven A. Karian; Edward J. Dudewicz. *Technometrics*, 34(3):366, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270060`.

Lawera:1995:BRB

[Law95] Martin Lawera. Book review: *Predictive Inference: An Introduction* by Seymour Geisser. *Technometrics*, 37(1):121, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269169`.

Lawson:1996:BRB

[Law96] John Lawson. Book review: *Reliability: Probabilistic Models and Statistical Methods* by Lawrence M. Leemis. *Technometrics*, 38 (3):287–288, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270616`.

Lawrence:1998:BRB

[Law98] Kenneth D. Lawrence. Book review: *Data Analysis, Regression and Forecasting* by Arthur Schleifer,; David E. Bell. *Technometrics*, 40(3):258–259, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271186`.

Lamb:1996:TEV

[LBB96] R. H. Lamb, Dennis D. Boos, and Cavell Brownie. Testing for effects on variance in experiments with factorial treatment structure and nested errors. *Technometrics*, 38(2):170–177, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270410.

Lucas:1990:CCN

[LC90] James M. Lucas and R. Dennis Cook. Comments on Cook and Nachtsheim (1989). *Technometrics*, 32(3):363–365, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269141.

Le-Cointe:1994:BRB

[LC94] Lillian Le-Cointe. Book review: *Basic Quality Improvement* by Susan M. Garrity. *Technometrics*, 36(1):124, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269221.

Le-Cointe:1998:BRB

[LC98] Lillian Le-Cointe. Book review: *Applied Statistics: A Handbook of Techniques* by Lothar Sachs. *Technometrics*, 40(2):155, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270651.

Lin:1992:PPP

[LD92] Dennis K. J. Lin and Norman R. Draper. Projection properties of Plackett and Burman designs. *Technometrics*, 34(4):423–428, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268941.

Lee:1990:BRB

[Lee90] Haelie Lee. Book review: *Interpreting Data* by Alan Anderson. *Technometrics*, 32(4):452–453, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270130.

Lee:1993:BRB

[Lee93] Kwan R. Lee. Book review: *Reliability Methods for Engineers* by K. S. Krishnamoorthi. *Technometrics*, 35(3):333, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269540.

Lee:1994:BRB

[Lee94] Carl Lee. Book review: *Beginning Statistics A to Z* by William Mendenhall. *Technometrics*, 36(3):329, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269392.

Lee:1999:BRB

[Lee99] Kwan Lee. Book review: *The Analysis of Proximity Data* by B. S. Everitt; S. Rabe-hesketh. *Technometrics*, 41(1):73–74, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270998.

Leigh:1991:BRB

[Lei91] Stefan Leigh. Book review: *Probability and Random Processes for Electrical Engineering* by Alberto Leon-Garcia. *Technometrics*, 33(3):372–373, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268805.

Leigh:1992:BRB

[Lei92] Stefan D. Leigh. Book review: *U-Statistics Theory and Practice* by A. J. Lee. *Technometrics*, 34(3):364–365, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270058.

Leigh:1993:BRB

[Lei93] Stefan Leigh. Book review: *A User's Guide to Principal Components* by J. Edward Jackson. *Technometrics*, 35(1):84–85, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269292.

Leigh:1997:BRB

[Lei97] Stefan Leigh. Book review: *The Pleasures of Probability* by Richard Isaac. *Technometrics*, 39(1):109, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270792.

Leigh:1999:BRB

[Lei99] Stefan Leigh. Book review: *Statistical Inference Based on the Likelihood* by Adelchi Azzalini. *Technometrics*, 41(2):176–177, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270746.

Lenth:1990:BRB

[Len90] Russell V. Lenth. Book review: *Computer Intensive Methods for Testing Hypotheses: An Introduction* by Eric W. Noreen. *Technometrics*, 32(4):453, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270131.

Lenth:1993:BRB

[Len93] Russell V. Lenth. Book review: *Meta-Analysis by the Confidence Profile Method: The Statistical Synthesis of Evidence* by David M. Eddy; Vic Hasselblad; Ross Shachter. *Technometrics*, 35(2):237, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269690.

Lenth:1995:BRB

[Len95] Russell V. Lenth. Book review: *Computer Intensive Statistical Methods: Validation, Model Selection, and Bootstrap* by J. S. Urban Hjorth. *Technometrics*, 37(4):458–459, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269741.

LePage:1990:BRBa

[LeP90a] Raoul LePage. Book review: *Probability: Methods and Measurement* by Anthony O'Hagan. *Technometrics*, 32(1):112, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269871.

LePage:1990:BRBb

[LeP90b] Raoul LePage. Book review: *Simulation Methodology for Statisticians, Operations Analysts, and Engineers (Vol. 1)* by P. A. W. Lewis; E. J. Orav. *Technometrics*, 32(3):351–352, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269126.

Lewis:1992:BRB

[Lew92] Richard A. Lewis. Book review: *Quality Assurance for the Chemical and Process Industries* by American Society for Quality Control. *Technometrics*, 34(1):102–103, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269563.

Lewis:1993:BRB

[Lew93] Richard A. Lewis. Book review: *Optimization and Variation Reduction in Quality* by Wayne A. Taylor. *Technometrics*, 35(1):92–93, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269302.

Luceno:1999:EDP

[LG99] Alberto Luceño and Francisco J. González. Effects of dynamics on the properties of feedback adjustment schemes with dead band. *Technometrics*, 41(2):142–152, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270730.

Li:1997:BRB

[LH97] Ta-Hsin Li and Tailen Hsing. Book review: *Complex Stochastic Systems and Engineering* by D. M. Titterington. *Technometrics*, 39(3):336, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271142. See correction [Ano97e].

Li:1997:TSC

[Li97] Ta-Hsin Li. Time series characterization, Poisson integral, and robust divergence measures. *Technometrics*, 39(4):357–371, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271500.

Ling:1990:BRB

[Lin90] Robert F. Ling. Book review: *Principles of Multivariate Analysis* by W. Krzanowski. *Technometrics*, 32(2):225, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268873.

Lindstrom:1992:BRB

[Lin92] Mary J. Lindstrom. Book review: *The Analysis of Repeated Measures* by M. J. Crowder; D. J. Hand. *Technometrics*, 34(2):227–228, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269242.

Lin:1993:ALF

[Lin93a] Dennis K. J. Lin. Another look at first-order saturated designs: the p-efficient designs. *Technometrics*, 35(3):284–292, August 1993.

CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269521. See correction [Lin95a].

Lin:1993:NCS

[Lin93b] Dennis K. J. Lin. A new class of supersaturated designs. *Technometrics*, 35(1):28–31, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269286. See comments [WKWL95].

Lin:1995:CAL

[Lin95a] Dennis K. J. Lin. Correction: "Another look at first-order saturated designs: the p-efficient designs" [*Technometrics* **35** (1993), no. 3, 284–292]. *Technometrics*, 37(4):473, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269765. See [Lin93a].

Lin:1995:GSS

[Lin95b] Dennis K. J. Lin. Generating systematic supersaturated designs. *Technometrics*, 37(2):213–225, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269622.

Lin:1999:BRB

[Lin99] Yachen Lin. Book review: *Introductory Statistics and Random Phenomena* by Manfred Denker; Wojbor A. Woyczynski. *Technometrics*, 41(3):270, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270584.

Little:1991:BRB

[Lit91] Kevin Little. Book review: *Presenting Statistics: A Manager's Guide to the Persuasive Use of Statistics* by L. Witzling; R. Greenstreet. *Technometrics*, 33(4):478, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269425.

Liu:1992:BRBa

[Liu92a] Shin Ta Liu. Book review: *Decision-Making under Uncertainty: An Applied Statistics Approach* by George K. Chacko. *Technometrics*, 34(2):243–244, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269267.

Liu:1992:BRBb

[Liu92b] Shin Ta Liu. Book review: *Making Hard Decisions, an Introduction to Decision Analysis* by Robert T. Clemen. *Technometrics*, 34(3):365–366, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270059.

Liu:1999:BRB

[Liu99] Shin Ta Liu. Book review: *Risk Modeling, Assessment, and Management* by Yacov Y. Haimes. *Technometrics*, 41(4):376–377, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271367.

Liao:1996:COT

[LIV96] C. T. Liao, H. K. Iyer, and D. F. Vecchia. Construction of orthogonal two-level designs of user-specified resolution where $N \neq 2^k$. *Technometrics*, 38(4):342–353, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271305.

Li:1999:MZI

[LLP+99] Chin-Shang Li, Jye-Chyi Lu, Jinho Park, Kyungmoo Kim, Paul A. Brinkley, and John P. Peterson. Multivariate zero-inflated Poisson models and their applications. *Technometrics*, 41(1):29–38, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270992.

Lucas:1996:CCE

[LLW+96] James M. Lucas, J. M. Lucas, William J. Welch, Robert J. Buck, Jerome Sacks, Henry P. Wynn, Max D. Morris, and Matthias Schonlau. Comments on computer experiments. *Technometrics*, 38(2):197–203, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270442. See [WBS+92].

Lu:1993:UDM

[LM93] C. Joseph Lu and William Q. Meeker. Using degradation measures to estimate a time-to-failure distribution. *Technometrics*, 35(2):161–174, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269661.

Lawless:1995:SSR

[LN95] J. F. Lawless and C. Nadeau. Some simple robust methods for the analysis of recurrent events. *Technometrics*, 37(2):158–168, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269617.

Liski:1996:PRM

[LN96] Erkki P. Liski and Tapio Nummi. Prediction in repeated-measures models with engineering applications. *Technometrics*, 38(1):25–36, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268900.

Loughin:1997:PTE

[LN97] Thomas M. Loughin and William Noble. A permutation test for effects in an unreplicated factorial design. *Technometrics*, 39(2):180–190, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270906.

Loh:1992:BRB

[Loh92] Wei-Yin Loh. Book review: *Symmetric Multivariate and Related Distributions* by Kai-Tai Fang; Samuel Kotz; Kai-Wang Ng. *Technometrics*, 34(2):235–236, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269255.

Lohr:1994:BRB

[Loh94] Sharon Lohr. Book review: *Statistics* by David Freeman; Robert Pisani; Roger Purves; Ani Adhikari. *Technometrics*, 36(1):119–120, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269215.

Lordo:1992:BRB

[Lor92] Robert A. Lordo. Book review: *A Course in Simulation* by Sheldon M. Ross. *Technometrics*, 34(2):236–238, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269257.

Lordo:1993:BRB

[Lor93] Robert A. Lordo. Book review: *Simulation: A Statistical Perspective* by Jack Kleijnen; Willem van Groenendaal. *Technometrics*, 35(4):453–454, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270283.

Lordo:1999:BRB

[Lor99] Robert A. Lordo. Book review: *Statistical Reasoning and Methods* by Richard A. Johnson; Kam-Wah Tsui. *Technometrics*, 41 (3):269–270, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270583.

Leger:1992:BTA

[LPR92] Christian Léger, Dimitris N. Politis, and Joseph P. Romano. Bootstrap technology and applications. *Technometrics*, 34(4):378–398, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268938.

Lu:1997:SIT

[LPY97] Jye-Chyi Lu, Jinho Park, and Qing Yang. Statistical inference of a time-to-failure distribution derived from linear degradation data. *Technometrics*, 39(4):391–400, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271503.

Lucas:1990:CCV

[LS90a] James M. Lucas and Michael S. Saccucci. [CUSUM Charts with Variable Sampling Intervals]: Discussion. *Technometrics*, 32(4): 387–388, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270116. See [RAA90a].

Lucas:1990:EWMa

[LS90b] James M. Lucas and Michael S. Saccucci. Exponentially weighted moving average control schemes: Properties and enhancements. *Technometrics*, 32(1):1–12, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269835. See discussion [Bax90, WM90, FHT90, Hun90b, MH90] and response [LS90c].

Lucas:1990:EWMb

[LS90c] James M. Lucas and Michael S. Saccucci. [Exponentially Weighted Moving Average Control Schemes: Properties and Enhancements]:

Response. *Technometrics*, 32(1):27–29, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269841.

Laviolette:1995:PSVb

[LSBW95a] Michael Laviolette, John W. Seaman, Jr., J. Douglas Barrett, and William H. Woodall. [A Probabilistic and Statistical View of Fuzzy Methods]: Reply. *Technometrics*, 37(3):287–292, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269912. See [LSBW95b].

Laviolette:1995:PSVa

[LSBW95b] Michael Laviolette, John W. Seaman, Jr., J. Douglas Barrett, and William H. Woodall. A probabilistic and statistical view of fuzzy methods. *Technometrics*, 37(3):249–261, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269905. See discussion and reply [LSBW95a].

Leon:1993:SAP

[LST93] Ramon V. Leon, Anne C. Shoemaker, and Kwok-Leung Tsui. [A Systematic Approach to Planning for a Designed Industrial Experiment]: Discussion. *Technometrics*, 35(1):21–24, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269284. See [CM93b].

Lawless:1996:PPM

[LT96] J. F. Lawless and K. Thiagarajah. A point-process model incorporating renewals and time trends, with application to repairable systems. *Technometrics*, 38(2):131–138, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270406.

Lucas:1994:RLD

[Luc94] James M. Lucas. [Run-Length Distributions of Special-Cause Control Charts for Correlated Processes]: Discussion. *Technometrics*, 36(1):17–19, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269192. See [WMP94a].

Luceno:1998:PDF

[Luc98] Alberto Luceño. Performance of discrete feedback adjustment schemes with dead band, under stationary versus nonstationary stochastic disturbance. *Technometrics*, 40(3):223–233, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271178.

LuValle:1990:BRB

[LuV90] M. J. LuValle. Book review: *Generalized Poisson Distributions: Properties and Applications* by P. C. Consul. *Technometrics*, 32 (3):346–347, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269119.

Li:1997:CPA

[LW97] William W. Li and C. F. Jeff Wu. Columnwise-pairwise algorithms with applications to the construction of supersaturated designs. *Technometrics*, 39(2):171–179, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270905. See comments [LW98].

Li:1998:CLW

[LW98] William W. Li and C. F. Jeff Wu. Comments on Li and Wu (1997). *Technometrics*, 40(4):362, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270560. See [LW97].

Lowry:1992:MEW

[LWCR92] Cynthia A. Lowry, William H. Woodall, Charles W. Champ, and Steven E. Rigdon. A multivariate exponentially weighted moving average control chart. *Technometrics*, 34(1):46–53, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269551.

Lwin:1994:AWF

[Lwi94] Thaung Lwin. Analysis of weight frequency distributions using replicated data. *Technometrics*, 36(1):28–36, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269196.

Lynch:1994:BRB

[Lyn94] Richard O. Lynch. Book review: *Statistics in Practice* by Ernest A. Blaisdell. *Technometrics*, 36(2):222–223, May 1994. CODEN

TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270243.

Lynch:1995:BRB

[Lyn95] James Lynch. Book review: *Reliability, Maintainability and Supportability: A Probabilistic Approach* by J. Knezevic. *Technometrics*, 37(1):122, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269171.

Lynch:1997:BRBa

[Lyn97a] James Lynch. Book review: *Reliability Engineering* by E. A. Elsayed. *Technometrics*, 39(2):226–227, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270911.

Lynch:1997:BRBb

[Lyn97b] Richard Otis Lynch. Book review: *Applied Factor Analysis in the Natural Sciences* by Richard Reyment; K. G. Jöreskog. *Technometrics*, 39(4):427, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271512.

Lynch:1999:BRB

[Lyn99] Richard O. Lynch. Book review: *Introduction to Design and Analysis of Experiments* by George W. Cobb. *Technometrics*, 41(2): 170, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270737.

Maryak:1992:BRB

[MA92] John L. Maryak and David J. Abeshouse. Book review: *Probability, Statistical Optics, and Data Testing: A Problem Solving Approach* by B. R. Frieden. *Technometrics*, 34(3):369–370, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270065.

Mack:1990:BRB

[Mac90a] Gregory Mack. Book review: *Chemometrics: A Textbook* by D. L. Massart; B. G. M. Vandeginste; S. N. Deming; Y. Michotte; L. Kaufman. *Technometrics*, 32(1):104–105, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269863.

MacKay:1990:CCB

[Mac90b] Jock MacKay. Commentary: [Communications between Statisticians and Engineers/Physical Scientists]. *Technometrics*, 32(3): 263–264, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269099`. See [HK90].

MacGregor:1992:SPM

[Mac92] John F. MacGregor. [Statistical Process Monitoring and Feedback Adjustment]: Discussion. *Technometrics*, 34(3):273–275, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270030`. See [BK92a].

Madrigal:1996:BRB

[Mad96] J. L. Madrigal. Book review: *Stochastic Models: An Algorithmic Approach* by Henk C. Tijms. *Technometrics*, 38(1):84, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268918`.

Madrigal:1998:BRB

[Mad98] J. L. Madrigal. Book review: *Theory of Sample Surveys* by M. E. Thompson. *Technometrics*, 40(4):356–357, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270546`.

Magoun:1990:BRB

[Mag90] A. Dale Magoun. Book review: *Decision Estimation and Classification* by Charles W. Therrien. *Technometrics*, 32(4):464, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270148`.

Magoun:1996:BRB

[Mag96] A. Dale Magoun. Book review: *Elementary Statistics Laboratory Manual* by John D. Spurrier; Don Edwards; Lori A. Thombs. *Technometrics*, 38(2):190, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270428`.

Mallows:1995:MC

[Mal95] Colin L. Mallows. More comments on C_P. *Technometrics*, 37 (4):362–372, November 1995. CODEN TCMTA2. ISSN 0040-

1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269729.

Margavio:1994:BRB

[Mar94] Thomas M. Margavio. Book review: *Data Quality: Management and Technology* by Thomas C. Redman. *Technometrics*, 36(1): 122–123, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269220.

Marx:1996:IRP

[Mar96] Brian D. Marx. Iteratively reweighted partial least squares estimation for generalized linear regression. *Technometrics*, 38(4): 374–381, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271308.

Marcucci:1997:BRB

[Mar97] Mark Marcucci. Book review: *Applied Multivariate Techniques* by Subhash Sharma. *Technometrics*, 39(1):101, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270777.

Maryak:1999:BRB

[Mar99] John Maryak. Book review: *Bayesian Heuristic Approach to Discrete and Global Optimization* by J. Mockus; W. Eddy; A. Mockus; L. Mockus; G. Reklaitis. *Technometrics*, 41(4):378–379, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271369.

Mason:1999:BRB

[Mas99] Robert L. Mason. Book review: *Multivariate Quality Control: Theory and Applications* by Camil Fuchs; Ron S. Kenett. *Technometrics*, 41(2):168–169, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270734.

Mathew:1996:BRB

[Mat96] Thomas Mathew. Book review: *Methods of Multivariate Analysis* by Alvin C. Rencher. *Technometrics*, 38(1):76–77, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268907.

Mathew:1997:BRB

[Mat97] Thomas Mathew. Book review: *Multivariate Statistical Analysis* by Narayan C. Giri. *Technometrics*, 39(1):101, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270778`.

Mathew:1998:BRB

[Mat98] Thomas Mathew. Book review: *Mathematical Tools for Applied Multivariate Analysis* by J. Douglas Carroll; Paul E. Green; Anil Chaturvedi. *Technometrics*, 40(3):259, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271187`.

Mazu:1993:BRB

[Maz93] Michael J. Mazu. Book review: *Regression Analysis by Example* by Samprit Chatterjee; Bertram Price. *Technometrics*, 35 (1):86–87, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269294`.

Mazu:1998:BRB

[Maz98] Michael J. Mazu. Book review: *Quality* by Donna C. S. Summers. *Technometrics*, 40(3):257–258, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271184`.

Mee:1998:SLD

[MB98] Robert W. Mee and Rodney L. Bates. Split-lot designs: Experiments for multistage batch processes. *Technometrics*, 40(2):127–140, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270647`.

McArthur:1990:BRB

[McA90] Richard D. McArthur. Book review: *Trace Residue Analysis: Chemometric Estimations of Sampling, Amount, and Error* by D. A. Kurtz. *Technometrics*, 32(4):461–462, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270144`.

McComb:1990:BRB

[McC90] Mark Anthony McComb. Book review: *Quality Control for Operators and Foremen* by K. S. Krishnamoorthi. *Technometrics*, 32

(4):459, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270141`.

McComb:1991:BRB

[McC91] Mark Anthony McComb. Book review: *Quality Control* by Dale H. Besterfield. *Technometrics*, 33(4):473–474, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269421`.

McCool:1994:BRB

[McC94] John I. McCool. Book review: *Methods for Experimental Design: Principles and Applications for Physicists and Chemists* by Jacques L. Goupy. *Technometrics*, 36(3):318–319, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269380`.

McComb:1998:BRB

[McC98] Mark A. McComb. Book review: *Measuring Process Capability* by Davis R. Bothe. *Technometrics*, 40(4):350–351, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270538`.

McCool:1999:BRB

[McC99] John I. McCool. Book review: *Engineering Reliability* by Richard E. Barlow. *Technometrics*, 41(1):75–76, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271001`.

McGuire:1994:BRB

[McG94] Stephen A. McGuire. Book review: *Statistical Process Control for Quality Improvement* by James R. Evans. *Technometrics*, 36 (4):420, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269958`.

McLaughlin:1995:BRB

[McL95] Gregory C. McLaughlin. Book review: *Practical Statistical Process Control: A Tool for Quality Manufacturing* by Fred Alsup; Ricky M. Watson. *Technometrics*, 37(4):461–462, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269746`.

Mee:1996:CUC

[ME96] Robert W. Mee and Keith R. Eberhardt. A comparison of uncertainty criteria for calibration. *Technometrics*, 38(3):221–229, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270605.

Marx:1999:GLR

[ME99] Brian D. Marx and Paul H. C. Eilers. Generalized linear regression on sampled signals and curves: A P-spline approach. *Technometrics*, 41(1):1–13, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270990.

Mee:1990:IPS

[Mee90a] Robert W. Mee. An improved procedure for screening based on a correlated, normally distributed variable. *Technometrics*, 32 (3):331–337, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269110.

Mee:1990:STI

[Mee90b] Robert W. Mee. Simultaneous tolerance intervals for normal populations with common variance. *Technometrics*, 32(1):83–92, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269847.

Meek:1991:BRB

[Mee91a] Gary E. Meek. Book review: *Investigations for a Course in Statistics* by Martin A. Tanner. *Technometrics*, 33(4):494, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269444.

Meeker:1991:BRB

[Mee91b] William Q. Meeker, Jr. Book review: *Accelerated Testing: Statistical Models, Test Plans, and Data Analyses* by Wayne Nelson. *Technometrics*, 33(2):236–238, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269050.

Meeker:1998:ADT

[MEL98] William Q. Meeker, Luis A. Escobar, and C. Joseph Lu. Accelerated degradation tests: Modeling and analysis. *Technomet-*

rics, 40(2):89–99, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270643.

Menten:1991:BRB

[Men91] Tom Menten. Book review: *Quality Engineering Using Robust Design* by Madhav Phadke. *Technometrics*, 33(2):236, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269049.

Mee:1991:CST

[MER91] Robert W. Mee, Keith R. Eberhardt, and Charles P. Reeve. Calibration and simultaneous tolerance intervals for regression. *Technometrics*, 33(2):211–219, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269047.

MacGregor:1990:EWM

[MH90] John F. MacGregor and Thomas J. Harris. [Exponentially Weighted Moving Average Control Schemes: Properties and Enhancements]: Discussion. *Technometrics*, 32(1):23–26, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269840. See [LS90b].

Mi:1997:BRB

[Mi97] Jie Mi. Book review: *Computational Statistics in Climatology* by Ilya Polyak. *Technometrics*, 39(4):428–429, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271514.

Mi:1999:BRB

[Mi99] Jie Mi. Book review: *Robust Nonparametric Statistical Methods* by T. P. Hettmansperger; J. W. McKean. *Technometrics*, 41(1):74, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270999.

Milliken:1990:BRB

[Mil90] George A. Milliken. Book review: *Nonlinear Regression Analysis and Its Applications* by Douglas M. Bates; Donald G. Watts. *Technometrics*, 32(2):219–220, May 1990. CODEN TCMTA2.

ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268866.

Miller:1991:BRB

[Mil91] Bill Miller. Book review: *Principles of Quality Control* by Jerry Banks. *Technometrics*, 33(3):358–359, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268790.

Miller:1994:BRB

[Mil94] John E. Miller. Book review: *A Basic Approach to Quality Control and SPC* by Peter D. Mauch. *Technometrics*, 36(4):424–425, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269964.

Miller:1997:SPC

[Mil97] Arden Miller. Strip-plot configurations of fractional factorials. *Technometrics*, 39(2):153–161, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270903.

Milliken:1998:BRB

[Mil98] George A. Milliken. Book review: *Statistical Methods: A Geometric Primer* by David J. Saville; Graham R. Wood. *Technometrics*, 40(1):78–80, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271405.

Miller:1999:BRB

[Mil99] Melinda A. Miller. Book review: *Statistical Methods for Engineers* by G. Geoffrey Vining. *Technometrics*, 41(3):264–265, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270574.

Minton:1993:BRB

[Min93] Paul D. Minton. Book review: *Sample Survey Principles and Methods* by Vic Barnett. *Technometrics*, 35(2):235, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269688.

Morrell:1991:RTN

[MJ91] Christopher H. Morrell and Richard A. Johnson. Random truncation and neutrinos. *Technometrics*, 33(4):429–440, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269415.

Martz:1996:EBE

[MKA96] Harry F. Martz, Paul H. Kvam, and Lee R. Abramson. Empirical Bayes estimation of the reliability of nuclear-power-plant emergency Diesel generators. *Technometrics*, 38(1):11–24, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268899.

Meeker:1995:ALT

[ML95] William Q. Meeker and Michael J. LuValle. An accelerated life test model based on reliability kinetics. *Technometrics*, 37(2):133–146, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269615.

McWilliams:1992:CLV

[MLV92] Thomas P. McWilliams, Thomas J. Lorenzen, and Lonnie C. Vance. Comments on Lorenzen and Vance (1986). *Technometrics*, 34(2):248–249, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269276.

Meeter:1994:OAL

[MM94] Carol A. Meeter and William Q. Meeker, Jr. Optimum accelerated life tests with a nonconstant scale parameter. *Technometrics*, 36(1):71–83, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269200.

Merchant:1998:IMC

[MME98] Aparna Merchant, Melinda McCann, and Don Edwards. Improved multiple comparisons with a control in response surface analysis. *Technometrics*, 40(4):297–303, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270530.

Morris:1993:BDA

[MMY93] Max D. Morris, Toby J. Mitchell, and Donald Ylvisaker. Bayesian design and analysis of computer experiments: Use of derivatives in surface prediction. *Technometrics*, 35(3):243–255, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269517.

Meyer:1995:CEA

[MN95] Ruth K. Meyer and Christopher J. Nachtsheim. The coordinate-exchange algorithm for constructing exact optimal experimental designs. *Technometrics*, 37(1):60–69, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269153.

Moore:1990:CCB

[Moo90] David S. Moore. Commentary: [Communications between Statisticians and Engineers/Physical Scientists]. *Technometrics*, 32(3): 265–266, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269100. See [HK90].

Moore:1991:BRB

[Moo91] Leslie M. Moore. Book review: *Statistical Modelling in GLIM* by Murray Aitkin; Dorothy Anderson; Brian Francis; John Hinde. *Technometrics*, 33(1):109–110, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269016.

Moore:1996:BRB

[Moo96] Leslie M. Moore. Book review: *The Basic Practice of Statistics* by David S. Moore. *Technometrics*, 38(4):404–405, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271317.

Moore:1999:BRB

[Moo99] Roger H. Moore. Book review: *Regression Graphics: Ideas for Studying Regressions through Graphics* by R. Dennis Cook. *Technometrics*, 41(4):368–369, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271354.

Morris:1991:FSP

[Mor91] Max D. Morris. Factorial sampling plans for preliminary computational experiments. *Technometrics*, 33(2):161–174, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269043`.

Morganstein:1992:BRB

[Mor92] David Morganstein. Book review: *An Introduction to Team Approach to Problem Solving* by Louis Jones; Ronald McBride. *Technometrics*, 34(1):103–104, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269564`.

Morgan:1993:BRB

[Mor93a] Carolyn Morgan. Book review: *Truncated and Censored Samples, Theory and Applications* by A. Clifford Cohen. *Technometrics*, 35(2):220–221, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269667`.

Morton:1993:BRB

[Mor93b] Michael J. Morton. Book review: *Statistical Methods in Applied Chemistry* by Jurand Czerminski; Andrzej Iwasiewicz; Zbigniew Paszek; Andrzej Sikorski. *Technometrics*, 35(2):228–229, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269678`.

Morris:1997:BRB

[Mor97a] Max D. Morris. Book review: *Cyclic and Computer Generated Designs* by J. A. John; E. R. Williams. *Technometrics*, 39(1):104, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270783`.

Morris:1997:ER

[Mor97b] Max D. Morris. Editor's report. *Technometrics*, 39(1):1–2, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270763`.

Morgan:1998:OCL

[Mor98a] J. P. Morgan. Orthogonal collections of Latin squares. *Technometrics*, 40(4):327–333, November 1998. CODEN TCMTA2.

ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270533.

Morris:1998:EA

[Mor98b] Max Morris. Editorial announcement. *Technometrics*, 40(1):1–2, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271387.

Morris:1998:ER

[Mor98c] Max D. Morris. Editor's report. *Technometrics*, 40(4):271–272, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270527.

Morgan:1999:BRB

[Mor99a] Walter T. Morgan. Book review: *SPC for Short Run Manufacturing* by Leonard A. Doty. *Technometrics*, 41(2):169, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270735.

Morganstein:1999:BRB

[Mor99b] David R. Morganstein. Book review: *Practical Sampling Techniques* by R. K. Som. *Technometrics*, 41(2):175, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270743.

Martz:1999:ETS

[MPR99] Harry F. Martz, Robert L. Parker, and Dale M. Rasmuson. Estimation of trends in the scram rate at nuclear power plants. *Technometrics*, 41(4):352–364, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271351.

Marr:1991:NTS

[MQ91] Ray L. Marr and C. P. Quesenberry. A NU test for serial correlation of residuals from one or more regression regimes. *Technometrics*, 33(4):441–457, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269416.

McDonald:1990:DAR

[MS90] Gary C. McDonald and William J. Studden. Design aspects of regression-based ratio estimation. *Technometrics*, 32(4):417–424, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270121.

Morris:1995:DAI

[MS95] M. D. Morris and A. D. Solomon. Design and analysis for an inverse problem arising from an advection-dispersion process. *Technometrics*, 37(3):293–302, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269913.

Meyer:1996:FDRa

[MSB96a] R. Daniel Meyer, David M. Steinberg, and George Box. Follow-up designs to resolve confounding in multifactor experiments. *Technometrics*, 38(4):303–313, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271297. See discussion [Fed96, JD96, Tob96] and reply [MSB96b].

Meyer:1996:FDRb

[MSB96b] R. Daniel Meyer, David S. Steinberg, and George Box. [Follow-Up Designs to Resolve Confounding in Multifactor Experiments]: Reply. *Technometrics*, 38(4):327–332, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271303. See [MSB96a].

Mudholkar:1995:EWF

[MSF95] Govind S. Mudholkar, Deo Kumar Srivastava, and Marshall Freimer. The exponentiated Weibull family: A reanalysis of the bus-motor-failure data. *Technometrics*, 37(4):436–445, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269735.

McKean:1994:RHB

[MSH94] Joseph W. McKean, Simon J. Sheather, and Thomas P. Hettmansperger. Robust and high-breakdown fits of polynomial models. *Technometrics*, 36(4):409–415, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269956.

McShane:1991:PLO

[MT91] Lisa M. McShane and Bruce W. Turnbull. Probability limits on outgoing quality for continuous sampling plans. *Technometrics*, 33(4):393–404, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269412.

Moskowitz:1992:BVA

[MT92] Herbert Moskowitz and Kwei Tang. Bayesian variables acceptance-sampling plans: Quadratic loss function and step-loss function. *Technometrics*, 34(3):340–347, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270040.

Meyer:1998:KCS

[MTV98] R. Daniel Meyer, Donald C. Trost, and Kimberly E. Vukovinsky. [Key Challenges for Statisticians in Business and Industry]: Discussion. *Technometrics*, 40(3):203–205, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271173. See [HH98a].

Mulekar:1997:BRB

[Mul97] Madhuri S. Mulekar. Book review: *Workshop Statistics, Discovery with Data* by Allan J. Rossman. *Technometrics*, 39(2):235–236, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270925.

Martz:1990:BRA

[MW90] H. F. Martz and R. A. Waller. Bayesian reliability analysis of complex series/parallel systems of binomial subsystems and components. *Technometrics*, 32(4):407–416, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270120.

Moorhead:1998:CDP

[MW98] P. R. Moorhead and C. F. J. Wu. Cost-driven parameter design. *Technometrics*, 40(2):111–119, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270645.

Myers:1991:BRB

[Mye91] Donald E. Myers. Book review: *Statistics for Geoscientists* by D. Marsal. *Technometrics*, 33(1):118, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269029.

Myers:1996:BRB

[Mye96] Donald E. Myers. Book review: *Multivariate Geostatistics* by Hans Wackernagel. *Technometrics*, 38(4):401–402, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271311.

Nair:1990:ER

[Nai90a] Vijay Nair. Editor's report. *Technometrics*, 32(4):369–370, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270113.

Nair:1990:CLA

[Nai90b] Vijayan N. Nair. [A Critical Look at Accumulation Analysis and Related Methods]: Discussion. *Technometrics*, 32(2):151–152, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268857. See [HW90b].

Nair:1991:ER

[Nai91a] Vijay Nair. Editor's report. *Technometrics*, 33(4):378–380, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269410.

Nair:1991:NE

[Nai91b] Vijay Nair. New Editor. *Technometrics*, 33(4):377, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269409.

Nair:1992:ER

[Nai92] Vijay Nair. Editor's report. *Technometrics*, 34(4):377, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268937.

Naik:1994:BRB

[Nai94] Dayanand N. Naik. Book review: *Applied Multivariate Data Analysis* by Brian S. Everitt; Graham Dunn. *Technometrics*, 36(2):214, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270233.

Naik:1996:BRB

[Nai96] Dayanand N. Naik. Book review: *Random Factors in ANOVA* by Sally Jackson; Dale E. Brashers. *Technometrics*, 38(2):187, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270421.

Nair:1992:TPD

[NAM+92] Vijayan N. Nair, Bovas Abraham, Jock MacKay, John A. Nelder, George Box, Madhav S. Phadke, Raghu N. Kacker, Jerome Sacks, William J. Welch, Thomas J. Lorenzen, Anne C. Shoemaker, Kwok L. Tsui, James M. Lucas, Shin Taguchi, Raymond H. Myers, G. Geoffrey Vining, and C. F. Jeff Wu. Taguchi's parameter design: A panel discussion. *Technometrics*, 34(2):127–161, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269231. Edited by Vijayan N. Nair.

Nandagopalan:1994:BRB

[Nan94] S. Nandagopalan. Book review: *Engineering Applications of Correlation and Spectral Analysis* by Julius S. Bendat; Allan G. Piersol. *Technometrics*, 36(2):220–221, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270240.

Narayanan:1993:BRB

[Nar93] A. Narayanan. Book review: *Probability and Statistics in Engineering and Management Science* by William W. Hines; Douglas C. Montgomery. *Technometrics*, 35(2):238–239, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269692.

Nayak:1998:BRB

[Nay98] Tapan K. Nayak. Book review: *Statistical Significance: Rationale, Validity and Utility* by Siu L. Chow. *Technometrics*, 40(2): 161–162, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270661.

Nelson:1993:AUA

[Nel93] Peter R. Nelson. Additional uses for the analysis of means and extended tables of critical values. *Technometrics*, 35(1):61–71, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269290`.

Nelson:1995:CLR

[Nel95] Wayne Nelson. Confidence limits for recurrence data: Applied to cost or number of product repairs. *Technometrics*, 37(2):147–157, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269616`.

Nelson:1998:BRB

[Nel98] Wayne Nelson. Book review: *Statistical Methods for Reliability Data* by William Q. Meeker; Luis A. Escobar. *Technometrics*, 40(3):255–256, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271181`.

Nemeth:1992:BRB

[Nem92] Margaret A. Nemeth. Book review: *Basic Statistics: Tools for Continuous Improvement* by Mark J. Kiemele; Stephen R. Schmidt. *Technometrics*, 34(2):231–232, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269249`.

Nemeth:1995:BRB

[Nem95] Margaret A. Nemeth. Book review: *Multivariate Pattern Recognition in Chemometrics, Illustrated by Case Studies (Data Handling in Science and Technology, Vol. 9)* by Richard G. Brereton. *Technometrics*, 37(1):116, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269162`.

Nemeth:1997:BRB

[Nem97] Margaret A. Nemeth. Book review: *Multivariate Statistical Methods: A Primer* by Bryan F. J. Manly. *Technometrics*, 39(4): 426–427, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271511`.

Nemeth:1998:KCS

[Nem98] Margaret A. Nemeth. [Key Challenges for Statisticians in Business and Industry]: Discussion. *Technometrics*, 40(3):206–207, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271174. See [HH98a].

Neubauer:1999:BRB

[Neu99] Dean V. Neubauer. Book review: *Success through Quality* by Timothy J. Clark. *Technometrics*, 41(4):375, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271365.

Neyer:1994:OBS

[Ney94] Barry T. Neyer. A *D*-optimality-based sensitivity test. *Technometrics*, 36(1):61–70, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269199.

Nguyen:1994:COB

[Ngu94] Nam-Ky Nguyen. Construction of optimal block designs by computer. *Technometrics*, 36(3):300–307, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269374.

Nguyen:1996:AAC

[Ngu96a] Nam-Ky Nguyen. An algorithmic approach to constructing supersaturated designs. *Technometrics*, 38(1):69–73, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268904.

Nguyen:1996:NCN

[Ngu96b] Nam-Ky Nguyen. A note on the construction of near-orthogonal arrays with mixed levels and economic run size. *Technometrics*, 38(3):279–283, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270612.

Niknian:1993:BRB

[Nik93] Minoo Niknian. Book review: *Randomization and Monte Carlo Methods in Biology* by Bryan F. J. Manly. *Technometrics*, 35 (1):96–97, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269308.

Niknian:1995:BRB

[Nik95] Minoo Niknian. Book review: *Permutation Tests: A Practical Guide to Resampling Methods for Testing Hypotheses* by Philip Good. *Technometrics*, 37(3):341–342, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269919.

Niple:1992:BRB

[Nip92] Edward R. Niple. Book review: *Linear Models for Multivariate, Time Series, and Spatial Data* by Ronald Christensen. *Technometrics*, 34(3):354–355, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270043.

Nelder:1998:JMM

[NLB+98] John A. Nelder, Youngjo Lee, Bo Bergman, Anders Hynén, A. Freek Huele, and Jan Engel. Joint modeling of mean and dispersion. *Technometrics*, 40(2):168–175, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270676.

Nomikos:1995:MSC

[NM95] Paul Nomikos and John F. MacGregor. Multivariate SPC charts for monitoring batch processes. *Technometrics*, 37(1):41–59, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269152.

Nychka:1996:NNA

[NO96] Douglas Nychka and Michael O'Connell. [Neural Networks in Applied Statistics]: Discussion. *Technometrics*, 38(3):218–220, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270603. See [Ste96a].

Notz:1992:BRBa

[Not92a] William I. Notz. Book review: *Continuous Bivariate Distributions Emphasising Applications* by T. P. Hutchinson; C. D. Lai. *Technometrics*, 34(2):236, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269256.

Notz:1992:BRBc

[Not92b] William I. Notz. Book review: *Exploratory and Multivariate Data Analysis* by Michel Jambu. *Technometrics*, 34(4):489–490, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268952.

Notz:1992:BRBb

[Not92c] William I. Notz. Book review: *The Engineering Statistician's Guide to Continuous Bivariate Distributions* by T. P. Hutchinson; C. D. Lai. *Technometrics*, 34(4):489, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268951.

Nayebpour:1993:ATL

[NW93] Mohamad R. Nayebpour and William H. Woodall. An analysis of Taguchi's on-line quality-monitoring procedures for attributes. *Technometrics*, 35(1):53–60, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269289.

ODonnell:1997:BRB

[O'D97] Robert O'Donnell. Book review: *Statistical Aspects of Quality Control* by Cyrus Derman; Sheldon M. Ross. *Technometrics*, 39(4):424, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271506.

ODonnell:1999:BRB

[O'D99] Robert O'Donnell. Book review: *Manufacturing Process Design and Optimization* by Robert F. Rhyder. *Technometrics*, 41(1):78–79, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271006.

Odeh:1990:TSP

[Ode90] Robert E. Odeh. Two-sided prediction intervals to contain at least k out of m future observations from a normal distribution. *Technometrics*, 32(2):203–216, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268864.

Oehlert:1994:IOC

[Oeh94] Gary W. Oehlert. Isolating one-cell interactions. *Technometrics*, 36(4):403–408, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269955.

Olin:1997:BRB

[Oli97] Bryan Olin. Book review: *Principles of Statistical Data Handling* by Fred Davidson. *Technometrics*, 39(2):235, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270924.

Olin:1998:BRB

[Oli98] Bryan Olin. Book review: *Design of Experiments in Quality Engineering* by J. T. Luftig; V. S. Jordan. *Technometrics*, 40(4): 350, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270537.

Olin:1996:ASMa

[OM96a] Bryan D. Olin and William Q. Meeker. Applications of statistical methods to nondestructive evaluation. *Technometrics*, 38(2): 95–112, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270399. See discussion [Ber96a, CR96, Spe96b, Swe96, Swe96, Tuc96] and reply [OM96b].

Olin:1996:ASMb

[OM96b] Bryan D. Olin and William Q. Meeker. [Applications of Statistical Methods to Nondestructive Evaluation]: Reply. *Technometrics*, 38(2):128–130, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270405. See [OM96a].

Oman:1991:RCM

[Oma91] Samuel D. Oman. Random calibration with many measurements: An application of Stein estimation. *Technometrics*, 33(2):187–195, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269045.

Ord:1996:BRB

[Ord96] Keith Ord. Book review: *Multivariate Tests for Time Series Models* by Jeff B. Cromwell; Michael J. Hannan; Walter C. Labys;

Michel Terraza. *Technometrics*, 38(2):187, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270422.

Osborne:1997:BRB

[Osb97] Deborah M. Osborne. Book review: *Modern Regression Methods* by Thomas P. Ryan. *Technometrics*, 39(4):426, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271509.

Otto:1990:BRB

[Ott90] Gordon H. Otto. Book review: *Statistical Models for Optimizing Mineral Exploration* by T. K. Wignall; J. de Geoffroy. *Technometrics*, 32(4):460–461, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270143.

Offodile:1993:ACS

[OUH93] O. Felix Offodile, Kingsley O. Ugwu, and Leslie Hayduk. Analysis of the causal structures linking process variables to robot repeatability and accuracy. *Technometrics*, 35(4):421–435, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270275.

Owen:1991:BRB

[Owe91] Christopher R. Owen. Book review: *SPC Tools for Operators* by John T. Burr. *Technometrics*, 33(1):116, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269025.

Owen:1996:BRB

[Owe96] Willis L. Owen. Book review: *Modelling Frequency and Count Data* by J. K. Lindsey. *Technometrics*, 38(3):290–291, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270619.

Pankratz:1992:BRB

[Pan92] Peter C. Pankratz. Book review: *Understanding Industrial Designed Experiments* by Steven R. Schmidt; Robert G. Launsby. *Technometrics*, 34(4):492, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268955.

Pankratz:1996:BRB

[Pan96] Peter C. Pankratz. Book review: *Using Statistics in Industry: Quality Improvement Through Total Process Control* by Gordon Betteley; Neville Metterick; Edward Sweeny; David Wilson. *Technometrics*, 38(1):81, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268913.

Pan:1999:IUL

[Pan99] Guohua Pan. The impact of unidentified location effects on dispersion-effects identification from unreplicated factorial designs. *Technometrics*, 41(4):313–326, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271348.

Papp:1995:BRB

[Pap95] Zoltan Papp. Book review: *Multi-Vari Chart and Analysis: A Pre-Experimentation Technique* by Mario Perez-Wilson. *Technometrics*, 37(1):121, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269170.

Papp:1996:BRB

[Pap96] Zoltan Papp. Book review: *Probabilistic Reliability Engineering* by Boris V. Gnedenko; Igor A. Ushakov; James A. Falk. *Technometrics*, 38(2):184–185, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270416.

Parmigiani:1992:BRB

[Par92] Giovanni Parmigiani. Book review: *Large Deviation Techniques in Decision, Simulation and Estimation* by James A. Bucklew. *Technometrics*, 34(1):120–121, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269587.

Patch:1991:BRB

[Pat91] Steven Patch. Book review: *Designing Experiments and Analyzing Data* by S. Maxwell; H. Delaney. *Technometrics*, 33(3):375–376, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268809.

Paul:1992:CBR

[PBR92] S. R. Paul, D. J. Best, and J. C. W. Rayner. Comment on Best and Rayner (1987). *Technometrics*, 34(2):249–250, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269277.

Palm:1995:STC

[PD95] Andrew C. Palm and Robert L. DeAmico. [Shewhart-Type Charts in Nonstandard Situations]: Discussion. *Technometrics*, 37(1):26–29, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269148. See [RD95a].

Phillips:1997:SIG

[PE97] Steven D. Phillips and Keith R. Eberhardt. [Statistical Issues in Geometric Feature Inspection Using Coordinate Measuring Machines]: Discussion. *Technometrics*, 39(1):22–24, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270767. See [DGTZ97a].

Pederson:1998:BRB

[Ped98] Shane P. Pederson. Book review: *Hidden Markov and Other Models for Discrete-Valued Time Series* by Iain L. MacDonald; Walter Zucchini. *Technometrics*, 40(3):263, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271194.

Pena:1991:MID

[Peñ91] Daniel Peña. Measuring influence in dynamic regression models. *Technometrics*, 33(1):93–101, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269010.

Percival:1992:BRB

[Per92] Donald B. Percival. Book review: *Statistical Spectral Analysis: A Nonprobabilistic Theory* by William A. Gardner. *Technometrics*, 34(1):109–110, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269574.

Perry:1997:BRB

[Per97] Robert L. Perry. Book review: *The Power of Statistical Thinking* by M. G. Leitnaker; R. D. Sanders; C. Hild. *Technometrics*, 39(1):108, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270790.

Percival:1998:BRB

[Per98] Donald B. Percival. Book review: *The Spectral Analysis of Time Series* by Lambert H. Koopmans. *Technometrics*, 40(4): 354, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270543.

Peterson:1993:GAR

[Pet93] John J. Peterson. A general approach to ridge analysis with confidence intervals. *Technometrics*, 35(2):204–214, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269665.

Peterson:1999:BRB

[Pet99] John J. Peterson. Book review: *Regression Analysis of Count Data* by A. Colin Cameron; Pravin K. Trivedi. *Technometrics*, 41 (4):371, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271358.

Paul:1991:GES

[PF91] S. R. Paul and Karen Y. Fung. A generalized extreme Studentized residual multiple-outlier-detection procedure in linear regression. *Technometrics*, 33(3):339–348, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268785. See comments [HSPF92].

Pfahler:1992:BRB

[Pfa92] Lori Pfahler. Book review: *The Deming Dimension* by H. R. Neave. *Technometrics*, 34(1):104, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269565.

Pfahler:1999:BRB

[Pfa99] Lori B. Pfahler. Book review: *Statistical Graphics for Visualizing Multivariate Data* by William G. Jacoby. *Technometrics*, 41(3):262, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270570.

Pham-Gia:1995:CWJ

[PGT95] T. Pham-Gia and N. Turkkan. Comment on Weerahandi and Johnson (1992). *Technometrics*, 37(1):130–131, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269186. See [WJ92].

Pebesma:1999:LHS

[PH99] Edzer J. Pebesma and Gerard B. M. Heuvelink. Latin hypercube sampling of Gaussian random fields. *Technometrics*, 41(4):303–312, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271347.

Piepel:1990:BRBb

[Pie90a] Gregory F. Piepel. Book review: *Empirical Model Building* by James R. Thompson. *Technometrics*, 32(3):353, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269128.

Piepel:1990:BRBa

[Pie90b] Gregory F. Piepel. Book review: *Quality Control, Robust Design, and the Taguchi Method* by Khosrow Dehnad. *Technometrics*, 32(2):221, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268868. See corrections [Ano90g].

Pigeon:1991:BRB

[Pig91] Joseph G. Pigeon. Book review: *Statistical Modeling: Applications in Contemporary Issues* by William S. Mallios. *Technometrics*, 33(3):375, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268808.

Pitts:1992:BRB

[Pit92] Karen A. Pitts. Book review: *A Guide to Graphical Problem-Solving Processes* by J. W. Moran; R. P. Talbot; R. M. Benson. *Technometrics*, 34(1):106, February 1992. CODEN TCMTA2.

ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269568`.

Pitts:1996:BRB

[Pit96] Karen A. Pitts. Book review: *Fundamentals Concepts in the Design of Experiments* by Charles R. Hicks. *Technometrics*, 38 (1):82–84, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268916`.

Pederson:1990:EMD

[PJ90] Shane P. Pederson and Mark E. Johnson. Estimating model discrepancy. *Technometrics*, 32(3):305–314, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269107`.

Placzkowski:1990:BRB

[Pla90] Gene Placzkowski. Book review: *In-Process Quality Control for Manufacturing* by William E. Barkman. *Technometrics*, 32(4): 458, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270139`.

Placzkowski:1996:BRB

[Pla96] Gene Placzkowski. Book review: *Reliability, Maintainability and Availability Assessment* by Mitchell O. Locks. *Technometrics*, 38 (3):288–289, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270617`.

Pascual:1999:EFC

[PM99] Francis G. Pascual and William Q. Meeker. Estimating fatigue curves with the random fatigue-limit model. *Technometrics*, 41 (4):277–290, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271342`. See discussion [Ann99, KK99, JFM99] and response [Ano99f].

Polsky:1993:BRB

[Pol93] Boris R. Polsky. Book review: *Statistical Methods for Testing, Development, and Manufacturing* by Forrest W. Breyfogle. *Technometrics*, 35(4):455–456, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270285`.

Porter:1993:BRB

[Por93] Donald R. Porter. Book review: *Introduction to Linear Regression Analysis* by Douglas C. Montgomery; Elizabeth A. Peck. *Technometrics*, 35(2):224–225, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269673.

Portier:1997:BRBb

[Por97a] Kenneth Portier. Book review: *Statistical Modelling in Hydrology* by Robin T. Clarke. *Technometrics*, 39(4):427–428, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271513.

Portier:1997:BRBa

[Por97b] Kenneth M. Portier. Book review: *Adaptive Sampling* by Steven K. Thompson; George A. F. Seber. *Technometrics*, 39(2):236, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270926.

Poston:1998:BRB

[Pos98] Wendy L. Poston. Book review: *Discrete Multivariate Distributions* by Norman L. Johnson; Samuel Kotz; N. Balakrishnan. *Technometrics*, 40(2):160–161, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270659.

Potter:1993:BRB

[Pot93] Randall W. Potter. Book review: *Confidence Intervals on Variance Components* by Richard K. Burdick; Franklin A. Graybill. *Technometrics*, 35(3):328, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269531.

Price:1993:BRB

[Pri93] Barbara Price. Book review: *A First Course in Factor Analysis* by Andrew L. Comrey; Howard B. Lee. *Technometrics*, 35 (4):453, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270282.

Price:1998:BRB

[Pri98] Barbara Price. Book review: *Robust Planning and Analysis of Experiments* by Christine H. Muller. *Technometrics*, 40(3):258, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271185.

Propst:1990:BRB

[Pro90] Annabeth Propst. Book review: *Quantitative Methods for Quality and Productivity Improvement* by Marilyn K. Hart; Robert F. Hart. *Technometrics*, 32(4):458–459, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270140.

Propst:1992:BRBb

[Pro92a] Annabeth Propst. Book reviews: *How to Apply Response Surface Methodology* by John A. Cornell; *How to Use Regression Analysis in Quality Control* by Douglas C. Crocker. *Technometrics*, 34(3):359, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270049.

Propst:1992:BRBa

[Pro92b] Annabeth L. Propst. Book review: *Designing for Quality, an Introduction to the Best of Taguchi and Western Methods of Statistical Experimental Design* by Robert H. Lochnar; Joseph E. Matar. *Technometrics*, 34(1):100, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269560.

Propst:1993:BRBa

[Pro93a] Annabeth L. Propst. Book review: *Statistical Problem Solving* by Hans J. Bajaria; Richard P. Copp. *Technometrics*, 35(2):234, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269686.

Propst:1993:BRBb

[Pro93b] Annabeth L. Propst. Book review: *The Deming Vision: SPC/TQM for Administrators* by Gary Fellers. *Technometrics*, 35(4):456–457, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270287.

Propst:1994:BRB

[Pro94] Annabeth L. Propst. Book review: *SPC Tools for Everyone* by John T. Burr. *Technometrics*, 36(3):322–323, August 1994. CO-

DEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269384.

Propst:1996:BRB

[Pro96] Annabeth L. Propst. Book review: *The New Economics: For Industry, Government, Education* by W. Edwards Deming. *Technometrics*, 38(3):294–295, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270625.

Qiu:1995:BRB

[Qiu95] Chunfu Qiu. Book review: *Nonparametric Regression and Generalized Linear Models: A Roughness Penalty Approach* by P. J. Green; B. W. Silverman. *Technometrics*, 37(3):342–343, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269920.

Qiu:1998:LPJ

[QY98] Peihua Qiu and Brian Yandell. A local polynomial jump-detection algorithm in nonparametric regression. *Technometrics*, 40(2):141–152, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270648.

Reynolds:1990:CCVa

[RAA90a] Marion R. Reynolds, Jr., Raid W. Amin, and Jesse C. Arnold. CUSUM charts with variable sampling intervals. *Technometrics*, 32(4):371–384, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270114. See discussion [Hea90, LS90a, Woo90] and response [RAA90b].

Reynolds:1990:CCVb

[RAA90b] Marion R. Reynolds, Jr., Raid W. Amin, and Jesse C. Arnold. [CUSUM Charts with Variable Sampling Intervals]: Response. *Technometrics*, 32(4):393–396, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270118.

Rabinowitz:1992:BRB

[Rab92] Larry Rabinowitz. Book review: *A Primer in Probability* by Kathleen Subrahmaniam. *Technometrics*, 34(3):369, August 1992. CO-

DEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270064.

Raghavachari:1991:BRB

[Rag91] Madabhushi Raghavachari. Book review: *Applied Probability and Stochastic Processes in Engineering and Physical Sciences* by Michael K. Ochi. *Technometrics*, 33(4):491, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269439.

Raghavachari:1993:BRB

[Rag93] M. Raghavachari. Book review: *Turbulence and Stochastic Processes: Kolmogorov's Ideas 50 Years on* by J. C. R. Hunt; O. M. Phillips; D. Williams. *Technometrics*, 35(3):330, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269534.

Raghavachari:1995:BRB

[Rag95] Madabhushi Raghavachari. Book review: *Monotone Structure in Discrete-Event Systems* by Paul Glasserman; David D. Yao. *Technometrics*, 37(4):467–468, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269754.

Raghavachari:1998:NOC

[Rag98] M. Raghavachari. A note on optimal component test plans for series system reliability with exponential failure times. *Technometrics*, 40(4):345–347, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270535.

Ramsey:1991:BRB

[Ram91] Philip Ramsey. Book review: *Process Quality Control: Troubleshooting and Interpretation of Data* by Ellis R. Ott; Edward G. Schilling. *Technometrics*, 33(3):359–360, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268791.

Ramsay:1993:BRB

[Ram93] Philip H. Ramsay. Book review: *Multivariate Density Estimation, Theory, Practice, and Visualization* by David W. Scott. *Technometrics*, 35(4):451–452, November 1993. CODEN TCMTA2.

ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270280`.

Ramsey:1994:BRB

[Ram94] Philip H. Ramsey. Book review: *Data Fitting in the Chemical Sciences* by Peter Gans. *Technometrics*, 36(4):430–431, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269973`.

Ramsey:1996:BRB

[Ram96] Philip H. Ramsey. Book review: *Statistical Methods in the Atmospheric Sciences* by Daniel S. Wilks. *Technometrics*, 38(4):402, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271312`.

Ramirez:1999:BRB

[Ram99] José G. Ramírez. Book review: *Understanding Design of Experiments: A Primer for Technologists* by R. J. del Vecchio. *Technometrics*, 41(3):265, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270575`.

Rao:1998:BRB

[Rao98] M. B. Rao. Book review: *Survival Analysis Techniques for Censored and Truncated Data* by John P. Klein; Melvin L. Moeschberger. *Technometrics*, 40(2):159–160, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270658`.

Rayens:1993:BRB

[Ray93] William S. Rayens. Book review: *Discriminant Analysis and Statistical Pattern Recognition* by Geoffrey J. McLachlan. *Technometrics*, 35(3):324–326, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269528`.

Razzaghi:1991:BRB

[Raz91] Mehdi Razzaghi. Book review: *Mixture Models* by Geoffrey J. McLachan; Kaye E. Basford. *Technometrics*, 33(3):365–366, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268796`.

Roes:1995:STCa

[RD95a] Kit C. B. Roes and Ronald J. M. M. Does. Shewhart-type charts in nonstandard situations. *Technometrics*, 37(1):15–24, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269146. See discussion [BC95, PD95, HD95, SWG95] and reply [RD95b].

Roes:1995:STCb

[RD95b] Kit C. B. Roes and Ronald J. M. M. Does. [Shewhart-Type Charts in Nonstandard Situations]: Reply. *Technometrics*, 37 (1):36–40, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269151. See [RD95a].

Read:1993:BRB

[Rea93] Sherry L. Read. Book review: *Managing for World-Class Quality: A Primer for Executives and Managers* by E. S. Shecter. *Technometrics*, 35(3):335–336, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269543.

Ruberg:1992:MCP

[RH92] Stephen J. Ruberg and Jason C. Hsu. Multiple comparison procedures for pooling batches in stability studies. *Technometrics*, 34(4):465–472, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268945.

Radson:1995:AFE

[RH95] Darrell Radson and Gary D. Herrin. Augmenting a factorial experiment when one factor is an uncontrollable random variable: A case study. *Technometrics*, 37(1):70–81, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269154.

Riedel:1994:BRBb

[Rie94a] Kurt S. Riedel. Book review: *Detection of Abrupt Changes: Theory and Application* by Michèle Basseville; Igor V. Nikiforov. *Technometrics*, 36(3):326–327, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269388.

Riedel:1994:BRBa

[Rie94b] Kurt S. Riedel. Book review: *Signal Processing and Its Applications (Handbook of Statistics 10)* by N. K. Bose; C. R. Rao. *Technometrics*, 36(3):325–326, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269387`.

Riedel:1997:BRB

[Rie97] Kurt S. Riedel. Book review: *Numerical Bayesian Methods Applied to Signal Processing* by Joseph J. K. O. Ruanaidh; William J. Fitzgerald. *Technometrics*, 39(1):106, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270786`.

Rigdon:1992:BRBb

[Rig92a] Steven E. Rigdon. Book review: *Mathematics in Chemistry: An Introduction to Modern Methods* by Harry G. Hecht. *Technometrics*, 34(2):239–240, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269260`.

Rigdon:1992:BRBa

[Rig92b] Steven E. Rigdon. Book review: *Reliability Statistics* by Robert A. Dovich. *Technometrics*, 34(1):118, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269584`.

Rigdon:1993:BRB

[Rig93] Steven E. Rigdon. Book review: *Introduction to Reliability Analysis: Probability Models and Statistical Methods* by Shelemyahu Zacks. *Technometrics*, 35(2):221, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269668`.

Rigdon:1999:BRB

[Rig99] Steven E. Rigdon. Book review: *Model-Oriented Design of Experiments* by Valerii V. Federov; Peter Hackl. *Technometrics*, 41(1):77–78, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271005`.

Rocke:1997:ODE

[RJ97] David M. Rocke and Geoffrey Jones. Optimal design for ELISA and other forms of immunoassay. *Technometrics*, 39(2):162–170, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270904.

Rocke:1995:TCM

[RL95] David M. Rocke and Stefan Lorenzato. A two-component model for measurement error in analytical chemistry. *Technometrics*, 37(2):176–184, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269619.

Rajgopal:1995:DCT

[RM95] Jayant Rajgopal and Mainak Mazumdar. Designing component test plans for series system reliability via mathematical programming. *Technometrics*, 37(2):195–212, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269621.

Rieck:1991:LLM

[RN91] James R. Rieck and Jerry R. Nedelman. A log-linear model for the Birnbaum–Saunders distribution. *Technometrics*, 33(1):51–60, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269007.

Robinson:1990:BRB

[Rob90] Jeffrey A. Robinson. Book review: *Probability and Statistics for Engineers and Scientists* by Ronald E. Walpole; Raymond H. Myers. *Technometrics*, 32(3):348–349, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269122.

Robinson:1998:EDD

[Rob98] Jeff Robinson. [Events Defined by Duration and Severity, with an Application to Network Reliability]: Discussion. *Technometrics*, 40(3):190, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271168. See [BCL98a].

Rocke:1993:BTF

[Roc93] David M. Rocke. On the beta transformation family. *Technometrics*, 35(1):72–81, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269291.

Roecker:1991:PEE

[Roe91] Ellen B. Roecker. Prediction error and its estimation for subset-selected models. *Technometrics*, 33(4):459–468, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269417.

Rohatgi:1991:BRB

[Roh91] Vijay K. Rohatgi. Book review: *Robustness of Statistical Tests* by Takeaki Kariya; Bimal K. Sinha. *Technometrics*, 33(2):246, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269062.

Rollins:1993:BRB

[Rol93] Derrick K. Rollins. Book review: *Fundamentals of Industrial Quality Control* by Lawrence Aft. *Technometrics*, 35(2):232–233, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269683.

Rosenbaum:1996:SUC

[Ros96] Paul R. Rosenbaum. Some useful compound dispersion experiments in quality design. *Technometrics*, 38(4):354–364, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271306.

Rosenbaum:1999:BCD

[Ros99] Paul R. Rosenbaum. Blocking in compound dispersion experiments. *Technometrics*, 41(2):125–134, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270728.

Rousseeuw:1995:DFC

[Rou95] Peter J. Rousseeuw. Discussion: Fuzzy clustering at the intersection. *Technometrics*, 37(3):283–286, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269911.

Rozum:1993:BRB

[Roz93] Michael A. Rozum. Book review: *Evaluation and Control of Measurements* by John Mandel. *Technometrics*, 35(2):223, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269671`.

Rukhin:1997:BRBa

[Ruk97a] Andrew L. Rukhin. Book review: *Bayes and Empirical Bayes Methods for Data Analysis* by Bradley P. Carlin; Thomas A. Louis. *Technometrics*, 39(3):337, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271144`.

Rukhin:1997:BRBb

[Ruk97b] Andrew L. Rukhin. Book review: *Tools for Statistical Inference* by Martin A. Tanner. *Technometrics*, 39(3):341, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271152`.

Rukhin:1998:BRB

[Ruk98] Andrew L. Rukhin. Book review: *Bayesian Methods for Finite Population Sampling* by Malay Ghosh; Glen Meeden. *Technometrics*, 40(3):262–263, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271193`.

Runger:1990:BRB

[Run90] George C. Runger. Book review: *Statistical Process Control in Automated Manufacturing* by J. B. Keats; N. F. Hubele. *Technometrics*, 32(3):341–342, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269113`.

Russell:1994:BRB

[Rus94] Edmund L. Russell III. Book review: *Statistics in the Environmental and Earth Sciences* by A. T. Walden; P. Guttorp. *Technometrics*, 36(4):431–432, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269974`.

Rutherford:1993:BRB

[Rut93] James A. Rutherford. Book review: *The Experimenter's Companion* by R. B. Clements. *Technometrics*, 35(1):94, February

1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269304.

Rutherford:1994:UCS

[Rut94] Brian M. Rutherford. [The Use of Conditional Simulation in Nuclear-Waste-Site Performance Assessment]: Discussion. *Technometrics*, 36(2):152–156, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270226. See [Got94c].

Rousseeuw:1999:FAM

[RvD99] Peter J. Rousseeuw and Katrien van Driessen. A fast algorithm for the minimum covariance determinant estimator. *Technometrics*, 41(3):212–223, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270566.

Ruppert:1997:LPV

[RWHH97] David Ruppert, M. P. Wand, Ulla Holst, and Ola Hössjer. Local polynomial variance-function estimation. *Technometrics*, 39(3):262–273, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271131.

Saccucci:1993:BRB

[Sac93] Michael S. Saccucci. Book review: *Engineering Quality and Experimental Design* by D. M. Groves; T. P. Davis. *Technometrics*, 35(4):454–455, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270284.

Sain:1996:BRB

[Sai96] Stephan R. Sain. Book review: *The Nature of Statistical Learning Theory* by V. N. Vapnik. *Technometrics*, 38(4):409, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271324.

Samaniego:1990:BRB

[Sam90] Francisco J. Samaniego. Book review: *Accelerated Life Testing and Experts' Opinions in Reliability* by C. A. Clarotti; D. V. Lindley. *Technometrics*, 32(2):233–234, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268884.

Samaniego:1999:BRBb

[Sam99a] Francisco J. Samaniego. Book review: *Reliability, Yield and Stress Burn-In: A Unified Approach for Microelectronics Systems Manufacturing and Software Development* by W. Kuo; W. T. K. Chien; T. Kim. *Technometrics*, 41(4):371–372, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271359.

Samaniego:1999:BRBa

[Sam99b] Francisco J. Samaniego. Book review: *The Practice of Bayesian Analysis* by S. French; J. Q. Smith. *Technometrics*, 41(1):73, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270997.

Sandry:1992:BRB

[San92] Thomas D. Sandry. Book review: *Nonlinear Estimation* by Gavin J. S. Ross. *Technometrics*, 34(3):356–357, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270045.

Sande:1998:BRB

[San98] Innis G. Sande. Book review: *Improving Your Measurement of Customer Satisfaction* by Terry G. Vavra. *Technometrics*, 40(3):264, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271195.

Sandry:1999:BRB

[San99] Thomas D. Sandry. Book review: *Practical Guide to Experimental Design* by Normand L. Frigon; David Mathews. *Technometrics*, 41(2):170–171, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270738.

Sarle:1990:BRB

[Sar90] Warren S. Sarle. Book review: *Algorithms for Clustering Data* by Anil K. Jain; Richard C. Dubes. *Technometrics*, 32(2):227–229, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268876.

Sartori:1993:BRB

[Sar93] David E. Sartori. Book review: *SPC Using Lotus 1–2–3* by Steven M. Zimmerman; Robert N. Zimmerman. *Technometrics*, 35(3): 336, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269544`.

Sartori:1994:BRBb

[Sar94a] Dave Sartori. Book review: *Elementary Statistics: A Step by Step Approach* by Allan G. Bluman. *Technometrics*, 36(4):427–428, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269968`.

Sartori:1994:BRBa

[Sar94b] Dave Sartori. Book review: *Statistical Quality Control with Microcomputer Applications* by Larry E. Shirland. *Technometrics*, 36(2):224–225, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270245`.

Sauter:1992:BRB

[Sau92] Roger M. Sauter. Book review: *Introduction to Statistical Quality Control* by Douglas C. Montgomery. *Technometrics*, 34(2): 232–233, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269251`.

Sauter:1994:BRB

[Sau94] Roger M. Sauter. Book review: *An Introduction to Statistics with Data Analysis* by Shelley Rasmussen. *Technometrics*, 36(1):118–119, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269214`.

Sauter:1997:BRB

[Sau97] Roger M. Sauter. Book review: *Fundamentals of Applied Statistics and Surveys* by David B. Orr. *Technometrics*, 39(1):106–107, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270787`.

Sauter:1998:BRB

[Sau98] Roger M. Sauter. Book review: *Introduction to the Statistical Analysis of Categorical Data* by Erling B. Andersen. *Technometrics*, 40(3):261–262, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271191`.

Shumway:1998:CSD

[SBD98] R. H. Shumway, D. R. Baumgardt, and Z. A. Der. A cepstral F statistic for detecting delay-fired seismic signals. *Technometrics*, 40(2):100–110, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270644`. See correction [Ano00].

Smith:1993:BDL

[SC93] Wendell F. Smith, Jr. and John A. Cornell. Biplot displays for looking at multiple response data in mixture experiments. *Technometrics*, 35(4):337–350, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270268`.

Sitter:1997:FRM

[SCF97] Randy R. Sitter, Jiahua Chen, and Moshe Feder. Fractional resolution and minimum aberration in blocked 2^{n-k} designs. *Technometrics*, 39(4):382–390, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271502`.

Schaefer:1991:BRB

[Sch91a] R. L. Schaefer. Book review: *Concise Statistics* by M. Godfrey; E. Roebuck; A. Sherlock. *Technometrics*, 33(1):112–113, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269019`.

Schiess:1991:BRB

[Sch91b] James R. Schiess. Book review: *From Data to Model* by Jan C. Willems. *Technometrics*, 33(4):489, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269436`.

Schmoyer:1991:NAT

[Sch91c] Richard L. Schmoyer. Nonparametric analyses for two-level single-stress accelerated life tests. *Technometrics*, 33(2):175–186, May

1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269044.

Schwarzmann:1991:CBL

[Sch91d] Bernd Schwarzmann. A connection between local-influence analysis and residual diagnostics. *Technometrics*, 33(1):103–104, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269011.

Schaefer:1992:BRB

[Sch92a] Robert L. Schaefer. Book review: *Subset Selection in Regression* by A. J. Miller. *Technometrics*, 34(2):229, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269244.

Schmoyer:1992:AVP

[Sch92b] Richard L. Schmoyer. Asymptotically valid prediction intervals for linear models. *Technometrics*, 34(4):399–408, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268939.

Schneider:1992:BRB

[Sch92c] Helmut Schneider. Book review: *Reliability Engineering Handbook (Vol. 1)* by Dimitri Kececioglu. *Technometrics*, 34(3):361–362, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270054.

Schuenemeyer:1992:BRB

[Sch92d] John H. Schuenemeyer. Book review: *Generalized Linear Models* by P. McCullagh; J. A. Nelder. *Technometrics*, 34(2):224, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269238.

Schneider:1993:BRB

[Sch93a] Helmut Schneider. Book review: *Reliability Engineering Handbook, Volume 2* by Dimitri Kececioglu. *Technometrics*, 35(1):94–95, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269305.

Schuenemeyer:1993:BRBb

[Sch93b] John H. Schuenemeyer. Book review: *Fundamentals of Exploratory Analysis of Variance* by David C. Hoaglin, Frederick

Mosteller, and John W. Tukey. *Technometrics*, 35(1):89, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269297.

Schuenemeyer:1993:BRBa

[Sch93c] John H. Schuenemeyer. Book review: *Fundamentals of Exploratory Analysis of Variance* by David C. Hoaglin; Frederick Mosteller; John W. Tukey. *Technometrics*, 35(1):89, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269297.

Schneider:1994:BRB

[Sch94a] Helmut Schneider. Book review: *Reliability Life Testing Handbook* by Dimitri Kececioglu. *Technometrics*, 36(1):111, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269204.

Schuenemeyer:1994:BRB

[Sch94b] John H. Schuenemeyer. Book review: *Introducing Quantitative Geography: Measurement, Methods and Generalised Linear Models* by Larry O'Brien. *Technometrics*, 36(1):114–115, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269208.

Schiferl:1995:BRB

[Sch95] Elizabeth A. Schiferl. Book review: *Efficiency in Research, Development and Production: The Statistical Design and Analysis of Chemical Experiments* by Leslie Davies. *Technometrics*, 37 (4):457–458, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269740.

Schaefer:1996:BRB

[Sch96a] Robert L. Schaefer. Book review: *An Introduction to Computational Statistics: Regression Analysis* by Robert I. Jennrich. *Technometrics*, 38(2):185–186, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270419.

Schneider:1996:BRB

[Sch96b] Helmut Schneider. Book review: *Failure Mode and Effect Analysis: FMEA from Theory to Execution* by D. H. Stamatis. *Techno-*

metrics, 38(1):80, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268911.

Schuenemeyer:1996:BRB

[Sch96c] John H. Schuenemeyer. Book review: *Geographical Data Analysis* by Nigel Walford. *Technometrics*, 38(2):188, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270424.

Schmee:1998:EDD

[Sch98a] Josef Schmee. [Events Defined by Duration and Severity, with an Application to Network Reliability]: Discussion. *Technometrics*, 40(3):191–192, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271169. See [BCL98a].

Schmid:1998:CZ

[Sch98b] Wolfgang Schmid. Comments on Zhang (1998). *Technometrics*, 40(4):362, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270559. See [Zha98].

Scott:1990:BRB

[Sco90] David W. Scott. Book review: *The New S Language* by R. A. Becker; J. M. Chambers; A. R. Wilks. *Technometrics*, 32(1):103–104, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269862.

Scott:1991:BRB

[Sco91] Del Scott. Book review: *Computations for the Analysis of Designed Experiments* by Richard Heiberger. *Technometrics*, 33(4):471–472, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269419.

Scott:1992:BRB

[Sco92] Douglas M. Scott. Book review: *Envisioning Information* by Edward R. Tufte. *Technometrics*, 34(1):106–107, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269569.

Schall:1990:IVL

[SD90] Robert Schall and Timothy T. Dunne. Influential variables in linear regression. *Technometrics*, 32(3):323–330, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269109.

Snee:1995:CDP

[SDP+95] Ronald D. Snee, N. R. Draper, P. Prescott, S. M. Lewis, A. M. Dean, P. W. M. John, and M. G. Tuck. Comments on Draper, Prescott, Lewis, Dean, John, and Tuck (1993): Understanding formulation systems. *Technometrics*, 37(1):131–132, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269187. See [DPL+93].

Sa:1993:MCC

[SE93] Ping Sa and Don Edwards. Multiple comparisons with a control in response surface methodology. *Technometrics*, 35(4):436–445, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270276.

Seaman:1990:BRB

[Sea90] John W. Seaman, Jr. Book review: *Introduction to the Theory of Coverage Processes* by Peter Hall. *Technometrics*, 32(2):237–238, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268888.

Seaman:1991:BRB

[Sea91] John W. Seaman, Jr. Book review: *Measurement Evaluation* by Andor Boros. *Technometrics*, 33(4):474–476, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269423.

Seaman:1993:BRB

[Sea93] John W. Seaman, Jr. Book review: *Sample Size Methodology* by M. M. Desu; D. Raghavarao. *Technometrics*, 35(1):95–96, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269307.

Seaman:1994:BRB

[Sea94] John W. Seaman, Jr. Book review: *Measurement and Calibration for Quality Assurance* by Alan S. Morris. *Technometrics*, 36(2):225–226, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270247.

Sengupta:1994:BRBb

[Sen94a] Sailes K. Sengupta. Book review: *Handbook for Digital Signal Processing* by Sanjit K. Mitra; James F. Kaiser. *Technometrics*, 36 (4):430, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269972.

Sengupta:1994:BRBa

[Sen94b] Sailes K. Sengupta. Book review: *Introduction to Applied Statistical Signal Analysis* by Richard Shiavi. *Technometrics*, 36(1): 113–114, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269207.

Sengupta:1995:BRB

[Sen95] Sailes K. Sengupta. Book review: *Fundamentals of Statistical Signal Processing: Estimation Theory* by Steven M. Kay. *Technometrics*, 37(4):465–466, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269750.

Sengupta:1997:BRB

[Sen97] Sailes K. Sengupta. Book review: *Introduction to Random Processes in Engineering* by A. V. Balakrishnan. *Technometrics*, 39 (2):230, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270916.

Sen:1998:ECR

[Sen98] Ananda Sen. Estimation of current reliability in a Duane-based reliability growth model. *Technometrics*, 40(4):334–344, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270534. See correction [Sen99b].

Sen:1999:BRB

[Sen99a] Ananda Sen. Book review: *The Theory of Dispersion Models* by Bent Jørgensen. *Technometrics*, 41(2):177–178, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270747.

Sen:1999:CEC

[Sen99b] Ananda Sen. Correction: “Estimation of current reliability in a Duane-based reliability growth model” [*Technometrics* **40** (1998), no. 4, 334–344; Sen:1998:ECR (99h:62126)]. *Technometrics*, 41 (4):385, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271384`. See [Sen98].

Stephenson:1999:BRB

[SG99] Hal W. Stephenson and Ned M. Gibbons. Book review: *Business Process Improvement Toolbox* by Bjørn Andersen. *Technometrics*, 41(4):374–375, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271364`.

Steiner:1996:GDS

[SGW96] Stefan H. Steiner, P. Lee Geyer, and George O. Wesolowsky. Grouped data-sequential probability ratio tests and cumulative sum control charts. *Technometrics*, 38(3):230–237, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270606`.

Shanmugam:1992:BRB

[Sha92] Ramalingam Shanmugam. Book review: *Assurance Technologies: Principles and Practices* by Dev G. Raheja. *Technometrics*, 34 (2):233–234, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269252`.

Shanmugam:1993:BRB

[Sha93] Ramalingam Shanmugam. Book review: *Statistical Methods in Reliability Theory and Practice* by Brian D. Bunday. *Technometrics*, 35(1):95, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269306`.

Shanmugam:1995:BRB

[Sha95] Ramalingam Shanmugam. Book review: *Multivariate AnalysisPart 1: Distributions, Ordination and Inference* by W. J. Krzanowski; F. H. C. Marriott. *Technometrics*, 37(3):351, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269930`.

Shanmugam:1997:BRBc

[Sha97a] Ramalingam Shanmugam. Book review: *Distributions in the Physical and Engineering Sciences* by Alexander I. Saichev; Wojbor A. Woyczynski. *Technometrics*, 39(4):431, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271519.

Shanmugam:1997:BRBb

[Sha97b] Ramalingam Shanmugam. Book review: *Introduction to Time Series and Forecasting* by Peter J. Brockwell; Richard A. Davis. *Technometrics*, 39(4):426, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271510.

Shanmugam:1997:BRBa

[Sha97c] Ramalingam Shanmugam. Book review: *Multivariate Analysis,Part 2: Classification, Covariance Structures, and Repeated Measurements* by W. J. Krzanowski; F. H. C. Marriott. *Technometrics*, 39(1):101, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270779.

Shanmugam:1998:BRB

[Sha98] Ram Shanmugam. Book review: *Parametric Statistical Inference* by J. K. Lindsey. *Technometrics*, 40(2):161, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270660.

Shea:1990:BRB

[She90a] Gerald Shea. Book review: *Quality Control Systems* by James R. Taylor. *Technometrics*, 32(2):221–222, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268869.

Sheesley:1990:BRB

[She90b] John H. Sheesley. Book review: *Quality Engineering in Production Systems* by G. Taguchi; E. Elsayed; T. Hsiang. *Technometrics*, 32 (4):457–458, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270138.

Shoemaker:1990:BRB

[Sho90] Lewis H. Shoemaker. Book review: *Order Restricted Statistical Inference* by Tim Robertson; F. T. Wright; R. L. Dykstra. *Technometrics*, 32(1):111–112, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269870.

Simonoff:1988:DOC

[Sim88] Jeffrey S. Simonoff. Detecting outlying cells in two-way contingency tables via backwards-stepping. *Technometrics*, 30(3):339–345, August 1988. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270088. See correction [Ano90e].

Simpson:1991:BRB

[Sim91] Douglas G. Simpson. Book review: *The Statistical Analysis of Discrete Data* by Thomas J. Santner; Diane E. Duffy. *Technometrics*, 33(2):242, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269057.

Simonson:1997:BRB

[Sim97] Katherine Hansen Simonson. Book review: *Pattern Classification: A Unified View of Statistical and Neural Approaches* by Jurgen Schürmann. *Technometrics*, 39(1):102, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270780.

Singh:1983:LRT

[Sin83] N. Singh. The likelihood ratio test for the equality of location parameters of $k(\geq 2)$ exponential populations based on Type II censored samples. *Technometrics*, 25(2):193–195, May 1983. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268553. See correction [Sin92].

Singh:1990:BRBa

[Sin90a] Ashok K. Singh. Book review: *Properties of Estimators for the Gamma Distribution* by K. O. Bowman; L. R. Shenton. *Technometrics*, 32(1):102–103, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269861.

Singh:1990:BRBb

[Sin90b] Ashok K. Singh. Book review: *Quality Control and Reliability (Handbook of Statistics, Vol. 7)* by P. R. Krishnaiah; C. R. Rao. *Technometrics*, 32(3):344, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269116.

Singh:1992:CLR

[Sin92] N. Singh. Correction to: "The likelihood ratio test for the equality of location parameters of k (≥ 2) exponential populations based on Type II censored samples" [*Technometrics* **25** (1983), no. 2, 193–195; MR0702171 (84g:62031)]. *Technometrics*, 34(4):502, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268969. See [Sin83].

Singh:1997:BRB

[Sin97] A. K. Singh. Book review: *The Exponential Distribution: Theory, Methods and Applications* by N. Balakrishnan; A. P. Basu. *Technometrics*, 39(3):341, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271151.

Singh:1998:BRB

[Sin98] Anita Singh. Book review: *Astrostatistics* by G. J. Babu; E. D. Feigelson. *Technometrics*, 40(1):76–77, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271400.

Smiley:1991:BRB

[Smi91] Richard A. Smiley. Book review: *Beating Your Competition Through Quality* by D. B. Owen. *Technometrics*, 33(1):116–117, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269026.

Smith:1993:BRB

[Smi93] Patricia L. Smith. Book review: *Chemometrics: Applications of Mathematics and Statistics to Laboratory Systems* by Richard G. Brereton. *Technometrics*, 35(3):330–331, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269535.

Spall:1995:BRB

[SN95] James C. Spall and J. Barry Nelson. Book review: *Numerical Methods for Stochastic Processes* by Nicolas Bouleau; Dominique Lepingle. *Technometrics*, 37(2):236–237, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269637.

Snee:1990:CPN

[Sne90] Ronald D. Snee. Commentary: A partnership is needed. *Technometrics*, 32(3):267–269, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269101. See [HK90].

Snee:1998:DIV

[Sne98] Ronald D. Snee. Discussion: Increasing the value of the statistics profession. *Technometrics*, 40(3):207–210, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271175.

Soyer:1995:BRB

[Soy95] Refik Soyer. Book review: *Ensuring Software Reliability* by Ann M. Neufelder. *Technometrics*, 37(1):122–123, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269172.

Sweeting:1995:ANA

[SP95] Trevor J. Sweeting and Michael J. Phillips. An application of nonstandard asymptotics to the analysis of repairable-systems data. *Technometrics*, 37(4):428–435, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269734.

Spagon:1999:BRB

[Spa99] Patrick D. Spagon. Book review: *Statistical Quality Assurance Methods for Engineers* by Stephen B. Vardeman; J. Marcus Jobe. *Technometrics*, 41(4):372–373, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271360.

Spencer:1991:BRB

[Spe91] Floyd W. Spencer. Book review: *Statistical Methods in Accelerated Life Testing* by Reinhard Viertl. *Technometrics*, 33(3):360–362, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print),

1537-2723 (electronic). URL http://www.jstor.org/stable/1268792.

Speck:1996:BRB

[Spe96a] Daniel Speck. Book review: *Quality Engineering Bible* by Thomas Pyzdek. *Technometrics*, 38(4):407–408, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271321.

Spencer:1996:ASM

[Spe96b] Floyd W. Spencer. [Applications of Statistical Methods to Nondestructive Evaluation]: Discussion. *Technometrics*, 38(2):122–124, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270402. See [OM96a].

Sposito:1990:BRB

[Spo90] Vince A. Sposito. Book review: *Nonlinear L_p-Norm Estimation* by René Gonin; Arthur H. Money. *Technometrics*, 32(4):450–451, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270127.

Spring:1991:BRB

[Spr91] Raymond V. Spring. Book review: *Exploring Operations Research and Statistics in the Micro Lab* by Erwin Kalvelagen; Henk C. Tijms. *Technometrics*, 33(1):120, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269033.

Spurrier:1992:ODC

[Spu92] John D. Spurrier. Optimal designs for comparing the variances of several treatments with that of a standard treatment. *Technometrics*, 34(3):332–339, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270039.

Spurrier:1993:CSC

[Spu93] John D. Spurrier. Comparison of simultaneous confidence bands for quadratic regression over a finite interval. *Technometrics*, 35(3):315–320, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269524.

Srinivasan:1992:BRB

[Sri92] Syamala Srinivasan. Book review: *Design and Analysis of Experiments* by Douglas C. Montgomery. *Technometrics*, 34(2):230, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269246.

Srinivasan:1993:BRB

[Sri93] Cidambi Srinivasan. Book review: *Combining Information: Statistical Issues and Opportunities for Research* by National Research Council. *Technometrics*, 35(4):462–463, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270296.

Srivastava:1989:SDA

[SS89] V. K. Srivastava and N. Singh. Small-disturbance asymptotic theory for linear-calibration estimators. *Technometrics*, 31(3):373–378, August 1989. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/3556147. See correction [Ano90f].

Song:1997:VCT

[SS97] Ruiguang Song and Stanley A. Shulman. Variance components in the two-way nested model with incomplete nesting information. *Technometrics*, 39(1):71–80, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270774.

Schneider:1990:APT

[ST90a] Helmut Schneider and Kwei Tang. Adaptive procedures for the two-stage group-testing problem based on prior distributions and costs. *Technometrics*, 32(4):397–405, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270119.

Spurrier:1990:CCD

[ST90b] John D. Spurrier and L. A. Thombs. Control charts for detecting cyclical behavior. *Technometrics*, 32(2):163–171, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268860.

StLaurent:1994:BRU

[St.94] Roy T. St. Laurent. Book review: *Understanding Regression Assumptions* by William D. Berry. *Technometrics*, 36(3):321, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269382.

Saltelli:1999:QMI

[STC99] A. Saltelli, S. Tarantola, and K. P.-S. Chan. A quantitative model-independent method for global sensitivity analysis of model output. *Technometrics*, 41(1):39–56, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270993.

Stein:1987:LSP

[Ste87] Michael Stein. Large sample properties of simulations using Latin hypercube sampling. *Technometrics*, 29(2):143–151, May 1987. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269769. See correction [Ste90b].

Stein:1990:BRB

[Ste90a] Michael Stein. Book review: *Estimating and Choosing* by G. Matheron; A. M. Hasofer. *Technometrics*, 32(3):358–359, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269136.

Stein:1990:CLS

[Ste90b] Michael Stein. Correction: "Large sample properties of simulations using Latin hypercube sampling" [*Technometrics* **29** (1987), no. 2, 143–151; MR0887702 (88e:62055)]. *Technometrics*, 32(3): 367, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269142. See [Ste87].

Stephenson:1990:BRB

[Ste90c] W. R. Stephenson. Book review: *Distribution Free Tests* by H. R. Neave; P. L. Worthington. *Technometrics*, 32(4):454–455, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270133.

Stein:1991:BRB

[Ste91] Michael Stein. Book review: *The Analysis of Directional Time Series: Applications to Wind Speed and Direction* by J. Breckling. *Technometrics*, 33(4):485–486, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269431.

Stern:1996:NNAa

[Ste96a] Hal S. Stern. Neural networks in applied statistics. *Technometrics*, 38(3):205–214, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270601. See discussion [dVU96, NO96] and reply [Ste96b].

Stern:1996:NNAb

[Ste96b] Hal S. Stern. [Neural Networks in Applied Statistics]: Reply. *Technometrics*, 38(3):220, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270604. See [Ste96a].

Stephenson:1998:BRB

[Ste98] W. Robert Stephenson. Book review: *Applied Statistics: A First Course in Inference* by F. A. Graybill; H. K. Iyer; R. K. Burdick. *Technometrics*, 40(4):352–353, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270540.

Stewart:1999:BRB

[Ste99] Paul Stewart. Book review: *Linear Mixed Models in Practice: A SAS-Oriented Approach (Lecture Notes in Statistics 126)* by Geert Verbeke; Geert Molenberghs. *Technometrics*, 41(1):79–80, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271007.

Stine:1997:BRB

[Sti97] Robert A. Stine. Book review: *Analysis of Observed Chaotic Data* by Henry D. I. Abarbanel. *Technometrics*, 39(3):334–335, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271140.

Stone:1992:BRB

[Sto92] Ricardo R. Stone. Book review: *Machine/Process Capability Study: A Five Stage Methodology for Optimizing Manufacturing Processes* by Mario Perez-Wilson. *Technometrics*, 34(2):232, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269250`.

Stokes:1996:BRB

[Sto96] S. Lynne Stokes. Book review: *How to Perform Continuous Sampling* by Kenneth S. Stephens. *Technometrics*, 38(1):82, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268914`.

Stromberg:1996:BRB

[Str96] Arnold J. Stromberg. Book review: *Number-Theoretic Methods in Statistics* by K.-T. Fang; Y. Wang. *Technometrics*, 38(2):189–190, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270426`.

Seaver:1999:IIS

[STR99] Bill Seaver, Konstantinos Triantis, and Chip Reeves. The identification of influential subsets in regression using a fuzzy clustering strategy. *Technometrics*, 41(4):340–351, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271350`.

Stufken:1994:BRB

[Stu94] John Stufken. Book review: *Taguchi Methods: A Hands-On Approach* by Glen Stuart Peace. *Technometrics*, 36(1):121–122, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269218`.

Shoemaker:1991:EEM

[STW91] Anne C. Shoemaker, Kwok-Leung Tsui, and C. F. Jeff Wu. Economical experimentation methods for robust design. *Technometrics*, 33(4):415–427, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269414`.

Steiner:1995:ECB

[SW95] S. H. Steiner and G. O. Wesolowsky. Estimating the correlation between destructively measured variables using proof-loading.

Technometrics, 37(1):94–101, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269156.

Sun:1997:OBS

[SWC97] Don X. Sun, C. F. Jeff Wu, and Youyi Chen. Optimal blocking schemes for 2^n and 2^{n-p} designs. *Technometrics*, 39(3):298–307, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271134.

Sweeting:1996:ASM

[Swe96] Trevor J. Sweeting. [Applications of Statistical Methods to Nondestructive Evaluation]: Discussion. *Technometrics*, 38(2):124–126, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270403. See [OM96a].

Sullivan:1995:STC

[SWG95] Joe H. Sullivan, William H. Woodall, and Martha M. Gardner. [Shewhart-Type Charts in Nonstandard Situations]: Discussion. *Technometrics*, 37(1):31–35, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269150. See [RD95a].

Syski:1999:BRB

[Sys99] R. Syski. Book review: *Fundamentals of Queueing Theory* by D. Gross; C. M. Harris. *Technometrics*, 41(1):76–77, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271003.

Taam:1991:BRB

[Taa91] Winson Taam. Book review: *Nonlinear System Analysis and Identification from Random Data* by Julius S. Bendat. *Technometrics*, 33(4):482–483, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269429.

Taam:1999:BRB

[Taa99] Winson Taam. Book review: *Introduction to Probability and Statistics for Scientists and Engineers* by Walter A. Rosenkrantz. *Technometrics*, 41(4):373, November 1999. CODEN TCMTA2.

ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271362.

Tamhane:1996:BRB

[Tam96] Ajit C. Tamhane. Book review: *Design and Analysis of Experiments for Statistical Selection, Screening and Multiple Comparisons* by Robert E. Bechhofer; Thomas J. Santner; David M. Goldsman. *Technometrics*, 38(3):289–290, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270618.

Tang:1993:BRB

[Tan93] Kwei Tang. Book review: *Guide to Acceptance Sampling* by Wayne A. Taylor. *Technometrics*, 35(4):458, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270289.

Tanaydin:1998:BRB

[Tan98] Suat Tanaydin. Book review: *Robust Design and Analysis for Quality Engineering* by Sung H. Park. *Technometrics*, 40(4):349, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270536.

Tatum:1996:CCD

[Tat96] Lawrence G. Tatum. Control charts for the detection of a periodic component. *Technometrics*, 38(2):152–160, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270408.

Tatum:1997:REP

[Tat97] Lawrence G. Tatum. Robust estimation of the process standard deviation for control charts. *Technometrics*, 39(2):127–141, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270901.

Thomas:1990:AIP

[TC90] William Thomas and R. Dennis Cook. Assessing influence on predictions from generalized linear models. *Technometrics*, 32(1):59–65, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269845.

Terrell:1992:BRB

[Ter92] George R. Terrell. Book review: *Influence Diagrams, Belief Nets, and Decision Analysis* by R. Oliver; J. Smith. *Technometrics*, 34(1):114–115, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269579.

Tucker:1993:ASP

[TFV93] William T. Tucker, Frederick W. Faltin, and Scott A. Vander Wiel. Algorithmic statistical process control: An elaboration. *Technometrics*, 35(4):363–375, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270270.

Taam:1993:DSE

[TH93] Winson Taam and Michael Hamada. Detecting spatial effects from factorial experiments: An application from integrated-circuit manufacturing. *Technometrics*, 35(2):149–160, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269660.

Thisted:1991:BRB

[Thi91] Ronald A. Thisted. Book review: *Linear Least Squares Computations* by R. W. Farebrother. *Technometrics*, 33(3):368–369, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268800.

Thomas:1990:BRB

[Tho90a] Edward V. Thomas. Book review: *Advanced Scientific Computing in BASIC with Applications in Chemistry, Biology, and Pharmacology* by P. Valkó; S. Vajda. *Technometrics*, 32(4):464–465, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270149.

Thompson:1990:BRB

[Tho90b] Carol B. Thompson. Book review: *Introductory Statistical Methods: An Integrated Approach Using Minitab* by Richard A. Groeneveld. *Technometrics*, 32(3):348, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269121.

Thomas:1991:EVE

[Tho91] Edward V. Thomas. Errors-in-variables estimation in multivariate calibration. *Technometrics*, 33(4):405–413, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269413`. See correction [Tho92a].

Thomas:1992:CEV

[Tho92a] Edward V. Thomas. Correction: "Errors-in-Variables Estimation in Multivariate Calibration". *Technometrics*, 34(3):372, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270074`. See [Tho91].

Thomson:1992:BRB

[Tho92b] Steve Thomson. Book review: *How SAS Works* by Paul Herzberg. *Technometrics*, 34(1):117, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269582`.

Thomas:1993:BRB

[Tho93] Edward V. Thomas. Book review: *Modelling Binary Data* by D. Collett. *Technometrics*, 35(2):224, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269672`.

Thomas:1994:EIS

[Tho94] Edward V. Thomas. Evaluating the ignition sensitivity of thermal-battery heat pellets. *Technometrics*, 36(3):273–282, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269371`.

Thode:1999:BRB

[Tho99] Henry C. Thode, Jr. Book review: *Applied Probability for Engineers and Scientists* by Ephraim Suhir. *Technometrics*, 41(1):76, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271002`.

Tan:1999:MMC

[TI99] Charles Y. Tan and Boris Iglewicz. Measurement-methods comparisons and linear statistical relationship. *Technometrics*, 41

(3):192–201, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270564.

Timm:1995:BRB

[Tim95] Neil H. Timm. Book review: *Elements of Multivariate Time Series Analysis* by Gregory C. Reinsel. *Technometrics*, 37(1):118, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269165.

Timm:1996:BRB

[Tim96] Neil H. Timm. Book review: *Nonlinear Models for Repeated Measurement Data* by Marie Davidian; David M. Giltinan. *Technometrics*, 38(2):186–187, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270420.

Timm:1999:BRB

[Tim99] Neil H. Timm. Book review: *Multivariate Reduced-Rank Regression* by Gregory C. Reinsel; Raja P. Velu. *Technometrics*, 41 (4):369–370, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271356.

Tobias:1996:FDR

[Tob96] Randall D. Tobias. [Follow-Up Designs to Resolve Confounding in Multifactor Experiments]: Discussion. *Technometrics*, 38(4): 326–327, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271302. See [MSB96a].

Tobias:1999:BRB

[Tob99] Randall D. Tobias. Book review: *Chemometrics: A Practical Guide* by Kenneth R. Beebe; Randy J. Pell; Mary Beth Seasholtz. *Technometrics*, 41(4):375–376, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271366.

Toman:1995:BRB

[Tom95] Blaza Toman. Book review: *Design and Analysis of Experiments, Volume 1: Introduction to Experimental Design* by Klaus Hinkelman; Oscar Kempthorne. *Technometrics*, 37(3):348–349, August

1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269927.

Toran:1994:UCS

[Tor94] Laura Toran. [The Use of Conditional Simulation in Nuclear-Waste-Site Performance Assessment]: Discussion. *Technometrics*, 36(2):150–152, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270225. See [Got94c].

Tortorella:1995:BRB

[Tor95] Michael Tortorella. Book review: *Evaluating Control Systems Reliability: Techniques and Applications* by William M. Goble. *Technometrics*, 37(3):344–345, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269922.

Tortorella:1999:BRB

[Tor99] Michael Tortorella. Book review: *Advances in Stochastic Models for Reliability, Quality and Safety* by Waltraud Kahle; Elart von Collaní; Jurgen Franz; Uwe Jensen. *Technometrics*, 41(3):268–269, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270581.

Tribus:1990:CCB

[Tri90] Myron Tribus. Commentary: [Communications between Statisticians and Engineers/Physical Scientists]. *Technometrics*, 32(3):271–272, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269102. See [HK90].

Trosset:1997:BRB

[Tro97] Michael W. Trosset. Book review: *Biplots* by J. C. Gower; D. J. Hand. *Technometrics*, 39(3):339–340, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271148.

Tsai:1991:BRB

[Tsa91] Chih-Ling Tsai. Book review: *Analysis of Means in Some Non-Standard Situations* by J. B. Dijkstra. *Technometrics*, 33(1):115–116, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print),

1537-2723 (electronic). URL http://www.jstor.org/stable/1269024.

Tsokos:1992:BRB

[Tso92] Chris P. Tsokos. Book review: *Time Series: A Biostatistical Introduction* by Peter J. Diggle. *Technometrics*, 34(2):229–230, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269245.

Tucker:1992:SPM

[Tuc92] William T. Tucker. [Statistical Process Monitoring and Feedback Adjustment]: Discussion. *Technometrics*, 34(3):275–277, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270031. See [BK92a].

Tucker:1996:ASM

[Tuc96] William T. Tucker. [Applications of Statistical Methods to Nondestructive Evaluation]: Discussion. *Technometrics*, 38(2):126–127, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270404. See [OM96a].

Ture:1994:ORC

[Tür94] Tahsin Erkan Türe. Optimal row-column designs for multiple comparisons with a control: A complete catalog. *Technometrics*, 36 (3):292–299, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269373.

Tsai:1990:DTW

[TW90] Chih-Ling Tsai and Xizhi Wu. Diagnostics in transformation and weighted regression. *Technometrics*, 32(3):315–322, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269108.

Tsai:1992:TMD

[TW92] Chih-Ling Tsai and Xizhi Wu. Transformation-model diagnostics. *Technometrics*, 34(2):197–202, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269235.

Thomas:1996:SEE

[TW96] James P. Thomas and Robert P. Wei. Standard-error estimates for rates of change from indirect measurements. *Technometrics*, 38(1):59–68, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268903.

Tsung:1998:ERD

[TWN98] Fugee Tsung, Huaiqing Wu, and Vijayan N. Nair. On the efficiency and robustness of discrete proportional-integral control schemes. *Technometrics*, 40(3):214–222, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271177.

Umble:1999:DFB

[USM99] Elisabeth J. Umble, John W. Seaman, Jr., and Harry F. Martz. A distribution-free Bayesian approach for determining the joint probability of failure of materials subject to multiple proof loads. *Technometrics*, 41(3):183–191, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270563.

Vangel:1991:BRB

[Van91] Mark G. Vangel. Book review: *Continuous Mining Reliability: Design and Operation of Mechanized Systems* by Vladimir Pavlovic. *Technometrics*, 33(2):241, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269054.

VanBrackle:1992:BRB

[Van92a] Lewis N. VanBrackle. Book review: *Probability for Applications* by Paul Pfeiffer. *Technometrics*, 34(1):119–120, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269586.

Vangel:1992:NMO

[Van92b] Mark G. Vangel. New methods for one-sided tolerance limits for a one-way balanced random-effects ANOVA model. *Technometrics*, 34(2):176–185, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269233.

VanderWiel:1996:MPW

[Van96a] S. A. Vander Wiel. Monitoring processes that wander using integrated moving average models. *Technometrics*, 38(2):139–151, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270407.

Vangel:1996:BRB

[Van96b] Mark G. Vangel. Book review: *System Reliability Theory: Models and Statistical Methods* by Arnljot Høyland; Marvin Rausand. *Technometrics*, 38(1):79–80, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268910.

Vangel:1999:SNP

[Van99] Mark G. Vangel. [Simultaneous Nonparametric Prediction Limits]: Discussion. *Technometrics*, 41(2):108, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270725. See [DM99a].

Vardeman:1994:ER

[Var94a] Stephen B. Vardeman. Editor's report. *Technometrics*, 36(1):1–2, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269190.

Vardeman:1994:NE

[Var94b] Steve Vardeman. New Editor. *Technometrics*, 36(4):337, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269948.

Velilla:1994:DRU

[VB94a] Santiago Velilla and Juan A. Barrio. A discriminant rule under transformation. *Technometrics*, 36(4):348–353, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269950.

Viveros:1994:IEP

[VB94b] Román Viveros and N. Balakrishnan. Interval estimation of parameters of life from progressively censored data. *Technometrics*, 36(1):84–91, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269201.

Voss:1994:SIP

[VD94] Daniel T. Voss and Steven DeMartino. Spatial interpolation for photographic reproduction of color. *Technometrics*, 36(3):249–259, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269369`.

vanderVoet:1997:PMR

[vdVtBM97] Hilko van der Voet, Cajo J. F. ter Braak, and Colin Mallows. C_P and prediction with many regressors: Comments on Mallows (1995). *Technometrics*, 39(1):115–116, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270805`.

Verducci:1990:BRB

[Ver90] Joseph S. Verducci. Book review: *Topics in Applied Multivariate Analysis* by D. M. Hawkins. *Technometrics*, 32(1):99–100, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269857`.

Vining:1992:BRB

[Vin92] Geoff Vining. Book review: *Data Analysis: A Model-Comparison Approach* by Charles M. Judd; Gary H. McClelland. *Technometrics*, 34(1):107–108, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269570`.

Viveros:1991:CSS

[Viv91] R. Viveros. Combining series system data to estimate component characteristics. *Technometrics*, 33(1):13–23, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269004`.

Vining:1991:GAE

[VM91] G. Geoffrey Vining and Raymond H. Myers. A graphical approach for evaluating response surface designs in terms of the mean squared error of prediction. *Technometrics*, 33(3):315–326, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268783`.

vanNostrand:1990:BRB

[vN90] R. Craig van Nostrand. Book review: *Applied Regression Analysis: A Research Tool* by John O. Rawlings. *Technometrics*, 32

(1):95–96, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269851.

Voelkel:1994:BRB

[Voe94] Joseph O. Voelkel. Book review: *Understanding Variation: The Key to Managing Chaos* by D. Wheeler. *Technometrics*, 36(2):225, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270246.

Venter:1996:HTA

[VS96] J. H. Venter and S. J. Steel. A hypothesis-testing approach toward identifying active contrasts. *Technometrics*, 38(2):161–169, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270409.

Venter:1998:IAC

[VS98] J. H. Venter and S. J. Steel. Identifying active contrasts by stepwise testing. *Technometrics*, 40(4):304–313, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270531.

vonTress:1991:BRB

[vT91] Mark von Tress. Book review: *Analysis of Messy Data, Volume 2: Nonreplicated Experiments* by George A. Milliken; Dallas E. Johnson. *Technometrics*, 33(1):114–115, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269023.

vonTress:1995:BRB

[vT95] Mark von Tress. Book review: *Statistical Models for Ordinal Variables* by Clifford C. Clogg; Edward S. Shihadeh. *Technometrics*, 37(1):118–119, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269166.

VanderWiel:1992:ASP

[VTFD92] Scott A. Vander Wiel, William T. Tucker, Frederick W. Faltin, and Necip Doganaksoy. Algorithmic statistical process control: Concepts and an application. *Technometrics*, 34(3):286–297, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270035.

Vukovinsky:1998:BRB

[Vuk98] Kim Vukovinsky. Book review: *Statistical Process Control* by Leonard A. Doty. *Technometrics*, 40(1):73–74, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271395.

VanderWiel:1992:SPM

[VV92] Scott A. Vander Wiel and Stephen B. Vardeman. [Statistical Process Monitoring and Feedback Adjustment]: Discussion. *Technometrics*, 34(3):278–281, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270032. See [BK92a].

VanderWiel:1994:DAN

[VV94] Scott A. Vander Wiel and Stephen B. Vardeman. A discussion of all-or-none inspection policies. *Technometrics*, 36(1):102–109, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269203.

Vardeman:1999:TWR

[VV99] Stephen B. Vardeman and Enid S. VanValkenburg. Two-way random-effects analyses and gauge R&R studies. *Technometrics*, 41(3):202–211, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270565.

Wade:1999:BRB

[Wad99] Mark R. Wade. Book review: *Construction and Assessment of Classification Rules* by David J. Hand. *Technometrics*, 41(3):267, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270579.

Waller:1992:BRB

[Wal92a] Ray A. Waller. Book review: *Probability and Statistics for the Engineering, Computing, and Physical Sciences* by Edward R. Dougherty. *Technometrics*, 34(2):241–242, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269263.

Walters:1992:BRB

[Wal92b] Sherry K. Walters. Book review: *Quality and Reliability Methods for Primary Batteries* by P. Bro; S. C. Levy. *Technometrics*, 34(3):361, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270053.

Wangen:1990:CCB

[Wan90] Larry E. Wangen. Commentary: [Communications between Statisticians and Engineers/Physical Scientists]. *Technometrics*, 32(3):273–274, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269103. See [HK90].

Wang:1994:BRB

[Wan94] Min-Chiang Wang. Book review: *Pyzdek's Guide to SPC: Volume One, Fundamentals* by Thomas Pyzdek. *Technometrics*, 36 (4):422, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269961.

Warren:1990:BRB

[War90] John Warren. Book review: *Mathematical and Statistical Methods in Nuclear Safeguards* by F. Argentesi; R. Avenhaus; M. Franklin; J. P. Shipley. *Technometrics*, 32(3):360–361, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269138.

Wasserman:1991:BRB

[Was91] Gary S. Wasserman. Book review: *Probability and Statistics for Modern Engineering* by Lawrence Lapin. *Technometrics*, 33(4):490, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269438.

Wasserstein:1997:BRB

[Was97] Ronald L. Wasserstein. Book review: *Monte Carlo: Concepts, Algorithms, and Applications* by G. S. Fishman. *Technometrics*, 39(3):338, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271146.

Watt:1990:BRB

[Wat90] Terry L. Watt. Book review: *Applied Statistics: A First Course* by M. L. Berenson; D. M. Levine; D. Rindskopf. *Technometrics*, 32(2):224, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268871.

Watt:1996:BRB

[Wat96] Terry L. Watt. Book review: *Numerical Analysis for the Geological Sciences* by James R. Carr. *Technometrics*, 38(3):293–294, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270623.

Wendelberger:1994:UCS

[WB94] Joanne Wendelberger and Richard Beckman. [The Use of Conditional Simulation in Nuclear-Waste-Site Performance Assessment]: Discussion. *Technometrics*, 36(2):144–147, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270222. See [Got94c].

Welch:1992:SPC

[WBS+92] William J. Welch, Robert. J. Buck, Jerome Sacks, Henry P. Wynn, Toby J. Mitchell, and Max D. Morris. Screening, predicting, and computer experiments. *Technometrics*, 34(1):15–25, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269548. See comments [LLW+96].

Wu:1992:GAM

[WC92] C. F. J. Wu and Youyi Chen. A graph-aided method for planning two-level experiments when certain interactions are important. *Technometrics*, 34(2):162–175, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269232.

Webster:1990:BRB

[Web90] J. T. Webster. Book review: *Experimental Design and Analysis* by Marvin Lentner; Thomas Bishop. *Technometrics*, 32(1):95, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269850.

Wehrly:1991:BRB

[Weh91] Thomas E. Wehrly. Book review: *Engineering Applications of Stochastic Processes* by Alexander Zayadezny; Daniel Tabak; Dov Wulich. *Technometrics*, 33(1):120, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269032.

Wehrly:1993:BRB

[Weh93] Thomas Wehrly. Book review: *Complex Stochastic Systems* by D. R. Cox; D. M. Titterington. *Technometrics*, 35(4):461–462, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270294.

Wehrly:1995:BRB

[Weh95] Thomas E. Wehrly. Book review: *Statistical Analysis of Circular Data* by N. I. Fisher. *Technometrics*, 37(2):229–230, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269626.

Weisberg:1990:BRB

[Wei90] Sanford Weisberg. Book review: *Transformations and Weighting in Regression* by R. J. Carroll; D. Ruppert. *Technometrics*, 32 (1):96–97, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269852. See corrections [Ano90g].

Weisberg:1994:BRB

[Wei94] Sanford Weisberg. Book review: *Handbook of Statistics 9: Computational Statistics* by C. R. Rao. *Technometrics*, 36(3):328–329, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269391.

Welch:1990:BRB

[Wel90] Michael E. Welch. Book review: *Bayesian Analysis of Time Series and Dynamic Models* by James C. Spall. *Technometrics*, 32 (3):354–355, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269130.

Welch:1993:BRB

[Wel93] Michael E. Welch. Book review: *Bivariate Discrete Distributions* by Subrahmaniam Kocherlakota; Kathleen Kocherlakota. *Technometrics*, 35(3):328–329, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269532.

Wendelberger:1993:BRB

[Wen93] Joanne R. Wendelberger. Book review: *Adventures in Stochastic Processes* by Sidney I. Resnick. *Technometrics*, 35(4):461, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270293.

Wendelberger:1994:BRB

[Wen94] Joanne R. Wendelberger. Book review: *Statistics and Society, Data Collection and Interpretation* by Walter T. Federer. *Technometrics*, 36(3):329–330, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269393.

Wesolowsky:1990:SAC

[Wes90] G. O. Wesolowsky. Simultaneous acceptance control charts for two correlated processes. *Technometrics*, 32(1):43–48, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269843.

Westfall:1992:BRB

[Wes92] Peter H. Westfall. Book review: *Bayesian Forecasting and Dynamic Models* by M. West; J. Harrison. *Technometrics*, 34(1): 115–116, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269581.

Wardrop:1992:SPM

[WG92] Daniel M. Wardrop and Carlos E. Garcia. [Statistical Process Monitoring and Feedback Adjustment]: Discussion. *Technometrics*, 34(3):281–282, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270033. See [BK92a].

Woo:1997:SIG

[WH97] T. C. Woo and Chung-Chi Hsieh. [Statistical Issues in Geometric Feature Inspection Using Coordinate Measuring Machines]: Discussion. *Technometrics*, 39(1):20–22, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270766. See [DGTZ97a].

Wharton:1995:BRB

[Wha95] Robert M. Wharton. Book review: *Model-Free Curve Estimation* by Michael E. Tarter; Michael D. Lock. *Technometrics*, 37 (4):460, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269743.

Wheeler:1993:BRB

[Whe93] Robert E. Wheeler. Book review: *Optimum Experimental Designs* by A. C. Atkinson; A. N. Donev. *Technometrics*, 35(4): 450, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270278.

Wang:1994:TID

[WI94] C. Ming Wang and Hari K. Iyer. Tolerance intervals for the distribution of true values in the presence of measurement errors. *Technometrics*, 36(2):162–170, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270228.

Willner:1990:BRB

[Wil90a] Ozzie Willner. Book review: *How to Choose the Proper Sample Size* by Gary Brush. *Technometrics*, 32(1):94–95, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269849.

Wilson:1990:BRB

[Wil90b] William J. Wilson. Book review: *Elementary Statistics* by Robert Johnson. *Technometrics*, 32(1):113, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269873.

Wilson:1998:BRB

[Wil98] William J. Wilson. Book review: *Statistics: The Conceptual Approach* by Gudmund R. Iversen; Mary Gergen. *Technometrics*, 40(1):77, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271401.

Wincek:1990:BRB

[Win90] Michael A. Wincek. Book review: *Applied Statistical Time Series Analysis* by Robert H. Shumway. *Technometrics*, 32(3):353–354, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269129.

Wincek:1993:BRB

[Win93] Michael A. Wincek. Book review: *Forecasting with Dynamic Regression Models* by Alan Pankrantz. *Technometrics*, 35(1):87–88, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269295.

Witt:1994:BRB

[Wit94] Thomas Witt. Book review: *A MINITAB Companion with Macros* by Peter W. Zehna. *Technometrics*, 36(1):124, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269222.

Weerahandi:1992:TRS

[WJ92] Samaradasa Weerahandi and Richard A. Johnson. Testing reliability in a stress-strength model when X and Y are normally distributed. *Technometrics*, 34(1):83–91, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269555. See [PGT95].

Wang:1995:CL

[WKWL95] P. C. Wang, Nouna Kettaneh-Wold, and Dennis K. J. Lin. Comments on Lin (1993). *Technometrics*, 37(3):358–359, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269944. See [Lin93b].

Whitmore:1991:MSD

[WL91] G. Alex Whitmore and Mei Ling Ting Lee. A multivariate survival distribution generated by an inverse Gaussian mixture of exponentials. *Technometrics*, 33(1):39–50, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269006.

Wang:1997:MEM

[WL97] C. Ming Wang and C. Teresa Lam. A mixed-effects model for the analysis of circular measurements. *Technometrics*, 39(2):119–126, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270900.

Woodall:1990:EWM

[WM90] William H. Woodall and Hazem D. Maragah. [Exponentially Weighted Moving Average Control Schemes: Properties and Enhancements]: Discussion. *Technometrics*, 32(1):17–18, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269837. See [LS90b].

Wardell:1994:RLDa

[WMP94a] Don G. Wardell, Herbert Moskowitz, and Robert D. Plante. Run-length distributions of special-cause control charts for correlated processes. *Technometrics*, 36(1):3–17, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269191. See discussion [Luc94, AWS94, Fel94] and rejoinder [WMP94b].

Wardell:1994:RLDb

[WMP94b] Don G. Wardell, Herbert Moskowitz, and Robert D. Plante. [Run-Length Distributions of Special-Cause Control Charts for Correlated Processes]: Rejoinder. *Technometrics*, 36(1):23–27, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269195.

Wludyka:1997:AMT

[WN97] Peter S. Wludyka and Peter R. Nelson. An analysis-of-means-type test for variances from normal populations. *Technometrics*, 39(3):274–285, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271132.

Wolf:1991:BRB

[Wol91] Dennis A. Wolf. Book review: *Algorithms for Chemists* by Jure Zupan. *Technometrics*, 33(3):367–368, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268799.

Wolkan:1992:BRB

[Wol92] Joseph A. Wolkan. Book review: *Introduction to Probability and Statistics* by J. S. Milton; J. C. Arnold. *Technometrics*, 34(2):244, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269268.

Wold:1993:DPC

[Wol93] Svante Wold. Discussion: PLS in chemical practice. *Technometrics*, 35(2):136–139, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269657.

Wolstenholme:1995:NTW

[Wol95] Linda C. Wolstenholme. A nonparametric test of the weakest-link principle. *Technometrics*, 37(2):169–175, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269618.

Wolf:1996:BRB

[Wol96] Dennis A. Wolf. Book review: *Recent Advances in Descriptive Multivariate Analysis* by Wojtek J. Krzanowski. *Technometrics*, 38(3):291–292, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270621.

Wong:1992:ISP

[Won92] Augustine C. M. Wong. Inferences on the shape parameter of a gamma distribution: A conditional approach. *Technometrics*, 34(3):348–351, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270041.

Wong:1994:BRB

[Won94] Aldous Wong. Book review: *Statistical Methods* by R. J. Freund; W. J. Wilson. *Technometrics*, 36(2):222, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270242.

Wong:1998:BRB

[Won98] Aldous G. Wong. Book review: *The Theory of Constraints: Applications in Quality and Manufacturing* by Robert E. Stein. *Technometrics*, 40(3):257, August 1998. CODEN TCMTA2. ISSN 0040-

1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271183`.

Woodall:1990:CCV

[Woo90] William H. Woodall. [CUSUM Charts with Variable Sampling Intervals]: Discussion. *Technometrics*, 32(4):389–391, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270117`. See [RAA90a].

Wood:1991:BRB

[Woo91] Jack Wood. Book review: *News and Numbers: A Guide to Reporting Statistical Claims and Controversies in Health and Related Fields* by Victor Cohn. *Technometrics*, 33(3):373–374, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268806`.

Woodall:1992:BRB

[Woo92] William H. Woodall. Book review: *SPC and Continuous Improvement* by Mal Owen. *Technometrics*, 34(1):100–101, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269561`.

Wozniak:1991:BRB

[Woz91] Patricia J. Wozniak. Book review: *Applied Nonparametric Statistics* by Wayne W. Daniel. *Technometrics*, 33(3):364–365, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268795`.

Wolfinger:1998:JEL

[WT98] Russell D. Wolfinger and Randall D. Tobias. Joint estimation of location, dispersion, and random effects in robust design. *Technometrics*, 40(1):62–71, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271393`.

Wu:1999:BRB

[Wu99] Yuhai Wu. Book review: *Statistical Learning Theory* by Vladimir N. Vapnik. *Technometrics*, 41(4):377–378, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271368`.

Wang:1997:RRA

[WVYB97] C. Ming Wang, Dominic F. Vecchia, Matt Young, and Nathan A. Brilliant. Robust regression applied to optical-fiber dimensional quality control. *Technometrics*, 39(1):25–33, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270769.

Wang:1992:NOA

[WW92] J. C. Wang and C. F. J. Wu. Nearly orthogonal arrays with mixed levels and small runs. *Technometrics*, 34(4):409–422, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268940.

Wyckoff:1996:BRB

[Wyc96] James Wyckoff. Book review: *Statistical Methods for Quality: With Applications to Engineering and Management* by Irwin Miller; Marylees Miller. *Technometrics*, 38(2):183, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270414.

Yakowitz:1997:BRB

[Yak97] Sidney J. Yakowitz. Book review: *An Introduction to Bayesian Networks* by Finn V. Jensen. *Technometrics*, 39(3):336–337, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271143.

Yandell:1996:BRB

[Yan96] Brian S. Yandell. Book review: *Kernel Smoothing* by M. P. Wand; M. C. Jones. *Technometrics*, 38(1):75–76, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268906.

Yandell:1997:BRB

[Yan97] Brian S. Yandell. Book review: *Smoothing Methods in Statistics* by J. S. Simonoff. *Technometrics*, 39(3):338–339, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271147.

Yashchin:1990:LE

[Yas90] Emmanuel Yashchin. Letter to the Editor. *Technometrics*, 32 (4):469, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270155.

Yashchin:1992:ACO

[Yas92] Emmanuel Yashchin. Analysis of CUSUM and other Markov-type control schemes by using empirical distributions. *Technometrics*, 34(1):54–63, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269552.

Yashchin:1993:PCC

[Yas93] Emmanuel Yashchin. Performance of CUSUM control schemes for serially correlated observations. *Technometrics*, 35(1):37–52, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269288.

Yashchin:1994:MVC

[Yas94] Emmanuel Yashchin. Monitoring variance components. *Technometrics*, 36(4):379–393, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269953.

Yashchin:1995:ECM

[Yas95] Emmanuel Yashchin. Estimating the current mean of a process subject to abrupt changes. *Technometrics*, 37(3):311–323, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269915.

Yanagisawa:1990:CLA

[YDB90] Y. Yanagisawa, J. Disney, and A. Bendell. [A Critical Look at Accumulation Analysis and Related Methods]: Discussion. *Technometrics*, 32(2):153–157, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268858. See [HW90b].

Young:1994:EEQ

[YE94] Linda J. Young and Robert G. Easterling. Estimation of extreme quantiles based on sensitivity tests: A comparative study. *Technometrics*, 36(1):48–60, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269198.

Yeh:1993:BRB

[Yeh93] Chyon-Hwa Yeh. Book review: *Design Statistics in Pharmacochemistry* by Peter P. Mager. *Technometrics*, 35(3):331, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269536`.

Ying:1991:BRB

[Yin91] Zhiliang Ying. Book review: *Multi-Armed Bandit Allocation Indices* by John C. Gittins. *Technometrics*, 33(4):488, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269435`.

Yashchin:1995:CWM

[YWMP95] Emmanuel Yashchin, Don G. Wardell, Herbert Moskowitz, and Robert D. Plante. Comments on Wardell, Moskowitz, and Plante (1994). *Technometrics*, 37(2):243–245, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269653`.

Zadeh:1995:DPT

[Zad95] Lotfi A. Zadeh. Discussion: Probability theory and fuzzy logic are complementary rather than competitive. *Technometrics*, 37 (3):271–276, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269908`.

Zeitler:1994:BRB

[Zei94] David W. Zeitler. Book review: *Introduction to Quality Control* by Donald DelMar; George Sheldon. *Technometrics*, 36(1): 120–121, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269217`.

Zelterman:1994:BRB

[Zel94] Daniel Zelterman. Book review: *Statistical Models for Causal Analysis* by Robert D. Retherford; Minja Kim Choe. *Technometrics*, 36(3):327–328, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269389`.

Zhang:1992:BRB

[Zha92] Nien Fan Zhang. Book review: *Forecasting and Time Series Analysis* by D. C. Montgomery; L. A. Johnson; J. S. Gardiner.

Technometrics, 34(1):98–99, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269557.

Zhang:1994:MCA

[Zha94] Heping Zhang. Maximal correlation and adaptive splines. *Technometrics*, 36(2):196–201, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270231.

Zhang:1998:SCC

[Zha98] Nien Fan Zhang. A statistical control chart for stationary process data. *Technometrics*, 40(1):24–38, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271390. See comments [Sch98b].

Ziegel:1990:BRBx

[Zie90a] Eric R. Ziegel. Book review: *Applied Nonparametric Statistical Models* by P. Sprent. *Technometrics*, 32(4):455–456, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270134.

Ziegel:1990:BRBv

[Zie90b] Eric R. Ziegel. Book review: *Applied Regression Analysis in Econometrics* by Howard E. Doran. *Technometrics*, 32(4):451, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270128.

Ziegel:1990:BRBw

[Zie90c] Eric R. Ziegel. Book review: *Applied Time Series Analysis* by Robert Shumway. *Technometrics*, 32(4):451–452, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270129.

Ziegel:1990:BRBo

[Zie90d] Eric R. Ziegel. Book review: *COMPSTAT 1988* by D. Edwards; N. Raun. *Technometrics*, 32(2):239, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268892.

Ziegel:1990:BRBl

[Zie90e] Eric R. Ziegel. Book review: *Contouring Geologic Surfaces with the Computer* by T. Jones; D. Hamilton; C. Johnson. *Technometrics*, 32(2):232, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268882.

Ziegel:1990:BRBp

[Zie90f] Eric R. Ziegel. Book review: *Data Analysis and Informatics 5* by E. Diday. *Technometrics*, 32(2):239–240, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268893.

Ziegel:1990:BRBz

[Zie90g] Eric R. Ziegel. Book review: *Data, Expert Knowledge, and Decisions* by W. Gaul; M. Schader. *Technometrics*, 32(4):465–466, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270151.

Ziegel:1990:BRBh

[Zie90h] Eric R. Ziegel. Book review: *Encyclopedia of Statistical Sciences, Volume 9: Strata Chart to End with Cumulative Index* by S. Kotz; N. Johnson; C. Read. *Technometrics*, 32(2):225, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268872.

Ziegel:1990:BRBd

[Zie90i] Eric R. Ziegel. Book review: *Geostatistical Case Studies* by G. Matheron; M. Armstrong. *Technometrics*, 32(1):105–106, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269864.

Ziegel:1990:BRBj

[Zie90j] Eric R. Ziegel. Book review: *Geostatistics and Petroleum Geology* by Michael Hohn. *Technometrics*, 32(2):231, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268880.

Ziegel:1990:BRBy

[Zie90k] Eric R. Ziegel. Book review: *Handbook of Statistics, Volume 6: Sampling* by P. R. Krishnaiah; C. R. Rao. *Technometrics*, 32

(4):460, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270142.

Ziegel:1990:BRBa

[Zie90l] Eric R. Ziegel. Book review: *Juran's Quality Control Handbook* by J. M. Juran; F. M. Gryna. *Technometrics*, 32(1):97–98, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269854.

Ziegel:1990:BRBe

[Zie90m] Eric R. Ziegel. Book review: *Mathematical Geology* by N. Rock. *Technometrics*, 32(1):106, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269865.

Ziegel:1990:BRBq

[Zie90n] Eric R. Ziegel. Book review: *Mathematical Modelling* by J. N. Kapur. *Technometrics*, 32(2):240, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268894.

Ziegel:1990:BRBf

[Zie90o] Eric R. Ziegel. Book review: *Model-Oriented Data Analysis* by V. Federov; H. Lauter. *Technometrics*, 32(1):106, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269866.

Ziegel:1990:BRBaa

[Zie90p] Eric R. Ziegel. Book review: *On Model Uncertainty and Its Statistical Implications* by Theo Dijkstra. *Technometrics*, 32(4):466, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270152.

Ziegel:1990:BRBi

[Zie90q] Eric R. Ziegel. Book review: *Optimal Design and Analysis of Experiments* by Y. Dodge; V. Federov; H. Wynn. *Technometrics*, 32(2):229, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268877.

Ziegel:1990:BRBs

[Zie90r] Eric R. Ziegel. Book review: *Principles of Environmental Sampling* by Lawrence Keith. *Technometrics*, 32(3):357, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269133`.

Ziegel:1990:BRBn

[Zie90s] Eric R. Ziegel. Book review: *Probability and Statistics* by Jaya Srivastava. *Technometrics*, 32(2):239, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268891`.

Ziegel:1990:BRBr

[Zie90t] Eric R. Ziegel. Book review: *Statistical Quality Control* by E. Grant; R. Leavenworth. *Technometrics*, 32(3):343–344, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269115`.

Ziegel:1990:BRBu

[Zie90u] Eric R. Ziegel. Book review: *Statistical Tables and Formulae* by S. Kokoska; C. Nevison. *Technometrics*, 32(3):361, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269140`.

Ziegel:1990:BRBg

[Zie90v] Eric R. Ziegel. Book review: *Statistical Theory and Data Analysis II* by K. Matusita. *Technometrics*, 32(1):113–114, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269874`.

Ziegel:1990:BRBt

[Zie90w] Eric R. Ziegel. Book review: *Statistics: A Guide to the Unknown* by J. Tanur; F. Mosteller; W. Kruskal; E. Lehman; R. Link; R. Pieters; G. Rising. *Technometrics*, 32(3):361, August 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269139`.

Ziegel:1990:BRBb

[Zie90x] Eric R. Ziegel. Book review: *Statistics in Research* by Bernard Ostle; Linda Malone. *Technometrics*, 32(1):100–101, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269858`.

Ziegel:1990:BRBm

[Zie90y] Eric R. Ziegel. Book review: *The Evolving Role of Statistical Assessments as Evidence in the Courts* by Stephen Fienberg. *Technometrics*, 32(2):238–239, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268890.

Ziegel:1990:BRBk

[Zie90z] Eric R. Ziegel. Book review: *Use and Abuse of Statistical Methods in the Earth Sciences* by William Size. *Technometrics*, 32(2): 231–232, May 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268881.

Ziegel:1990:BRBc

[Zie90-27] Eric R. Ziegel. Book reviews: *Data Analysis for Managers* by Harry Roberts; *Minitab Handbook for Business and Economics* by Robert Miller; *Essential Business Statistics* by K. Bond; J. Scott; *Mathematical Modelling with Minitab* by W. Fox; F. Giordano; S. Maddox; M. Weir. *Technometrics*, 32(1):102, February 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269860.

Ziegel:1990:BRBab

[Zie90-28] Eric R. Ziegel. Book reviews: *Survey Errors and Survey Costs* by Robert M. Groves; *Telephone Survey Methodology* by R. Groves; P. Biemer; L. Lyberg; J. Massey; W. Nicholls; J. Waksberg; *Panel Surveys* by D. Karprzyk; G. Duncan; G. Kalton; M. Singh. *Technometrics*, 32(4):466–467, November 1990. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270153.

Ziegel:1991:BRBl

[Zie91a] Eric R. Ziegel. Book review: *A Dictionary of Statistical Terms* by F. H. C. Marriott. *Technometrics*, 33(2):247–248, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269067.

Ziegel:1991:BRBp

[Zie91b] Eric R. Ziegel. Book review: *Assignments in Applied Statistics* by Simon Conrad. *Technometrics*, 33(2):249, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269071.

Ziegel:1991:BRBm

[Zie91c] Eric R. Ziegel. Book review: *Beta Mathematics Handbook* by L. Rade; B. Westergren. *Technometrics*, 33(2):248, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269068`.

Ziegel:1991:BRBo

[Zie91d] Eric R. Ziegel. Book review: *Classical and Modern Regression with Applications* by Raymond Myers. *Technometrics*, 33(2):248, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269070`.

Ziegel:1991:BRBk

[Zie91e] Eric R. Ziegel. Book review: *Collected Works of John W. Tukey, Volume 6: More Mathematical 1938–1984* by Colin Mallows and John W. Tukey. *Technometrics*, 33(2):247, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269066?`.

Ziegel:1991:BRBj

[Zie91f] Eric R. Ziegel. Book review: *Collected Works of John W. Tukey, Volume 6: More Mathematical 1938–1984* by Colin Mallows; John W. Tukey. *Technometrics*, 33(2):247, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269066`.

Ziegel:1991:BRBa

[Zie91g] Eric R. Ziegel. Book review: *Concise Encyclopedia of Science and Technology* by Sybil Parker. *Technometrics*, 33(1):121, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269034`.

Ziegel:1991:BRBq

[Zie91h] Eric R. Ziegel. Book review: *Data Analysis in the Chemical Industry: Volume 1. Basics* by Roland Caulcott. *Technometrics*, 33(3):366, August 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268797`.

Ziegel:1991:BRBc

[Zie91i] Eric R. Ziegel. Book review: *Handbook of Nonlinear Regression Models* by David Ratkowsky. *Technometrics*, 33(2):240–241, May

1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269053.

Ziegel:1991:BRBn

[Zie91j] Eric R. Ziegel. Book review: *Linear Statistical Models: An Applied Approach* by Bruce Bowerman; Richard O'Connell. *Technometrics*, 33(2):248, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269069.

Ziegel:1991:BRBi

[Zie91k] Eric R. Ziegel. Book review: *Multivariate Statistics and Probability: Essays in Honor of P. R. Krishnaiah* by C. Rao; M. Rao. *Technometrics*, 33(2):247, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269065.

Ziegel:1991:BRBh

[Zie91l] Eric R. Ziegel. Book review: *Nonlinear Regression, Functional Relations, and Robust Methods* by H. Bunke; O. Bunke. *Technometrics*, 33(2):247, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269064.

Ziegel:1991:BRBd

[Zie91m] Eric R. Ziegel. Book review: *Probability and Statistics in Geodesy and Geophysics* by L. Kubackova; L. Kubacek; J. Kukuca. *Technometrics*, 33(2):241, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269055.

Ziegel:1991:BRBb

[Zie91n] Eric R. Ziegel. Book review: *Risk Management and Assessment* by Lester Lave. *Technometrics*, 33(1):121, February 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269035.

Ziegel:1991:BRBr

[Zie91o] Eric R. Ziegel. Book review: *Statistical Design and Analysis of Industrial Experiments* by Subir Ghosh. *Technometrics*, 33(4):470, November 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269418.

Ziegel:1991:BRBg

[Zie91p] Eric R. Ziegel. Book review: *Taguchi Methods (Special Issue of Quality and Reliability Engineering)* by Norman Harris. *Technometrics*, 33(2):246–247, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269063`.

Ziegel:1991:BRBe

[Zie91q] Eric R. Ziegel. Book reviews: *Analysis of Binary Data* by D. R. Cox; E. J. Snell; *Design and Analysis of Cross-Over Trials* by Byron Jones; Michael Kenward. *Technometrics*, 33(2):242–243, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269058`.

Ziegel:1991:BRBf

[Zie91r] Eric R. Ziegel. Book reviews: *Statistical Methodology in the Pharmaceutical Sciences* by Donald L. Berry; *Statistical Issues in Drug Research and Development* by Karl E. Peace. *Technometrics*, 33 (2):243, May 1991. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269059`.

Ziegel:1992:BRBd

[Zie92a] Eric R. Ziegel. Book review: *A History of Probability and Statistics and Their Applications before 1750* by Anders Hald. *Technometrics*, 34(1):122, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269591`.

Ziegel:1992:BRBa

[Zie92b] Eric R. Ziegel. Book review: *Applied Linear Statistical Models* by John Neter; William Wasserman; Michael Kutner. *Technometrics*, 34(1):121, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269588`.

Ziegel:1992:BRBl

[Zie92c] Eric R. Ziegel. Book review: *Chemometrics Tutorials* by D. Massart; R. Brereton; R. Dessy; P. Hopke; C. Spiegelman; W. Wegscheider. *Technometrics*, 34(2):247, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269275`.

Ziegel:1992:BRBh

[Zie92d] Eric R. Ziegel. Book review: *Computation Methods in the Chemical Sciences* by A. Carley; P. Morgan. *Technometrics*, 34(2): 245–246, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269271.

Ziegel:1992:BRBk

[Zie92e] Eric R. Ziegel. Book review: *Computer-Aided Multivariable Analysis* by A. Afifi; V. Clark. *Technometrics*, 34(2):246–247, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269274.

Ziegel:1992:BRBc

[Zie92f] Eric R. Ziegel. Book review: *Data Analysis for Research Designs* by G. Keppel; C. Zedick. *Technometrics*, 34(1):122, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269590.

Ziegel:1992:BRBg

[Zie92g] Eric R. Ziegel. Book review: *Encyclopedia of Statistical Sciences, Supplement Volume* by S. Kotz; N. Johnson; C. Read. *Technometrics*, 34(1):123, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269594.

Ziegel:1992:BRBf

[Zie92h] Eric R. Ziegel. Book review: *Geostatistics* by M. Armstrong. *Technometrics*, 34(1):123, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269593.

Ziegel:1992:BRBn

[Zie92i] Eric R. Ziegel. Book review: *How to Run Mixture Experiments for Product Quality* by John Cornell. *Technometrics*, 34(3):370, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270067.

Ziegel:1992:BRBb

[Zie92j] Eric R. Ziegel. Book review: *Mastering Technical Writing* by Joseph Mancuso. *Technometrics*, 34(1):121–122, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269589.

Ziegel:1992:BRBj

[Zie92k] Eric R. Ziegel. Book review: *Multiway Data Analysis* by R. Coppi; S. Bolasco. *Technometrics*, 34(2):246, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269273`.

Ziegel:1992:BRBt

[Zie92l] Eric R. Ziegel. Book review: *Probability and Statistics for Engineering and the Sciences* by Jay L. Devore. *Technometrics*, 34(3): 372, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270073`.

Ziegel:1992:BRBs

[Zie92m] Eric R. Ziegel. Book review: *Sampling of Populations: Methods and Applications* by P. Levy; S. Lemeshaw. *Technometrics*, 34(3):372, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270072`.

Ziegel:1992:BRBu

[Zie92n] Eric R. Ziegel. Book review: *SAS System for Linear Models* by R. Littell; R. Freund; P. Spector. *Technometrics*, 34(4):500, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268965`.

Ziegel:1992:BRBv

[Zie92o] Eric R. Ziegel. Book review: *SAS System for Regression* by R. Freund; R. Littell. *Technometrics*, 34(4):500–501, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268966`.

Ziegel:1992:BRBr

[Zie92p] Eric R. Ziegel. Book review: *State Space Modeling of Time Series* by M. Aoki. *Technometrics*, 34(3):371–372, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270071`.

Ziegel:1992:BRBi

[Zie92q] Eric R. Ziegel. Book review: *Statistical Data Analysis and Inference* by Yadolah Dodge. *Technometrics*, 34(2):246, May 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269272`.

Ziegel:1992:BRBo

[Zie92r] Eric R. Ziegel. Book review: *Statistical Process Control in Manufacturing* by J. Keats; D. Montgomery. *Technometrics*, 34(3):370–371, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270068`.

Ziegel:1992:BRBx

[Zie92s] Eric R. Ziegel. Book review: *Statistical Theory and Modelling* by D. Hinkley; N. Reid; E. J. Snell. *Technometrics*, 34(4):501, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268968`.

Ziegel:1992:BRBe

[Zie92t] Eric R. Ziegel. Book review: *Statistics for Lawyers* by M. Finkelstein; B. Levin. *Technometrics*, 34(1):122–123, February 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269592`.

Ziegel:1992:BRBw

[Zie92u] Eric R. Ziegel. Book review: *Statistics in Research and Development* by R. Caulcott. *Technometrics*, 34(4):501, November 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268967`.

Ziegel:1992:BRBq

[Zie92v] Eric R. Ziegel. Book review: *Time Series: Theory and Methods* by P. Brockwell; R. Davis. *Technometrics*, 34(3):371, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270070`.

Ziegel:1992:BRBp

[Zie92w] Eric R. Ziegel. Book review: *Total Quality Control* by A. Fergenbaum. *Technometrics*, 34(3):371, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270069`.

Ziegel:1992:BRBm

[Zie92x] Eric R. Ziegel. Book review: *Understanding Industrial Experimentation* by Donald J. Wheeler. *Technometrics*, 34(3):370, August 1992. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270066`.

Ziegel:1993:BRBm

[Zie93a] Eric R. Ziegel. Book review: *A Leader's Journey to Quality* by Dana Cound. *Technometrics*, 35(1):102, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269322.

Ziegel:1993:BRBae

[Zie93b] Eric R. Ziegel. Book review: *ANOVA: Repeated Measures* by E. Girden. *Technometrics*, 35(4):464–465, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270301.

Ziegel:1993:BRBab

[Zie93c] Eric R. Ziegel. Book review: *Applied Statistics for Engineers and Physical Scientists* by R. Hogg; J. Ledolter. *Technometrics*, 35 (4):463, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270298.

Ziegel:1993:BRBd

[Zie93d] Eric R. Ziegel. Book review: *Chemometrics: Experimental Design* by E. Morgan. *Technometrics*, 35(1):99, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269313.

Ziegel:1993:BRBaa

[Zie93e] Eric R. Ziegel. Book review: *Computing and Graphics in Statistics* by A. Buja; P. Tukey. *Technometrics*, 35(4):463, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270297.

Ziegel:1993:BRBr

[Zie93f] Eric R. Ziegel. Book review: *Control and Analysis of Noisy Processes* by D. Koenig. *Technometrics*, 35(2):231–232, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269681.

Ziegel:1993:BRBq

[Zie93g] Eric R. Ziegel. Book review: *Correspondence Analysis Handbook* by J. P. Benzecri. *Technometrics*, 35(1):103, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269326.

Ziegel:1993:BRBc

[Zie93h] Eric R. Ziegel. Book review: *Data Analysis for Managers* by Harry Roberts. *Technometrics*, 35(1):99, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269312`.

Ziegel:1993:BRBs

[Zie93i] Eric R. Ziegel. Book review: *Deming's Road to Continual Improvement* by W. Scherkenbach. *Technometrics*, 35(2):233–234, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269685`.

Ziegel:1993:BRBac

[Zie93j] Eric R. Ziegel. Book review: *Design and Inference in Finite Population Sampling* by A. Hedayat; B. Sinha. *Technometrics*, 35 (4):463–464, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270299`.

Ziegel:1993:BRBp

[Zie93k] Eric R. Ziegel. Book review: *Directions in Robust Statistics and Diagnostics (Parts 1 and 2)* by W. Stahel; S. Wersberg. *Technometrics*, 35(1):103, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269325`.

Ziegel:1993:BRBaj

[Zie93l] Eric R. Ziegel. Book review: *Handbook of Quality Assurance for the Analytical Chemical Laboratory* by J. Dux. *Technometrics*, 35 (4):466, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270306`.

Ziegel:1993:BRBi

[Zie93m] Eric R. Ziegel. Book review: *Introductory Statistics* by Prem Mann. *Technometrics*, 35(1):100–101, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269318`.

Ziegel:1993:BRBw

[Zie93n] Eric R. Ziegel. Book review: *ISO 9000* by J. Lamprecht. *Technometrics*, 35(2):240, May 1993. CODEN TCMTA2. ISSN 0040-

1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269696.

Ziegel:1993:BRBah

[Zie93o] Eric R. Ziegel. Book review: *Latent Variable Models* by J. Loehlin. *Technometrics*, 35(4):465, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270304.

Ziegel:1993:BRBal

[Zie93p] Eric R. Ziegel. Book review: *Managing Quality* by R. Schuler; D. Harris. *Technometrics*, 35(4):466, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270308.

Ziegel:1993:BRBo

[Zie93q] Eric R. Ziegel. Book review: *Managing Quality Dynamics* by James Teboul. *Technometrics*, 35(1):102–103, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269324.

Ziegel:1993:BRBg

[Zie93r] Eric R. Ziegel. Book review: *Measurement Errors in Surveys* by P. Biemer; R. Groves; L. Lyberg; N. Mathiowetz; S. Sudman. *Technometrics*, 35(1):100, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269316.

Ziegel:1993:BRBt

[Zie93s] Eric R. Ziegel. Book review: *Nonparametric Statistical Inference* by J. Gibbons; S. Chakraborti. *Technometrics*, 35(2):239–240, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269693.

Ziegel:1993:BRBad

[Zie93t] Eric R. Ziegel. Book review: *Nonsampling Error in Surveys* by J. Lessler; W. Kalsbeek. *Technometrics*, 35(4):464, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270300.

Ziegel:1993:BRBn

[Zie93u] Eric R. Ziegel. Book review: *Quality at Work in Research and Development* by George Kidd. *Technometrics*, 35(1):102, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269323`.

Ziegel:1993:BRBb

[Zie93v] Eric R. Ziegel. Book review: *Quality Engineering Handbook* by T. Pyzdek; R. Berger. *Technometrics*, 35(1):98–99, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269311`.

Ziegel:1993:BRBai

[Zie93w] Eric R. Ziegel. Book review: *Quality Through Engineering Design* by W. Kuo; M. Pierson. *Technometrics*, 35(4):465–466, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270305`.

Ziegel:1993:BRBe

[Zie93x] Eric R. Ziegel. Book review: *Regression Diagnostics* by John Fox; Newbury Park. *Technometrics*, 35(1):99–100, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269314`.

Ziegel:1993:BRBz

[Zie93y] Eric R. Ziegel. Book review: *Sampling* by Steven Thompson. *Technometrics*, 35(3):324, August 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269527`.

Ziegel:1993:BRBj

[Zie93z] Eric R. Ziegel. Book review: *SAS System for Statistical Graphics* by M. Friendly. *Technometrics*, 35(1):101, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269319`.

Ziegel:1993:BRBk

[Zie93-27] Eric R. Ziegel. Book review: *Statistical Methods for Survival Data Analysis* by Elisa T. Lee. *Technometrics*, 35(1):101, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269320`.

Ziegel:1993:BRBaf

[Zie93-28] Eric R. Ziegel. Book review: *Statistical Methods in Biological and Medical Sciences* by C. R. Rao; R. Chakraborty. *Technomet-*

rics, 35(4):465, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270302.

Ziegel:1993:BRBh

[Zie93-29] Eric R. Ziegel. Book review: *Statistical Methods: The Geometric Approach* by D. Saville; G. Wood. *Technometrics*, 35(1):100, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269317.

Ziegel:1993:BRBa

[Zie93-30] Eric R. Ziegel. Book review: *Statistical Theory and Modelling* by D. Hinkley; N. Reid; E. J. Snell. *Technometrics*, 35(1):98, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269310.

Ziegel:1993:BRBag

[Zie93-31] Eric R. Ziegel. Book review: *Statistics for Toxicologists* by David Salsburg. *Technometrics*, 35(4):465, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270303.

Ziegel:1993:BRBu

[Zie93-32] Eric R. Ziegel. Book review: *Survey Sampling* by A. Chaudhuri; H. Stenger. *Technometrics*, 35(2):240, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269694.

Ziegel:1993:BRBf

[Zie93-33] Eric R. Ziegel. Book review: *Survey Sampling Principles* by E. K. Foreman. *Technometrics*, 35(1):100, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269315.

Ziegel:1993:BRBx

[Zie93-34] Eric R. Ziegel. Book review: *The Team Approach to Quality* by K. Shilliff; P. Motiska. *Technometrics*, 35(2):240–241, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269697.

Ziegel:1993:BRBy

[Zie93-35] Eric R. Ziegel. Book review: *The Whats, Whys, and Hows of Quality Improvement* by G. Miller; L. Krumm. *Technometrics*, 35 (2):241, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269698.

Ziegel:1993:BRBv

[Zie93-36] Eric R. Ziegel. Book review: *Total Engineering Quality Management* by R. Cottman. *Technometrics*, 35(2):240, May 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269695.

Ziegel:1993:BRBak

[Zie93-37] Eric R. Ziegel. Book review: *Total Quality Management* by A. Tenner; I. DeToro. *Technometrics*, 35(4):466, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270307.

Ziegel:1993:BRBl

[Zie93-38] Eric R. Ziegel. Book review: *Understanding Statistical Process Control* by D. Wheeler; D. Chambers. *Technometrics*, 35(1):101–102, February 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269321.

Ziegel:1994:BRBao

[Zie94a] Eric R. Ziegel. Book review: *100 Statistical Tests* by G. K. Kanji. *Technometrics*, 36(4):436, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269982.

Ziegel:1994:BRBh

[Zie94b] Eric R. Ziegel. Book review: *A Geostatistical Primer* by Peter Brooker. *Technometrics*, 36(2):219–220, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270239.

Ziegel:1994:BRBu

[Zie94c] Eric R. Ziegel. Book review: *Adequacy of Sample Size in Health Studies* by S. Lemeshow; D. Hosmer; J. Klar; S. Luanga. *Technometrics*, 36(2):232, May 1994. CODEN TCMTA2. ISSN 0040-

1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270261`.

Ziegel:1994:BRBag

[Zie94d] Eric R. Ziegel. Book review: *Advanced Calculus with Applications in Statistics* by Andre Khuri. *Technometrics*, 36(3):333, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269402`.

Ziegel:1994:BRBab

[Zie94e] Eric R. Ziegel. Book review: *Advances in GLIM and Statistical Modelling* by L. Fahrmeir; B. Francis; R. Gilchrist; G. Tutz. *Technometrics*, 36(3):331, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269397`.

Ziegel:1994:BRBad

[Zie94f] Eric R. Ziegel. Book review: *An Introduction to Statistical Methods and Data Analysis* by Lyman Ott. *Technometrics*, 36(3): 332, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269399`.

Ziegel:1994:BRBe

[Zie94g] Eric R. Ziegel. Book review: *Basic Statistics for Laboratories* by W. Kelly; T. Ratliff; C. Nenadic. *Technometrics*, 36(1):126, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269226`.

Ziegel:1994:BRBac

[Zie94h] Eric R. Ziegel. Book review: *Basic Statistics: Tools for Continuous Improvement* by M. Kiemele; S. Schmidt. *Technometrics*, 36(3):331, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269398`.

Ziegel:1994:BRBs

[Zie94i] Eric R. Ziegel. Book review: *Biostatistics* by L. Fisher; G. van Belle. *Technometrics*, 36(2):231–232, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270259`.

Ziegel:1994:BRBan

[Zie94j] Eric R. Ziegel. Book review: *Boostrapping: A Nonparametric Approach to Statistical Inference* by C. Mooney; R. Duvall. *Technometrics*, 36(4):435–436, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269981.

Ziegel:1994:BRBae

[Zie94k] Eric R. Ziegel. Book review: *Chemometrics Tutorials II* by R. Brereton; D. Scott; R. Massart; R. Dessy; P. Hopke; C. Spiegelman; W. Wegscheider. *Technometrics*, 36(3):332, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269400.

Ziegel:1994:BRBf

[Zie94l] Eric R. Ziegel. Book review: *Continuous Improvement: Teams and Tools* by R. Lynch; T. Werner. *Technometrics*, 36(1):126, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269227.

Ziegel:1994:BRBv

[Zie94m] Eric R. Ziegel. Book review: *Cross-Over Experiments* by D. Ratkowsky; M. Evans; J. Alldredge. *Technometrics*, 36(2):232–233, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270262.

Ziegel:1994:BRBw

[Zie94n] Eric R. Ziegel. Book review: *Cross-Over Trials in Clinical Research* by Stephen Senn. *Technometrics*, 36(2):233, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270263.

Ziegel:1994:BRBa

[Zie94o] Eric R. Ziegel. Book review: *Data Analysis for the Chemical Sciences* by Richard Graham. *Technometrics*, 36(1):116, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269210.

Ziegel:1994:BRBt

[Zie94p] Eric R. Ziegel. Book review: *Design and Analysis of Bioavailability and Bioequivalence Studies* by S. Chow; J. Liu. *Techno-*

metrics, 36(2):232, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270260.

Ziegel:1994:BRBy

[Zie94q] Eric R. Ziegel. Book review: *Ecological Risk Estimation* by S. Bartell; R. Gardner; R. O'Neill. *Technometrics*, 36(3):324–325, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269386.

Ziegel:1994:BRBai

[Zie94r] Eric R. Ziegel. Book review: *Essentials of SPC in the Process Industries* by J. Pruett; H. Schneider. *Technometrics*, 36(4):421–422, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269960.

Ziegel:1994:BRBi

[Zie94s] Eric R. Ziegel. Book review: *Experimental Design: A Chemometric Approach* by Stanley N. Deming; Stephen L. Morgan. *Technometrics*, 36(2):227–228, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270249.

Ziegel:1994:BRBaj

[Zie94t] Eric R. Ziegel. Book review: *Forecasting and Time Series: An Applied Approach* by Bruce Bowerman; Richard O'Connell. *Technometrics*, 36(4):434, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269977.

Ziegel:1994:BRBaa

[Zie94u] Eric R. Ziegel. Book review: *Handbook of Sequential Analysis* by B. Ghosh; P. Sen. *Technometrics*, 36(3):331, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269396.

Ziegel:1994:BRBap

[Zie94v] Eric R. Ziegel. Book review: *Handbook of Statistics 11: Econometrics* by G. Maddala; C. Rao; H. Vinod. *Technometrics*, 36(4):436, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269983.

Ziegel:1994:BRBah

[Zie94w] Eric R. Ziegel. Book review: *Handbook of Writing for the Mathematical Sciences* by N. Higham. *Technometrics*, 36(3):333, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269403`.

Ziegel:1994:BRBak

[Zie94x] Eric R. Ziegel. Book review: *Introduction to Multiple Time Series Analysis* by H. Lütkepohl. *Technometrics*, 36(4):434–435, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269978`.

Ziegel:1994:BRBb

[Zie94y] Eric R. Ziegel. Book review: *Introduction to the Practice of Statistics* by D. Moore; G. McCabe. *Technometrics*, 36(1):124–125, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269223`.

Ziegel:1994:BRBr

[Zie94z] Eric R. Ziegel. Book review: *Longitudinal Data with Serial Correlation: A State-Space Approach* by R. Jones. *Technometrics*, 36 (2):231, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270258`.

Ziegel:1994:BRBq

[Zie94-27] Eric R. Ziegel. Book review: *Multiple Comparisons, Selection, and Applications in Biometry* by Fred Hoppe. *Technometrics*, 36(2):230–231, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270257`.

Ziegel:1994:BRBal

[Zie94-28] Eric R. Ziegel. Book review: *Networks and Chaos: Statistical and Probabilistic Aspects* by O. Barndorff-Nielson; J. L. Jensen; W. S. Kendall. *Technometrics*, 36(4):435, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269979`.

Ziegel:1994:BRBam

[Zie94-29] Eric R. Ziegel. Book review: *New Directions in Statistical Data Analysis and Robustness* by S. Morgenthaler; E. Ronchetti; W.

Stahel. *Technometrics*, 36(4):435, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269980.

Ziegel:1994:BRBaq

[Zie94-30] Eric R. Ziegel. Book review: *Principles of Biostatistics* by M. Pagano; K. Gauvreau. *Technometrics*, 36(4):436–437, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269984.

Ziegel:1994:BRBc

[Zie94-31] Eric R. Ziegel. Book review: *Probability and Statistics for Engineers and Scientists* by R. Walpole; R. Myers. *Technometrics*, 36(1):125, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269224.

Ziegel:1994:BRBj

[Zie94-32] Eric R. Ziegel. Book review: *Probability* by J. Pitman. *Technometrics*, 36(2):228, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270250.

Ziegel:1994:BRBn

[Zie94-33] Eric R. Ziegel. Book review: *Quality Control for Profit* by R. Lester; N. Enrick; H. Mottley. *Technometrics*, 36(2):229, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270254.

Ziegel:1994:BRBx

[Zie94-34] Eric R. Ziegel. Book review: *Real-Time Statistical Process Control* by P. Badavas. *Technometrics*, 36(3):321–322, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269383.

Ziegel:1994:BRBz

[Zie94-35] Eric R. Ziegel. Book review: *Regression with Dummy Variables* by M. Hardy. *Technometrics*, 36(3):330–331, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269395.

Ziegel:1994:BRBo

[Zie94-36] Eric R. Ziegel. Book review: *Root Cause Analysis* by P. Wilson; L. Dell; G. Anderson. *Technometrics*, 36(2):230, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270255.

Ziegel:1994:BRBp

[Zie94-37] Eric R. Ziegel. Book review: *Sequential Data in Biological Experiments* by E. Roberts. *Technometrics*, 36(2):230, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270256.

Ziegel:1994:BRBl

[Zie94-38] Eric R. Ziegel. Book review: *Statistical Distributions* by M. Evans; N. Hastings; B. Peacock. *Technometrics*, 36(2):229, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270252.

Ziegel:1994:BRBas

[Zie94-39] Eric R. Ziegel. Book review: *Statistical Models in Engineering* by G. Hahn; S. Shapiro. *Technometrics*, 36(4):437, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269986.

Ziegel:1994:BRBk

[Zie94-40] Eric R. Ziegel. Book review: *Statistics for Engineering and the Sciences* by W. Mendenhall; T. Sincich. *Technometrics*, 36(2):228–229, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270251.

Ziegel:1994:BRBar

[Zie94-41] Eric R. Ziegel. Book review: *Statistics for Spatial Data* by Noel Cressie. *Technometrics*, 36(4):437, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269985.

Ziegel:1994:BRBaf

[Zie94-42] Eric R. Ziegel. Book review: *Statistics for the Environment* by V. Barnett; K. Turkman. *Technometrics*, 36(3):332–333, August 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269401.

Ziegel:1994:BRBm

[Zie94-43] Eric R. Ziegel. Book review: *Statistics Quality Control for the Workplace* by F. Kaminsky; R. Davis; R. Burke. *Technometrics*, 36(2):229, May 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270253.

Ziegel:1994:BRBg

[Zie94-44] Eric R. Ziegel. Book review: *TQM: The Mechanics of Quality Processes* by R. Johnson; L. Kazense. *Technometrics*, 36(1):126, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269228.

Ziegel:1994:BRBd

[Zie94-45] Eric R. Ziegel. Book reviews: *Breakthrough in Statistics: Volume I, Foundations and Basic Theory* by S. Kotz; N. Johnson; *Breakthrough in Statistics: Volume II, Methodology and Distribution* by S. Kotz; N. Johnson. *Technometrics*, 36(1):125–126, February 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269225.

Ziegel:1995:BRBx

[Zie95a] Eric R. Ziegel. Book review: *A Handbook of Small Data Sets* by D. Hand; F. Daly; A. Lunn; K. McConway; E. Ostrowski. *Technometrics*, 37(2):242, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269650.

Ziegel:1995:BRBav

[Zie95b] Eric R. Ziegel. Book review: *A Step-by-Step Approach to Using the SAS System for Univariate and Multivariate Statistics* by L. Hatcher; E. Stepanski. *Technometrics*, 37(4):471, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269762.

Ziegel:1995:BRBw

[Zie95c] Eric R. Ziegel. Book review: *AI and Computer Power: The Impact of Statistics* by D. J. Hand. *Technometrics*, 37(2):241–242, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269649.

Ziegel:1995:BRBaj

[Zie95d] Eric R. Ziegel. Book review: *Analysis of Longitudinal Data* by P. Diggle; K. Liang; S. Zeger. *Technometrics*, 37(3):356, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269941`.

Ziegel:1995:BRBas

[Zie95e] Eric R. Ziegel. Book review: *Applied Econometric Time Series* by W. Enders. *Technometrics*, 37(4):469–470, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269759`.

Ziegel:1995:BRBf

[Zie95f] Eric R. Ziegel. Book review: *Artificial Intelligence Frontiers in Statistics* by D. Hand. *Technometrics*, 37(1):127, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269180`.

Ziegel:1995:BRBag

[Zie95g] Eric R. Ziegel. Book review: *Aspects of Uncertainty* by P. Freeman; A. Smith. *Technometrics*, 37(3):355, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269938`.

Ziegel:1995:BRBaw

[Zie95h] Eric R. Ziegel. Book review: *Biostatistics* by Wayne Daniel. *Technometrics*, 37(4):471, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269763`.

Ziegel:1995:BRBal

[Zie95i] Eric R. Ziegel. Book review: *Biostatistics for Epidemiologists* by A. Ahlbom. *Technometrics*, 37(3):357, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269943`.

Ziegel:1995:BRBi

[Zie95j] Eric R. Ziegel. Book review: *Design and Analysis of Ecological Experiments* by S. Scheiner; J. Gurevitch. *Technometrics*, 37(1):128, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269183`.

Ziegel:1995:BRBv

[Zie95k] Eric R. Ziegel. Book review: *Developing New Products with TQM* by C. Cervetz. *Technometrics*, 37(2):241, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269648.

Ziegel:1995:BRBg

[Zie95l] Eric R. Ziegel. Book review: *Developments in Time Series Analysis* by T. S. Rao. *Technometrics*, 37(1):127–128, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269181.

Ziegel:1995:BRBq

[Zie95m] Eric R. Ziegel. Book review: *Ecological Risk Assessment* by Glenn Suter. *Technometrics*, 37(2):240, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269643.

Ziegel:1995:BRBh

[Zie95n] Eric R. Ziegel. Book review: *Environmental Statistics, Assessment, and Forecasting* by C. R. Cothern; N. P. Ross. *Technometrics*, 37(1):128, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269182.

Ziegel:1995:BRBaq

[Zie95o] Eric R. Ziegel. Book review: *Extreme Value Theory and Applications* by J. Galambos; J. Lechner; E. Simiu. *Technometrics*, 37 (4):469, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269757.

Ziegel:1995:BRBab

[Zie95p] Eric R. Ziegel. Book review: *Four Days with Dr. Deming* by W. Latzko; D. Saunders. *Technometrics*, 37(3):353–354, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269933.

Ziegel:1995:BRBa

[Zie95q] Eric R. Ziegel. Book review: *Fourth Generation Management: The New Business Consciousness* by Brian Joiner. *Technometrics*, 37(1):113, February 1995. CODEN TCMTA2. ISSN 0040-

1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269158`.

Ziegel:1995:BRBae

[Zie95r] Eric R. Ziegel. Book review: *Geostatistics Troia '92* by A. Soares. *Technometrics*, 37(3):355, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269936`.

Ziegel:1995:BRBc

[Zie95s] Eric R. Ziegel. Book review: *GSLIB: Geostatistical Software Library and User's Guide* by C. Deutsch; A. Journel. *Technometrics*, 37(1):126, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269177`.

Ziegel:1995:BRBam

[Zie95t] Eric R. Ziegel. Book review: *Introduction to Life Prediction of Industrial Plant Materials* by M. Kowaka. *Technometrics*, 37(4): 457, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269739`.

Ziegel:1995:BRBad

[Zie95u] Eric R. Ziegel. Book review: *Mastering the SAS System* by Jay Jaffe. *Technometrics*, 37(3):354–355, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269935`.

Ziegel:1995:BRBe

[Zie95v] Eric R. Ziegel. Book review: *Mathematical Statistics and Data Analysis* by John Rice. *Technometrics*, 37(1):127, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269179`.

Ziegel:1995:BRBk

[Zie95w] Eric R. Ziegel. Book review: *Measuring Customer Satisfaction* by Bob Hayes. *Technometrics*, 37(1):128–129, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269185`.

Ziegel:1995:BRBj

[Zie95x] Eric R. Ziegel. Book review: *Modelling for Survival Data in Medical Research* by D. Collett. *Technometrics*, 37(1):128, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269184.

Ziegel:1995:BRBd

[Zie95y] Eric R. Ziegel. Book review: *Near Infra-Red Spectroscopy: Bridging the Gap between Data Analysis and NIR Applications* by K. Hildrum; T. Isaksson; T. Naes; A. Tandberg. *Technometrics*, 37(1):126–127, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269178.

Ziegel:1995:BRBb

[Zie95z] Eric R. Ziegel. Book review: *Pierre Gy's Sampling Theory and Sampling Practice* by Francis Pitard; Pierre Gy. *Technometrics*, 37(1):125–126, February 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269176.

Ziegel:1995:BRBt

[Zie95-27] Eric R. Ziegel. Book review: *Practical Biostatistical Methods* by Steve Selvin. *Technometrics*, 37(2):241, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269646.

Ziegel:1995:BRBo

[Zie95-28] Eric R. Ziegel. Book review: *Probability and Statistics for Engineers* by R. Scheaffer; J. McClave. *Technometrics*, 37(2):239, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269641.

Ziegel:1995:BRBai

[Zie95-29] Eric R. Ziegel. Book review: *Proceedings of the First U.S./Japan Conference on the Frontiers of Statistical Modeling: An Informational Approach* by H. Bozdogan. *Technometrics*, 37(3):356, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269940.

Ziegel:1995:BRBac

[Zie95-30] Eric R. Ziegel. Book review: *Quality by Experimental Design* by Thomas Barker. *Technometrics*, 37(3):354, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269934.

Ziegel:1995:BRBap

[Zie95-31] Eric R. Ziegel. Book review: *Quality Management: Tools and Methods for Improvement* by H. Gitlow; A. Oppenheim; R. Oppenheim. *Technometrics*, 37(4):468–469, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269756.

Ziegel:1995:BRBau

[Zie95-32] Eric R. Ziegel. Book review: *SAS Software Roadmaps* by L. Burch; S. King. *Technometrics*, 37(4):470–471, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269761.

Ziegel:1995:BRBaf

[Zie95-33] Eric R. Ziegel. Book review: *Selecting Models from Data* by P. Cheeseman; R. Oldford. *Technometrics*, 37(3):355, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269937.

Ziegel:1995:BRBu

[Zie95-34] Eric R. Ziegel. Book review: *SPC in Extrusion* by Chris Rauwendaal. *Technometrics*, 37(2):241, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269647.

Ziegel:1995:BRBan

[Zie95-35] Eric R. Ziegel. Book review: *SPC Made Easy* by Peter McReynolds. *Technometrics*, 37(4):462–463, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269747.

Ziegel:1995:BRBs

[Zie95-36] Eric R. Ziegel. Book review: *Statistical Analysis of Epidemiological Data* by Steve Selvin. *Technometrics*, 37(2):240–241, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269645.

Ziegel:1995:BRBl

[Zie95-37] Eric R. Ziegel. Book review: *Statistical Methods for Groundwater Monitoring* by Robert Gibbons. *Technometrics*, 37(2):231–232, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269628.

Ziegel:1995:BRBar

[Zie95-38] Eric R. Ziegel. Book review: *Statistical Methods for Physical Science* by J. Stanford; S. Vardeman. *Technometrics*, 37(4):469, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269758.

Ziegel:1995:BRBr

[Zie95-39] Eric R. Ziegel. Book review: *Statistical Models in Epidemiology* by D. Clayton; M. Hills. *Technometrics*, 37(2):240, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269644.

Ziegel:1995:BRBax

[Zie95-40] Eric R. Ziegel. Book review: *Statistics for Accountants* by S. Letchford. *Technometrics*, 37(4):471, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269764.

Ziegel:1995:BRBak

[Zie95-41] Eric R. Ziegel. Book review: *Statistics in Toxicology* by D. Krewski; C. Franklin. *Technometrics*, 37(3):356–357, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269942.

Ziegel:1995:BRBah

[Zie95-42] Eric R. Ziegel. Book review: *Subjective Probability* by G. Wright; P. Ayton. *Technometrics*, 37(3):355–356, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269939.

Ziegel:1995:BRBz

[Zie95-43] Eric R. Ziegel. Book review: *The Collected Works of John Tukey: Volume VIII, Multiple Comparisons* by H. Braun; John Tukey. *Technometrics*, 37(2):242, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269652.

Ziegel:1995:BRBy

[Zie95-44] Eric R. Ziegel. Book review: *The Handbook of Research Synthesis* by H. Cooper; L. Hedges. *Technometrics*, 37(2):242, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269651.

Ziegel:1995:BRBao

[Zie95-45] Eric R. Ziegel. Book review: *The Quality Toolbox* by Nancy Tague. *Technometrics*, 37(4):468, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269755.

Ziegel:1995:BRBn

[Zie95-46] Eric R. Ziegel. Book review: *Time Series Analysis, Forecasting, and Control* by G. Box; G. Jenkins; G. Reinsel. *Technometrics*, 37(2):238–239, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269640.

Ziegel:1995:BRBm

[Zie95-47] Eric R. Ziegel. Book review: *Uncertainty* by M. Morgan; M. Henrion. *Technometrics*, 37(2):237–238, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269639.

Ziegel:1995:BRBaa

[Zie95-48] Eric R. Ziegel. Book review: *Weibull Analysis* by Bryan Dodson. *Technometrics*, 37(3):347–348, August 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269925.

Ziegel:1995:BRBat

[Zie95-49] Eric R. Ziegel. Book reviews: *Neural Networks in Computer Intelligence* by L. Fu; *Fundamentals of Neural Networks* by L. Fausett. *Technometrics*, 37(4):470, November 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269760.

Ziegel:1995:BRBp

[Zie95-50] Eric R. Ziegel. Book reviews: *Statistics for Business: Data Analysis and Modelling* by J. Cryer; R. Miller; *Introduction to Modern Business Statistics* by G. Canavos; D. Miller; *Introductory*

Business Statistics with Computer Applications by R. Shiffler; A. Adams; *Statistics for Business and Economics* by P. Mann. *Technometrics*, 37(2):239–240, May 1995. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269642.

Ziegel:1996:BRBaz

[Zie96a] Eric R. Ziegel. Book review: *Advances in Stochastic Modelling and Data Analysis* by J. Janssen; C. Skiadas; C. Zopounidis. *Technometrics*, 38(4):414, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271338.

Ziegel:1996:BRBaf

[Zie96b] Eric R. Ziegel. Book review: *Analysing Survival Data from Clinical Trials and Observational Studies* by E. Marubini; M. Valsecchi. *Technometrics*, 38(3):299, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270634.

Ziegel:1996:BRBq

[Zie96c] Eric R. Ziegel. Book review: *Applied Logistic Regression Analysis* by Scott Menard. *Technometrics*, 38(2):192, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270433.

Ziegel:1996:BRBai

[Zie96d] Eric R. Ziegel. Book review: *Applied Multivariate for Statistics with SAS(R) Software* by R. Khattree; D. Naik. *Technometrics*, 38(3):300, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270637.

Ziegel:1996:BRBap

[Zie96e] Eric R. Ziegel. Book review: *Bayesian Methods in Reliability* by P. Sander; R. Badoux. *Technometrics*, 38(4):411, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271328.

Ziegel:1996:BRBu

[Zie96f] Eric R. Ziegel. Book review: *Business Process Benchmarking* by Robert Camp. *Technometrics*, 38(2):193, May 1996. CODEN

TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270437.

Ziegel:1996:BRBh

[Zie96g] Eric R. Ziegel. Book review: *Business Survey Methods* by B. Cox; D. Binder; B. Chinnappa; A. Christianson; M. Colledge; P. Kott. *Technometrics*, 38(1):89, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268928.

Ziegel:1996:BRBaw

[Zie96h] Eric R. Ziegel. Book review: *Case Studies in Bayesian Statistics, Volume II* by C. Gatsonis; J. Hodges; R. Kass; N. Singpurwalla. *Technometrics*, 38(4):413, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271335.

Ziegel:1996:BRBav

[Zie96i] Eric R. Ziegel. Book review: *Categorical Data Analysis Using the SAS System* by M. Stokes; C. Davis; G. Koch. *Technometrics*, 38(4):413, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271334.

Ziegel:1996:BRBat

[Zie96j] Eric R. Ziegel. Book review: *Chemometrics in Environmental Chemistry: Statistical Methods* by J. Einax. *Technometrics*, 38 (4):412, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271332.

Ziegel:1996:BRBe

[Zie96k] Eric R. Ziegel. Book review: *Customer-Focused Quality* by N. Mowery; P. Reavis; S. Poling. *Technometrics*, 38(1):87, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268925.

Ziegel:1996:BRBs

[Zie96l] Eric R. Ziegel. Book review: *Data Analysis Handbook* by Ildiko Frank; Roberto Todeschini. *Technometrics*, 38(2):193, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270435.

Ziegel:1996:BRBa

[Zie96m] Eric R. Ziegel. Book review: *Data Analysis Using Microsoft Excel 5.0* by Michael Middleton. *Technometrics*, 38(1):78–79, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268909`.

Ziegel:1996:BRBam

[Zie96n] Eric R. Ziegel. Book review: *Decisions Involving Uncertainty* by James Murtha. *Technometrics*, 38(4):408, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271322`.

Ziegel:1996:BRBad

[Zie96o] Eric R. Ziegel. Book review: *Encyclopedia of Quality Terms and Concepts* by J. Cortada; J. Woods. *Technometrics*, 38(3):298, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270632`.

Ziegel:1996:BRBm

[Zie96p] Eric R. Ziegel. Book review: *Environmental Statistics* by G. Patil; C. Rao. *Technometrics*, 38(2):190–191, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270429`.

Ziegel:1996:BRBae

[Zie96q] Eric R. Ziegel. Book review: *Fundamentals of Quality Auditing* by B. Parsowith. *Technometrics*, 38(3):298–299, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270633`.

Ziegel:1996:BRBo

[Zie96r] Eric R. Ziegel. Book review: *Geostatistics for the Next Century* by R. Dimitrakopoulos. *Technometrics*, 38(2):191–192, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270431`.

Ziegel:1996:BRBp

[Zie96s] Eric R. Ziegel. Book review: *Growth Curves* by A. M. Kshirsagar; W. B. Smith. *Technometrics*, 38(2):192, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270432`.

Ziegel:1996:BRBah

[Zie96t] Eric R. Ziegel. Book review: *Image Analysis for the Biological Sciences* by C. Glasbey; C. Horgan. *Technometrics*, 38(3):299, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270636.

Ziegel:1996:BRBr

[Zie96u] Eric R. Ziegel. Book review: *Interpreting Probability Models* by T. Lao. *Technometrics*, 38(2):192–193, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270434.

Ziegel:1996:BRBy

[Zie96v] Eric R. Ziegel. Book review: *Introduction to Biostatistics* by R. Forthofer; E. Lee. *Technometrics*, 38(2):195, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270441.

Ziegel:1996:BRBak

[Zie96w] Eric R. Ziegel. Book review: *Introduction to Market Research Using the SAS(R) System* by *SAS Staff*. *Technometrics*, 38(3):300–301, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270639.

Ziegel:1996:BRBb

[Zie96x] Eric R. Ziegel. Book review: *Logistic Regression Examples Using the SAS System* by *SAS Institute Staff*. *Technometrics*, 38 (1):86–87, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268922.

Ziegel:1996:BRBz

[Zie96y] Eric R. Ziegel. Book review: *Managing Customer Value* by Bradley Gale. *Technometrics*, 38(3):295–296, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270627.

Ziegel:1996:BRBv

[Zie96z] Eric R. Ziegel. Book review: *Managing Quality* by B. Dale. *Technometrics*, 38(2):194, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270438.

Ziegel:1996:BRBay

[Zie96-27] Eric R. Ziegel. Book review: *Monte Carlo and Quasi-Monte Carlo Methods in Scientific Computing* by H. Niederreiter; P. Shiue. *Technometrics*, 38(4):414, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271337`.

Ziegel:1996:BRBag

[Zie96-28] Eric R. Ziegel. Book review: *Observational Studies* by Paul Rosenbaum. *Technometrics*, 38(3):299, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270635`.

Ziegel:1996:BRBj

[Zie96-29] Eric R. Ziegel. Book review: *Practical Methods for Design and Analysis of Complex Surveys* by R. Lehtonen; E. Pahkinen. *Technometrics*, 38(1):89–90, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268930`.

Ziegel:1996:BRBal

[Zie96-30] Eric R. Ziegel. Book review: *Probability, Statistics and Optimization* by F. Kelly. *Technometrics*, 38(3):301, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270640`.

Ziegel:1996:BRBaq

[Zie96-31] Eric R. Ziegel. Book review: *Problem Solving: A Statistician's Guide* by C. Chatfield. *Technometrics*, 38(4):411, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271329`.

Ziegel:1996:BRBac

[Zie96-32] Eric R. Ziegel. Book review: *Quality Function Deployment* by L. Cohen. *Technometrics*, 38(3):298, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270631`.

Ziegel:1996:BRBc

[Zie96-33] Eric R. Ziegel. Book review: *Quick Results with SAS/Graph Software* by A. Carpenter; C. Shipp. *Technometrics*, 38(1):87, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268923`.

Ziegel:1996:BRBab

[Zie96-34] Eric R. Ziegel. Book review: *Recent Advances in Life Testing and Reliability* by N. Balakrishnan. *Technometrics*, 38(3):297–298, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270630.

Ziegel:1996:BRBd

[Zie96-35] Eric R. Ziegel. Book review: *Reliability-Centered Maintenance* by John Moubray. *Technometrics*, 38(1):87, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268924.

Ziegel:1996:BRBx

[Zie96-36] Eric R. Ziegel. Book review: *SAS Programming by Example* by R. Cody; R. Pass. *Technometrics*, 38(2):194–195, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270440.

Ziegel:1996:BRBan

[Zie96-37] Eric R. Ziegel. Book review: *Statistical Applications in Process Control* by J. B. Keats; D. C. Montgomery. *Technometrics*, 38 (4):410, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271326.

Ziegel:1996:BRBn

[Zie96-38] Eric R. Ziegel. Book review: *Statistical Data Analysis for Ocean and Atmospheric Sciences* by H. Jean Thiebaux. *Technometrics*, 38(2):191, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270430.

Ziegel:1996:BRBk

[Zie96-39] Eric R. Ziegel. Book review: *Statistical Design and Analysis in Pharmaceutical Science* by S. Chow; J. Liu. *Technometrics*, 38(1):90, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268931.

Ziegel:1996:BRBax

[Zie96-40] Eric R. Ziegel. Book review: *Statistical Modelling* by G. Seeber; B. Francis; R. Hatzinger; G. Stechel-Berger. *Technometrics*, 38

(4):413–414, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271336.

Ziegel:1996:BRBao

[Zie96-41] Eric R. Ziegel. Book review: *Statistical Process Control* by C. Mamzic. *Technometrics*, 38(4):410–411, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271327.

Ziegel:1996:BRBl

[Zie96-42] Eric R. Ziegel. Book review: *Statistics and the Evaluation of Evidence for Forensic Scientists* by C. G. G. Aitken. *Technometrics*, 38(1):90–91, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268932.

Ziegel:1996:BRBau

[Zie96-43] Eric R. Ziegel. Book review: *Statistics in Epidemiology* by H. Sahai; A. Khurshid. *Technometrics*, 38(4):412–413, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271333.

Ziegel:1996:BRBar

[Zie96-44] Eric R. Ziegel. Book review: *Stochastic Modeling and Geostatistics* by J. Yarus; R. Chambers. *Technometrics*, 38(4):411–412, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271330.

Ziegel:1996:BRBaj

[Zie96-45] Eric R. Ziegel. Book review: *The How-To Book for SAS/Graph Software* by Thomas Miron. *Technometrics*, 38(3):300, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270638.

Ziegel:1996:BRBt

[Zie96-46] Eric R. Ziegel. Book review: *The Malcolm Baldrige National Quality Award* by M. Heaphy; G. Gruska. *Technometrics*, 38(2):193, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270436.

Ziegel:1996:BRBaa

[Zie96-47] Eric R. Ziegel. Book review: *The Survey Kit (Partial: Volumes 2, 5, 6, 8)* by Arlene Fink. *Technometrics*, 38(3):297, August 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270629`.

Ziegel:1996:BRBi

[Zie96-48] Eric R. Ziegel. Book review: *Understanding Industrial Designed Experiments* by S. Schmidt; R. Launsby. *Technometrics*, 38(1): 89, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268929`.

Ziegel:1996:BRBw

[Zie96-49] Eric R. Ziegel. Book review: *Understanding Neural Networks* by M. Caudill; C. Butler. *Technometrics*, 38(2):194, May 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270439`.

Ziegel:1996:BRBas

[Zie96-50] Eric R. Ziegel. Book review: *Variowin: Software for Spatial Data Analysis* by Y. Pannatier. *Technometrics*, 38(4):412, November 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271331`.

Ziegel:1996:BRBf

[Zie96-51] Eric R. Ziegel. Book review: *Winning with Quality* by J. Wesner; J. Hiatt; D. Trimble. *Technometrics*, 38(1):87–88, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268926`.

Ziegel:1996:BRBg

[Zie96-52] Eric R. Ziegel. Book reviews: *Statistics for Business* by J. Cryer; R. Miller; *Statistics for Managers* by U. Menzefricke; *Business Statistics for Quality and Productivity* by D. Levine; P. Ramsey; M. Berenson. *Technometrics*, 38(1):88, February 1996. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268927`.

Ziegel:1997:BRBr

[Zie97a] Eric R. Ziegel. Book review: *A Toolbox for Quality Improvement and Problem Solving* by D. Straker. *Technometrics*, 39(2):238, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270933.

Ziegel:1997:BRBaa

[Zie97b] Eric R. Ziegel. Book review: *Basic Principles of Structural Equation Modelling* by R. Mueller. *Technometrics*, 39(3):343, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271158.

Ziegel:1997:BRBg

[Zie97c] Eric R. Ziegel. Book review: *Bayesian Analysis in Statistics and Econometrics* by D. Berry; K. Chaloner; J. Geweke. *Technometrics*, 39(1):111, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270799.

Ziegel:1997:BRBh

[Zie97d] Eric R. Ziegel. Book review: *Bayesian Biostatistics* by D. Berry; D. Stangl. *Technometrics*, 39(1):111–112, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270800.

Ziegel:1997:BRBam

[Zie97e] Eric R. Ziegel. Book review: *Bayesian Forecasting and Dynamic Models* by M. West; J. Harrison. *Technometrics*, 39(4):433, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271526.

Ziegel:1997:BRBao

[Zie97f] Eric R. Ziegel. Book review: *Cases in Managerial Data Analysis* by W. Carlson. *Technometrics*, 39(4):434, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271528.

Ziegel:1997:BRBp

[Zie97g] Eric R. Ziegel. Book review: *Computational Modeling* by C. Taber; R. Timpone. *Technometrics*, 39(2):238, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270931.

Ziegel:1997:BRBab

[Zie97h] Eric R. Ziegel. Book review: *Computer-Aided Multivariate Analysis* by A. Afifi; V. Clark. *Technometrics*, 39(3):343, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271156`.

Ziegel:1997:BRBv

[Zie97i] Eric R. Ziegel. Book review: *Customer Satisfaction Measurement and Management* by E. Naumann; K. Giel. *Technometrics*, 39(2):239–240, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270937`.

Ziegel:1997:BRBm

[Zie97j] Eric R. Ziegel. Book review: *Data Analysis with Microsoft Excel 5.0 for Windows* by K. Berk; P. Carey. *Technometrics*, 39(2):237, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270928`.

Ziegel:1997:BRBu

[Zie97k] Eric R. Ziegel. Book review: *Design and Management of Service Processes* by R. Ramaswamy. *Technometrics*, 39(2):239, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270936`.

Ziegel:1997:BRBal

[Zie97l] Eric R. Ziegel. Book review: *Elements of Multivariate Time Series Analysis* by Gregory Reinsel. *Technometrics*, 39(4):433, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271525`.

Ziegel:1997:BRBaf

[Zie97m] Eric R. Ziegel. Book review: *Forecasting Examples for Business and Economics Using the SAS(R) System* by *SAS Staff*. *Technometrics*, 39(3):345, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271162`.

Ziegel:1997:BRBz

[Zie97n] Eric R. Ziegel. Book review: *Geostatistical Simulations* by M. Armstrong; P. Dowd. *Technometrics*, 39(3):343, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271157`.

Ziegel:1997:BRBe

[Zie97o] Eric R. Ziegel. Book review: *Glossary and Tables for Statistical Quality Control* by *ASQC Statistics Division*. *Technometrics*, 39(1):111, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270797.

Ziegel:1997:BRBaq

[Zie97p] Eric R. Ziegel. Book review: *Handbook of Statistical Analysis Using SAS* by B. Everitt; G. Der. *Technometrics*, 39(4):434, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271530.

Ziegel:1997:BRBl

[Zie97q] Eric R. Ziegel. Book review: *Improving Survey Questions* by F. Fowler. *Technometrics*, 39(1):113, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270804.

Ziegel:1997:BRBai

[Zie97r] Eric R. Ziegel. Book review: *Lifetime Data Models in Reliability and Survival Analysis* by N. Jewell; A. Kimber; M. Lee; G. Whitmore. *Technometrics*, 39(4):432, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271522.

Ziegel:1997:BRBah

[Zie97s] Eric R. Ziegel. Book review: *Measuring and Managing Customer Satisfaction* by Sheila Kessler. *Technometrics*, 39(3):345–346, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271164.

Ziegel:1997:BRBi

[Zie97t] Eric R. Ziegel. Book review: *Practical Longitudinal Data Analysis* by D. Hand; M. Crowder. *Technometrics*, 39(1):112, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270801.

Ziegel:1997:BRBan

[Zie97u] Eric R. Ziegel. Book review: *Process Redesign* by A. Tenner; I. DeToro. *Technometrics*, 39(4):433–434, November 1997. CODEN

TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271527.

Ziegel:1997:BRBf

[Zie97v] Eric R. Ziegel. Book review: *Process Validation for Business Success* by A. Elfe; J. Lahey; R. Launsby. *Technometrics*, 39(1): 111, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270798.

Ziegel:1997:BRBs

[Zie97w] Eric R. Ziegel. Book review: *Quality Planning, Control, and Improvement in Research and Development* by George Roberts. *Technometrics*, 39(2):238–239, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270934.

Ziegel:1997:BRBap

[Zie97x] Eric R. Ziegel. Book review: *Quick Start to Data Analysis with SAS* by F. Di Iorio; K. Hardy. *Technometrics*, 39(4):434, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271529.

Ziegel:1997:BRBw

[Zie97y] Eric R. Ziegel. Book review: *Response Surfaces: Designs and Analyses* by Andre Khuri; John Cornell. *Technometrics*, 39(3): 342, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271153.

Ziegel:1997:BRBo

[Zie97z] Eric R. Ziegel. Book review: *Robust Statistics, Data Analysis, and Computer Intensive Methods* by H. Rieder. *Technometrics*, 39 (2):238, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270930.

Ziegel:1997:BRBad

[Zie97-27] Eric R. Ziegel. Book review: *SAS(R) System for Mixed Models* by R. Littell; G. Milliken; W. Stroup; R. Wolfinger. *Technometrics*, 39(3):344, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271160.

Ziegel:1997:BRBak

[Zie97-28] Eric R. Ziegel. Book review: *Simulation* by S. M. Ross. *Technometrics*, 39(4):433, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271524.

Ziegel:1997:BRBag

[Zie97-29] Eric R. Ziegel. Book review: *Simulation Modeling Using @Risk* by Wayne Winston. *Technometrics*, 39(3):345, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271163.

Ziegel:1997:BRBq

[Zie97-30] Eric R. Ziegel. Book review: *Spatial Analysis and GIS* by S. Fotheringham; Peter Rogerson. *Technometrics*, 39(2):238, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270932.

Ziegel:1997:BRBt

[Zie97-31] Eric R. Ziegel. Book review: *Specifications for the Chemical and Process Industries* by *ASQC Chemical Interest Committee*. *Technometrics*, 39(2):239, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270935.

Ziegel:1997:BRBac

[Zie97-32] Eric R. Ziegel. Book review: *Statistical Quality Control Using the SAS(R) System* by Dennis King. *Technometrics*, 39(3):343–344, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271159.

Ziegel:1997:BRBb

[Zie97-33] Eric R. Ziegel. Book review: *Statistics and Data Analysis* by Andrew Siegel; Charles Morgan. *Technometrics*, 39(1):110, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270794.

Ziegel:1997:BRBaj

[Zie97-34] Eric R. Ziegel. Book review: *Statistics of Quality* by S. Ghosh; W. Schucany; W. Smith. *Technometrics*, 39(4):432–433, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271523.

Ziegel:1997:BRBd

[Zie97-35] Eric R. Ziegel. Book review: *Statistics: Theory and Methods* by Donald Berry; Bernard Lindgren. *Technometrics*, 39(1):110–111, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270796.

Ziegel:1997:BRBar

[Zie97-36] Eric R. Ziegel. Book review: *Stock Market Analysis Using the SAS System: Technical Analysis* by *SAS Staff*. *Technometrics*, 39(4):434–435, November 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271531.

Ziegel:1997:BRBj

[Zie97-37] Eric R. Ziegel. Book review: *Survival Analysis* by M. Parmar; D. Machin. *Technometrics*, 39(1):112–113, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270802.

Ziegel:1997:BRBae

[Zie97-38] Eric R. Ziegel. Book review: *Survival Analysis Using the SAS System* by Paul D. Allison. *Technometrics*, 39(3):344–345, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271161.

Ziegel:1997:BRBa

[Zie97-39] Eric R. Ziegel. Book review: *Taguchi Techniques for Quality Engineering* by Phillip Ross. *Technometrics*, 39(1):109–110, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270793.

Ziegel:1997:BRBy

[Zie97-40] Eric R. Ziegel. Book review: *The Analysis of Time Series* by Chris Chatfield. *Technometrics*, 39(3):342–343, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271155.

Ziegel:1997:BRBn

[Zie97-41] Eric R. Ziegel. Book review: *The Elements of Graphing Data* by William S. Cleveland. *Technometrics*, 39(2):237–238, May 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270929.

Ziegel:1997:BRBc

[Zie97-42] Eric R. Ziegel. Book review: *Time Series Models* by D. R. Cox; D. V. Hinkley; O. E. Barndorff-Nielsen. *Technometrics*, 39(1): 110, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270795`.

Ziegel:1997:BRBk

[Zie97-43] Eric R. Ziegel. Book review: *Wavelets and Statistics* by A. Antoniadis; G. Oppenheim. *Technometrics*, 39(1):113, February 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270803`.

Ziegel:1997:BRBx

[Zie97-44] Eric R. Ziegel. Book reviews: *Applied Linear Statistical Models* by J. Neter; M. Kutner; C. Nachtsheim; W. Wasserman; *Applied Linear Regression Models* by J. Neter; M. Kutner; C. Nachtsheim; W. Wasserman. *Technometrics*, 39(3):342, August 1997. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271154`.

Ziegel:1998:BRBaj

[Zie98a] Eric R. Ziegel. Book review: *A First Course in Probability* by Sheldon Ross. *Technometrics*, 40(3):268, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271207`.

Ziegel:1998:BRBx

[Zie98b] Eric R. Ziegel. Book review: *A Probabilistic Analysis of the Sacco and Vanzetti Evidence* by Joseph B. Kadane; David A. Schum. *Technometrics*, 40(2):166, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270674`.

Ziegel:1998:BRBe

[Zie98c] Eric R. Ziegel. Book review: *Advances in Knowledge Discovery and Data Mining* by Usama M. Fayyad; Gregory Piatetski-Shapiro; Padhraic Smyth; Ramasamy Uthurusamy. *Technometrics*, 40(1):83, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271414`.

Ziegel:1998:BRBt

[Zie98d] Eric R. Ziegel. Book review: *Advances in Statistical Decision Theory and Applications* by S. Panchapakesan; N. Balakrishnan. *Technometrics*, 40(2):165, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270670.

Ziegel:1998:BRBu

[Zie98e] Eric R. Ziegel. Book review: *Advances in the Theory and Practice of Statistics* by Norman L. Johnson; N. Balakrishnan. *Technometrics*, 40(2):165, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270671.

Ziegel:1998:BRBf

[Zie98f] Eric R. Ziegel. Book review: *Applications of Computer Aided Time Series Modeling* by Masanao Aoki; Arthur M. Havenner. *Technometrics*, 40(1):83, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271415.

Ziegel:1998:BRBn

[Zie98g] Eric R. Ziegel. Book review: *Applications of Time Series Analysis in Astronomy and Meteorology* by T. Subba Rao; M. B. Priestly; O. Lessi. *Technometrics*, 40(2):163, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270664.

Ziegel:1998:BRBae

[Zie98h] Eric R. Ziegel. Book review: *Applied Statistics and the SAS Programming Language* by Ronald P. Cody; Jeffrey K. Smith. *Technometrics*, 40(3):266–267, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271202.

Ziegel:1998:BRBq

[Zie98i] Eric R. Ziegel. Book review: *Bayesian Computation Using Minitab* by James H. Albert. *Technometrics*, 40(2):164, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270667.

Ziegel:1998:BRBao

[Zie98j] Eric R. Ziegel. Book review: *Bayesian Statistics: An Introduction* by Peter M. Lee. *Technometrics*, 40(4):358, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270551.

Ziegel:1998:BRBv

[Zie98k] Eric R. Ziegel. Book review: *Breakthroughs in Statistics, Volume III* by Samuel Kotz; Norman L. Johnson. *Technometrics*, 40 (2):165, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270672.

Ziegel:1998:BRBh

[Zie98l] Eric R. Ziegel. Book review: *Case Studies in Bayesian Statistics, Volume III* by Constantine Gatsonis; James S. Hodges; Robert E. Kass; Robert McCulloch; Peter Rossi; Nozer D. Singpurwalla. *Technometrics*, 40(1):84, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271417.

Ziegel:1998:BRBi

[Zie98m] Eric R. Ziegel. Book review: *Chemometrics in Environmental Analysis* by J. W. Einax; H. W. Zwanziger; S. Geiss. *Technometrics*, 40(1):84, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271418.

Ziegel:1998:BRBap

[Zie98n] Eric R. Ziegel. Book review: *Data, Statistics, and Decisions Models with Excel* by Donald L. Harnett; James F. Horrell. *Technometrics*, 40(4):358, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270552.

Ziegel:1998:BRBa

[Zie98o] Eric R. Ziegel. Book review: *Encyclopedia of Statistical Sciences, Update Volume 1* by S. Kotz; C. Read; D. Banks. *Technometrics*, 40(1):81–82, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271410.

Ziegel:1998:BRBas

[Zie98p] Eric R. Ziegel. Book review: *Encyclopedia of Statistical Sciences: Update Volume 2* by S. Kotz; C. Read; D. Banks. *Technometrics*, 40(4):359, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270555`.

Ziegel:1998:BRBar

[Zie98q] Eric R. Ziegel. Book review: *Evolutionary Operation: A Statistical Method for Process Improvement* by George Box; Norman R. Draper. *Technometrics*, 40(4):359, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270554`.

Ziegel:1998:BRBr

[Zie98r] Eric R. Ziegel. Book review: *Extending SAS(R) Survival Analysis Techniques for Medical Research* by Alan Cantor. *Technometrics*, 40(2):164, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270668`.

Ziegel:1998:BRBam

[Zie98s] Eric R. Ziegel. Book review: *GeoENV1*: Geostatistics for Environmental Applications by A. Soares; J. Gomez-Hernandez; R. Froidevaux. *Technometrics*, 40(4):357–358, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270549`.

Ziegel:1998:BRBal

[Zie98t] Eric R. Ziegel. Book review: *Geostatistical Software Library and User's Guide* by Clayton V. Deutsch; Andre G. Journel. *Technometrics*, 40(4):357, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270548`.

Ziegel:1998:BRBz

[Zie98u] Eric R. Ziegel. Book review: *Geostatistics Wollongong '96* by E. Y. Baafi; N. A. Schofield. *Technometrics*, 40(3):265, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271197`.

Ziegel:1998:BRBav

[Zie98v] Eric R. Ziegel. Book review: *Getting Started with the Market Research Application* by Donna M. Sawyer; Maura Stokes. *Technometrics*, 40(4):360, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270558.

Ziegel:1998:BRBy

[Zie98w] Eric R. Ziegel. Book review: *Handbook of Chemometrics and Qualimetrics: Part A* by D. Massart; B. Vandeginote; L. Buydens; S. DeJong; P. Lewi; J. Smeyers-Verbeke. *Technometrics*, 40(3):264–265, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271196.

Ziegel:1998:BRBs

[Zie98x] Eric R. Ziegel. Book review: *Industrial Statistics* by C. Kitsos; L. Edler. *Technometrics*, 40(2):164–165, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270669.

Ziegel:1998:BRBan

[Zie98y] Eric R. Ziegel. Book review: *Introduction to Chemical Exposure and Risk Assessment* by W. Brock Neely. *Technometrics*, 40(4): 358, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270550.

Ziegel:1998:BRBw

[Zie98z] Eric R. Ziegel. Book review: *Leading Personalities in Statistical Science* by Norman L. Johnson; Samuel Kotz. *Technometrics*, 40(2):165–166, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270673.

Ziegel:1998:BRBai

[Zie98-27] Eric R. Ziegel. Book review: *Log-Linear Models and Logistic Regression* by Ronald Christensen. *Technometrics*, 40(3):267–268, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271206.

Ziegel:1998:BRBl

[Zie98-28] Eric R. Ziegel. Book review: *Log-Linear Models for Event Histories* by J. Vermunt. *Technometrics*, 40(1):85, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271421.

Ziegel:1998:BRBat

[Zie98-29] Eric R. Ziegel. Book review: *Loss Models* by S. Klugman; H. Panju; G. Willmot. *Technometrics*, 40(4):359, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270556.

Ziegel:1998:BRBp

[Zie98-30] Eric R. Ziegel. Book review: *Matrix Algebra from a Statistician's Perspective* by David A. Harville. *Technometrics*, 40(2):164, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270666.

Ziegel:1998:BRBb

[Zie98-31] Eric R. Ziegel. Book review: *Measuring Customer Satisfaction* by Bob Hayes. *Technometrics*, 40(1):82, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271411.

Ziegel:1998:BRBah

[Zie98-32] Eric R. Ziegel. Book review: *Monte Carlo Simulation* by C. Mooney. *Technometrics*, 40(3):267, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271205.

Ziegel:1998:BRBc

[Zie98-33] Eric R. Ziegel. Book review: *Practical Handbook of Spatial Statistics* by S. Arlinghaus. *Technometrics*, 40(1):82, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271412.

Ziegel:1998:BRBaf

[Zie98-34] Eric R. Ziegel. Book review: *Proceedings in Computational Statistics* by Albert Prat. *Technometrics*, 40(3):267, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271203.

Ziegel:1998:BRBaq

[Zie98-35] Eric R. Ziegel. Book review: *Quality Improvement through Statistical Methods* by Bovas Abraham. *Technometrics*, 40(4):358–359, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270553`.

Ziegel:1998:BRBj

[Zie98-36] Eric R. Ziegel. Book review: *Randomization, Bootstrap and Monte Carlo Methods in Biology* by B. Manly. *Technometrics*, 40(1):84, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271419`.

Ziegel:1998:BRBo

[Zie98-37] Eric R. Ziegel. Book review: *Randomization Tests* by E. Edgington. *Technometrics*, 40(2):163, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270665`.

Ziegel:1998:BRBak

[Zie98-38] Eric R. Ziegel. Book review: *S+ Spatial Stats* by S. Kaluzny; S. Vega; T. Cardoso; A. Shelley. *Technometrics*, 40(4):357, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270547`.

Ziegel:1998:BRBad

[Zie98-39] Eric R. Ziegel. Book review: *Spreadsheet Modeling and Decision Analysis* by C. Ragsdale. *Technometrics*, 40(3):266, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271201`.

Ziegel:1998:BRBm

[Zie98-40] Eric R. Ziegel. Book review: *Statistical Case Studies for Industrial Process Improvement* by Veronica Czitrom; Patrick D. Spagon. *Technometrics*, 40(2):163, May 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270663`.

Ziegel:1998:BRBag

[Zie98-41] Eric R. Ziegel. Book review: *Statistical Theory and Computational Aspects of Smoothing* by W. Härdle; M. G. Schimek. *Technomet-*

rics, 40(3):267, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271204.

Ziegel:1998:BRBaa

[Zie98-42] Eric R. Ziegel. Book review: *Statistics for Environmental Biology and Toxicology* by Walter W. Piegorsch; A. John Bailar. *Technometrics*, 40(3):265–266, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271198.

Ziegel:1998:BRBg

[Zie98-43] Eric R. Ziegel. Book review: *Survey Measurement and Process Quality* by L. Lyberg; P. Biemer; M. Collins; E. de Leeuw; C. Dippo; N. Schwartz; D. Trewin. *Technometrics*, 40(1):83–84, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271416.

Ziegel:1998:BRBk

[Zie98-44] Eric R. Ziegel. Book review: *Survival Analysis with Long-Term Survivors* by R. Maller; X. Zhou. *Technometrics*, 40(1):85, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271420.

Ziegel:1998:BRBab

[Zie98-45] Eric R. Ziegel. Book review: *The Balanced Scorecard* by R. Kaplan; D. Norton. *Technometrics*, 40(3):266, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271199.

Ziegel:1998:BRBd

[Zie98-46] Eric R. Ziegel. Book review: *The Basics of S and S-PLUS* by Andreas Krause; Melvin Olson. *Technometrics*, 40(1):82–83, February 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271413.

Ziegel:1998:BRBau

[Zie98-47] Eric R. Ziegel. Book review: *The Robust Organization* by William Stinson. *Technometrics*, 40(4):359–360, November 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270557.

Ziegel:1998:BRBac

[Zie98-48] Eric R. Ziegel. Book review: *Value Leadership* by Michael Harris. *Technometrics*, 40(3):266, August 1998. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271200.

Ziegel:1999:BRBl

[Zie99a] Eric R. Ziegel. Book review: *101 Good Ideas: How to Improve Just about Any Process* by Karen Bemowski; Brad Stratton. *Technometrics*, 41(1):84–85, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271021.

Ziegel:1999:BRBm

[Zie99b] Eric R. Ziegel. Book review: *A History of Mathematical Statistics from 1750 to 1930* by Anders Hald. *Technometrics*, 41(1):85, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271022.

Ziegel:1999:BRBb

[Zie99c] Eric R. Ziegel. Book review: *Applied Multivariate Statistical Analysis* by Richard A. Johnson; Dean W. Wichern. *Technometrics*, 41(1):81–82, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271011.

Ziegel:1999:BRBd

[Zie99d] Eric R. Ziegel. Book review: *Applied Regression Analysis: A Research Tool* by John O. Rawlings; Sastry G. Pantula; David A. Dickey. *Technometrics*, 41(1):82, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271013.

Ziegel:1999:BRBav

[Zie99e] Eric R. Ziegel. Book review: *ARCH Models and Financial Applications* by Christian Gourieroux. *Technometrics*, 41(4):382–383, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271379.

Ziegel:1999:BRBah

[Zie99f] Eric R. Ziegel. Book review: *Case Studies in Environmental Statistics* by Douglas Nychka; Walter W. Piegorsch; Lawrence H. Cox. *Technometrics*, 41(3):273, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270593`.

Ziegel:1999:BRBs

[Zie99g] Eric R. Ziegel. Book review: *Common Statistical Methods for Clinical Research with SAS Examples* by Glenn A. Walker. *Technometrics*, 41(2):179–180, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270753`.

Ziegel:1999:BRBu

[Zie99h] Eric R. Ziegel. Book review: *Communication for Engineers* by Richard Ellis. *Technometrics*, 41(2):180, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270755`.

Ziegel:1999:BRBao

[Zie99i] Eric R. Ziegel. Book review: *Data Analysis with Microsoft(R) Excel* by Kenneth N. Berk; Patrick Carey. *Technometrics*, 41 (4):380, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271372`.

Ziegel:1999:BRBax

[Zie99j] Eric R. Ziegel. Book review: *Discretization and MCMC Convergence Assessment* by Christian P. Robert. *Technometrics*, 41 (4):383, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271381`.

Ziegel:1999:BRBac

[Zie99k] Eric R. Ziegel. Book review: *Doing Statistics with Excel^{TM} 97* by Marilyn Pelosi; Theresa M. Sandifer; Jersy J. Letkowski. *Technometrics*, 41(3):271–272, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270588`.

Ziegel:1999:BRBaa

[Zie99l] Eric R. Ziegel. Book review: *Engineering Statistics* by Douglas C. Montgomery; George C. Runger; Norma F. Hubele. *Technometrics*, 41(3):271, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270586.

Ziegel:1999:BRBr

[Zie99m] Eric R. Ziegel. Book review: *Environmental Stats for S-Plus* by Steven P. Millard. *Technometrics*, 41(2):179, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270752.

Ziegel:1999:BRBp

[Zie99n] Eric R. Ziegel. Book review: *Frontiers in Statistical Quality Control 5* by H. J. Lenz; P. T. Wilrich. *Technometrics*, 41(2):179, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270750.

Ziegel:1999:BRBn

[Zie99o] Eric R. Ziegel. Book review: *Fundamentals of Industrial Quality Control* by Lawrence S. Aft. *Technometrics*, 41(2):178, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270748.

Ziegel:1999:BRBf

[Zie99p] Eric R. Ziegel. Book review: *Handbook of Statistical Methods for Engineers and Scientists* by Harrison M. Wadsworth. *Technometrics*, 41(1):83, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271015.

Ziegel:1999:BRBg

[Zie99q] Eric R. Ziegel. Book review: *How to Conduct Organizational Surveys* by Jack E. Edwards; Marie D. Thomas; Paul Rosenfeld; Stephanie Booth-Kewley. *Technometrics*, 41(1):83, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271016.

Ziegel:1999:BRBi

[Zie99r] Eric R. Ziegel. Book review: *JMP Start Statistics* by John Sall; Ann Lehman (SAS Institute). *Technometrics*, 41(1):84, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271018.

Ziegel:1999:BRBaz

[Zie99s] Eric R. Ziegel. Book review: *Linear Models* by S. R. Searle. *Technometrics*, 41(4):383–384, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271383.

Ziegel:1999:BRBe

[Zie99t] Eric R. Ziegel. Book review: *Modelling Longitudinal and Spatially Correlated Data* by Timothy G. Gregoire; David R. Brillinger; Peter J. Diggle; Estelle Russek-Cohen; William G. Warren; Russell D. Wolfinger. *Technometrics*, 41(1):82–83, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271014.

Ziegel:1999:BRBan

[Zie99u] Eric R. Ziegel. Book review: *Nonparametric Statistical Methods* by Myles Hollander; Douglas A. Wolfe. *Technometrics*, 41 (4):380, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271371.

Ziegel:1999:BRBar

[Zie99v] Eric R. Ziegel. Book review: *Nonresponse in Household Interview Surveys* by Robert M. Groves; Mick P. Couper. *Technometrics*, 41(4):381, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271375.

Ziegel:1999:BRBag

[Zie99w] Eric R. Ziegel. Book review: *Numerical Linear Algebra for Applications in Statistics* by James E. Gentle. *Technometrics*, 41 (3):272–273, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270592.

Ziegel:1999:BRBz

[Zie99x] Eric R. Ziegel. Book review: *Odds Ratios in the Analysis of Contingency Tables* by T. Rudas. *Technometrics*, 41(2):181–182, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270760.

Ziegel:1999:BRBo

[Zie99y] Eric R. Ziegel. Book review: *Optimization in Quality Control* by K. Alsultan; M. A. Rahim. *Technometrics*, 41(2):178–179, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270749.

Ziegel:1999:BRBak

[Zie99z] Eric R. Ziegel. Book review: *Practical Management Science* by Wayne L. Winston; S. Christian Albright. *Technometrics*, 41(3): 274, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270596.

Ziegel:1999:BRBa

[Zie99-27] Eric R. Ziegel. Book review: *Practical Nonparametric and Semiparametric Bayesian Statistics* by D. D. Dey; P. Müller. *Technometrics*, 41(1):81, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271010.

Ziegel:1999:BRBap

[Zie99-28] Eric R. Ziegel. Book review: *Practical Risk Assessment for Project Management* by Stephen Grey. *Technometrics*, 41(4):380–381, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271373.

Ziegel:1999:BRBas

[Zie99-29] Eric R. Ziegel. Book review: *Principles of Total Quality* by Jill A. Swift; Joel E. Ross; Vincent K. Omachonu. *Technometrics*, 41(4):381–382, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271376.

Ziegel:1999:BRBv

[Zie99-30] Eric R. Ziegel. Book review: *Probability and Statistics for Engineers and Scientists* by Ronald E. Walpole; Raymond H. Meyers; Sharon L. Meyers. *Technometrics*, 41(2):180–181, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270756.

Ziegel:1999:BRBae

[Zie99-31] Eric R. Ziegel. Book review: *Programming Techniques for Object-Based Statistical Analysis with SAS Software* by Tanya Kolosova; Samuel Berestizhevsky. *Technometrics*, 41(3):272, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270590.

Ziegel:1999:BRBx

[Zie99-32] Eric R. Ziegel. Book review: *Prove It with Figures* by H. Zeisel; D. Kaye. *Technometrics*, 41(2):181, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270758.

Ziegel:1999:BRBat

[Zie99-33] Eric R. Ziegel. Book review: *Quality Assurance for the Chemical and Process Industries* by American Society for Quality. *Technometrics*, 41(4):382, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271377.

Ziegel:1999:BRBaq

[Zie99-34] Eric R. Ziegel. Book review: *Quantitative Risk Analysis* by David Vose. *Technometrics*, 41(4):381, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271374.

Ziegel:1999:BRBj

[Zie99-35] Eric R. Ziegel. Book review: *SAS(R) System for Elementary Statistical Analysis* by Sandra D. Schlotzhauer; Ramon C. Littell. *Technometrics*, 41(1):84, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271019.

Ziegel:1999:BRBay

[Zie99-36] Eric R. Ziegel. Book review: *Selected Papers of Hirotugu Akaike* by Hirotugu Akaike; Emanuel Parzen; Kunio Tanabe; Genshiro Kitagawa. *Technometrics*, 41(4):383, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271382.

Ziegel:1999:BRBau

[Zie99-37] Eric R. Ziegel. Book review: *Statistical Case Studies* by Roxy Peck; Larry D. Haugh; Arnold Goodman. *Technometrics*, 41(4):

382, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271378.

Ziegel:1999:BRBad

[Zie99-38] Eric R. Ziegel. Book review: *Statistical Design and Analysis of Experiments* by Peter John. *Technometrics*, 41(3):272, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270589.

Ziegel:1999:BRBaw

[Zie99-39] Eric R. Ziegel. Book review: *Statistical Issues in Drug Development* by Stephen Senn. *Technometrics*, 41(4):383, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271380.

Ziegel:1999:BRBy

[Zie99-40] Eric R. Ziegel. Book review: *Statistical Significance* by Siu Chow. *Technometrics*, 41(2):181, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270759.

Ziegel:1999:BRBw

[Zie99-41] Eric R. Ziegel. Book review: *Statistical Thinking for Managers* by David Hildebrand; Lyman Ott. *Technometrics*, 41(2):181, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270757.

Ziegel:1999:BRBab

[Zie99-42] Eric R. Ziegel. Book review: *Statistics: An Introduction* by Robert D. Mason; Douglas A. Lind; William G. Marchal. *Technometrics*, 41(3):271, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1270587.

Ziegel:1999:BRBam

[Zie99-43] Eric R. Ziegel. Book review: *Statistics for Petroleum Engineers and Geoscientists* by Jerry L. Jensen; Larry W. Lake; Patrick W. M. Corbett; David J. Goggin. *Technometrics*, 41(4):379–380, November 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1271370.

Ziegel:1999:BRBq

[Zie99-44] Eric R. Ziegel. Book review: *Statistics for the Environment 2* by Vic Barnett; K. Feridun Turkman. *Technometrics*, 41(2):179, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270751`.

Ziegel:1999:BRBai

[Zie99-45] Eric R. Ziegel. Book review: *Statistics for the Environment 3* by V. Barnett; K. Feridun Turkman. *Technometrics*, 41(3):273–274, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270594`.

Ziegel:1999:BRBaj

[Zie99-46] Eric R. Ziegel. Book review: *Stochastic Models in Geosystems* by Stanislav A. Molchanov; Wojbor A. Woyczynski. *Technometrics*, 41(3):274, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270595`.

Ziegel:1999:BRBaf

[Zie99-47] Eric R. Ziegel. Book review: *Strategic Data Warehousing Principles Using SAS Software* by Peter R. Welbrock. *Technometrics*, 41(3):272, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270591`.

Ziegel:1999:BRBt

[Zie99-48] Eric R. Ziegel. Book review: *Survey Research Using the SAS System* by Archer Gravely. *Technometrics*, 41(2):180, May 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270754`.

Ziegel:1999:BRBal

[Zie99-49] Eric R. Ziegel. Book review: *Theory of Point Estimation* by E. L. Lehmann; George Casella. *Technometrics*, 41(3):274, August 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270597`.

Ziegel:1999:BRBk

[Zie99-50] Eric R. Ziegel. Book review: *Total Quality Tools* by *PQ Systems, Inc. Technometrics*, 41(1):84, February 1999. CODEN TCMTA2.

ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271020`.

Ziegel:1999:BRBc

[Zie99-51] Eric R. Ziegel. Book review: *Univariate and Multivariate General Linear Models* by Neil H. Timm; Tammy A. Mieczkowski. *Technometrics*, 41(1):82, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271012`.

Ziegel:1999:BRBh

[Zie99-52] Eric R. Ziegel. Book reviews: *The Survey Research Handbook* by Pamela L. Alreck; Robert B. Settle; *How to Conduct Surveys: A Step-by-Step Guide* by Arlene Fink; Jacqueline Kosecoff. *Technometrics*, 41(1):83–84, February 1999. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1271017`.

Zinkgraf:1993:BRB

[Zin93] Stephen A. Zinkgraf. Book review: *Computer-Interactive Data Analysis* by A. D. Lunn; D. R. McNeil. *Technometrics*, 35(4):459, November 1993. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1270290`.

Zhou:1994:STV

[ZM94] Leping Zhou and Thomas Mathew. Some tests for variance components using generalized p values. *Technometrics*, 36(4):394–402, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269954`. See comment [BZM96].

Zhang:1994:AAD

[ZP94] Nien Fan Zhang and James F. Pollard. Analysis of autocorrelations in dynamic processes. *Technometrics*, 36(4):354–368, November 1994. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269951`.

Zimmerman:1991:CSS

[ZZ91] Dale L. Zimmerman and M. Bridget Zimmerman. A comparison of spatial semivariogram estimators and corresponding ordinary kriging predictors. *Technometrics*, 33(1):77–91, February 1991. CO-

DEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1269009.